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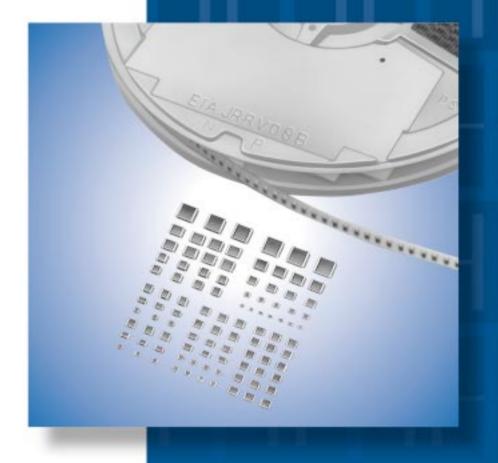
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Jameco Part Number 1859319

Chip Monolithic Ceramic Capacitors



muRata

Innovator in Electronics

Murata Manufacturing Co., Ltd.

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Part Numbering

Chip Monolithic Ceramic Capacitors

GR M 18 8 B1 1H 102 K A01 K (Part Number)

Product ID

2Series

3 001103				
Product ID	Code	Series		
	M	Tin Plated Layer		
GR	4	Only for Information Devices / Tip & Ring		
	7	Only for Camera Flash Circuit		
ER	В	High Frequency Type		
GQ	М	High Frequency for Flow/Reflow Soldering		
GM	Α	Monolithic Microchip		
GN	M	Capacitor Array		
	L Low ESL Wide Width T			
LL	Α	Eight-termination Low ESL Type		
•	М	Ten-termination Low ESL Type		
GJ	М	High Frequency Low Loss Type Tin Plated Type		
GA	2	for AC250V (r.m.s.)		
	3	Safety Standard Recognized Type		

3Dimension (LXW)

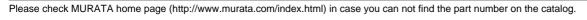
Code	Dimension (LXW)	EIA	
02	0.4×0.2mm	01005	
03	0.6×0.3mm	0201	
05	0.5×0.5mm	0202	
08	0.8×0.8mm	0303	
11	1.25×1.0mm	0504	
15	1.0×0.5mm	0402	
18	1.6×0.8mm	0603	
1D	1.4×1.4mm		
1X	Depends on individual standards.		
21	2.0×1.25mm	0805	
22	2.8×2.8mm 1111		
31	3.2×1.6mm 120		
32	3.2×2.5mm	1210	
3X	Depends on individual	standards.	
42	4.5×2.0mm	1808	
43	4.5×3.2mm	1812	
52	5.7×2.8mm 2211		
55	5.7×5.0mm 2220		

4Dimension (T)

Code	Dimension (T)			
2	0.2mm			
2	2-elements (Array Type)			
3	0.3mm			
4	4-elements (Array Type)			
5	0.5mm			
6	0.6mm			
7	0.7mm			
8	0.8mm			
9	0.85mm			
Α	1.0mm			
В	1.25mm			
С	1.6mm			
D	2.0mm			
E	2.5mm			
F	3.2mm			
М	1.15mm			
N	1.35mm			
R	1.8mm			
S	2.8mm			
Q	1.5mm			
Х	Depends on individual standards.			

With the array type GNM series, "Dimension(T)" indicates the number of elements.







5Temperature Characteristics

Temperature Characteristic Codes							
Code	Public STD (Code	Referance Temperature	Temperature Range	Capacitance Change or Temperature Coefficient	Operating Temperature Range	
1X	SL *1	JIS	20°C	20 to 85°C	+350 to -1000ppm/°C	-55 to 125°C	
2C	CH *1	JIS	20°C	20 to 125°C	0±60ppm/°C	-55 to 125°C	
2P	PH *1	JIS	20°C	20 to 85°C	-150±60ppm/°C	-25 to 85°C	
2R	RH *1	JIS	20°C	20 to 85°C	-220±60ppm/°C	-25 to 85°C	
2S	SH *1	JIS	20°C	20 to 85°C	-330±60ppm/°C	-25 to 85°C	
2T	TH *1	JIS	20°C	20 to 85°C	-470±60ppm/°C	-25 to 85°C	
3C	CJ *1	JIS	20°C	20 to 125°C	0±120ppm/°C	-55 to 125°C	
3P	PJ *1	JIS	20°C	20 to 85°C	-150±120ppm/°C	-25 to 85°C	
3R	RJ *1	JIS	20°C	20 to 85°C	-220±120ppm/°C	-25 to 85°C	
3S	SJ *1	JIS	20°C	20 to 85°C	-330±120ppm/°C	-25 to 85°C	
3T	TJ *1	JIS	20°C	20 to 85°C	-470±120ppm/°C	-25 to 85°C	
3U	UJ *1	JIS	20°C	20 to 85°C	-750±120ppm/°C	-25 to 85°C	
4C	CK *1	JIS	20°C	20 to 125°C	0±250ppm/°C	-55 to 125°C	
5C	C0G *1	EIA	25°C	25 to 125°C	0±30ppm/°C	-55 to 125°C	
5G	X8G *1	EIA	25°C	25 to 150°C	0±30ppm/°C	-55 to 150°C	
6C	C0H *1	EIA	25°C	25 to 125°C	0±60ppm/°C	-55 to 125°C	
6P	P2H *1	EIA	25°C	25 to 85°C	-150±60ppm/°C	-55 to 125°C	
6R	R2H *1	EIA	25°C	25 to 85°C	-220±60ppm/°C	-55 to 125°C	
6S	S2H *1	EIA	25°C	25 to 85°C	-330±60ppm/°C	-55 to 125°C	
6T	T2H *1	EIA	25°C	25 to 85°C	-470±60ppm/°C	-55 to 125°C	
7U	U2J *1	EIA	25°C	25 to 85°C	-750±120ppm/°C	-55 to 125°C	
B1	B *2	JIS	20°C	-25 to 85°C	±10%	-25 to 85°C	
В3	В	JIS	20°C	-25 to 85°C	±10%	-25 to 85°C	
C7	X7S	EIA	25°C	-55 to 125°C	±22%	-55 to 125°C	
C8	X6S	EIA	25°C	-55 to 105°C	±22%	-55 to 105°C	
F1	F *2	JIS	20°C	-25 to 85°C	+30, -80%	-25 to 85°C	
F5	Y5V	EIA	25°C	-30 to 85°C	+22, -82%	-30 to 85°C	
L8	X8L	EIA	25°C	-55 to 150°C	+15, -40%	-55 to 150°C	
R1	R *2	JIS	20°C	-55 to 125°C	±15%	-55 to 125°C	
R3	R	JIS	20°C	-55 to 125°C	±15%	-55 to 125°C	
R6	X5R	EIA	25°C	-55 to 85°C	±15%	-55 to 85°C	
R7	X7R	EIA	25°C	-55 to 125°C	±15%	-55 to 125°C	
R9	X8R	EIA	25°C	-55 to 150°C	±15%	-55 to 150°C	
0.5	71.54	*2	2000	-25 to 20°C	-4700+1000/-2500ppm/°C	25 4- 0500	
9E	ZLM	*3	20°C	20 to 85°C	-4700+500/-1000ppm/°C	-25 to 85°C	
14/0			2500	FF 1- 1050C	±10% *4	-55 to 125°C	
W0	-	-	25°C	-55 to 125°C	+22, -33% *5		

^{*1} Please refer to table for Capacitance Change under reference temperature.

Continued on the following page. $\begin{tabular}{|c|c|c|c|}\hline \end{tabular}$



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^{*2} Capacitance change is specified with 50% rated voltage applied.

^{*3,*4} Murata Temperature Characteristic Code.

^{*4} Apply DC350V bias.

^{*5} No DC bias.

●Capacitance Change from each temperature

JIS Code

			Capacitance Cha	nge from 20°C (%)		
Murata Code	−55°C		−25°C		−10°C	
	Max.	Min.	Max.	Min.	Max.	Min.
1X	-	-	-	-	-	-
2C	0.82	-0.45	0.49	-0.27	0.33	-0.18
2P	-	-	1.32	0.41	0.88	0.27
2R	_	-	1.70	0.72	1.13	0.48
28	-	-	2.30	1.22	1.54	0.81
2T	-	-	3.07	1.85	2.05	1.23
3C	1.37	-0.90	0.82	-0.54	0.55	-0.36
3P	-	-	1.65	0.14	1.10	0.09
3R	-	-	2.03	0.45	1.35	0.30
38	_	-	2.63	0.95	1.76	0.63
3T	_	-	3.40	1.58	2.27	1.05
3U	_	-	4.94	2.84	3.29	1.89
4C	2.56	-1.88	1.54	-1.13	1.02	-0.75

EIA Code

	Capacitance Change from 25°C (%)					
Murata Code	−55°C		-30°C		−10°C	
	Max.	Min.	Max.	Min.	Max.	Min.
5C/5G	0.58	-0.24	0.40	-0.17	0.25	-0.11
6C	0.87	-0.48	0.59	-0.33	0.38	-0.21
6P	2.33	0.72	1.61	0.50	1.02	0.32
6R	3.02	1.28	2.08	0.88	1.32	0.56
6S	4.09	2.16	2.81	1.49	1.79	0.95
6T	5.46	3.28	3.75	2.26	2.39	1.44
7U	8.78	5.04	6.04	3.47	3.84	2.21

6 Rated Voltage

Code	Rated Voltage		
0G	DC4V		
0J	DC6.3V		
1A	DC10V		
1C	DC16V		
1E	DC25V		
1H	DC50V		
2A	DC100V		
2D	DC200V		
2E	DC250V		
YD	DC300V		
2H	DC500V		
2J	DC630V		
3A	DC1kV		
3D	DC2kV		
3F	DC3.15kV		
ВВ	DC350V (for Camera Flash Circuit)		
E2	AC250V		
GB	X2; AC250V (Safety Standard Recognized Type GB)		
GC	X1/Y2; AC250V (Safety Standard Recognized Type GC)		
GD	Y3; AC250V (Safety Standard Recognized Type GD)		
GF	Y2, X1/Y2; AC250V (Safety Standard Recognized Type GF)		

Capacitance

Expressed by three-digit alphanumerics. The unit is pico-farad (pF). The first and second figures are significant digits, and the third figure expresses the number of zeros which follow the two numbers.If there is a decimal point, it is expressed by the capital letter "R". In this case, all figures are significant digits.

		9 9
Ex.)	Code	Capacitance
	R50	0.5pF
	1R0	1.0pF
	100	10pF
	103	10000pF

Continued on the following page.



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8Capacitance Tolerance

Code	Capacitance Tolerance	TC	Series	Capacitance Step	
W	±0.05pF	СД	GRM/GJM	≦9.9pF	0.1pF
В	±0.1pF	СΔ	GRM/GJM	≦9.9pF	0.1pF
		СΔ	GRM/GJM	≦9.9pF	0.1pF
С	±0.25pF	except CΔ	GRM	≦5pF	* 1pF
		СΔ	ERB/GQM	≦5pF	* 1pF
		СΔ	GRM/GJM	5.1 to 9.9pF	0.1pF
D	±0.5pF	except CΔ	GRM	5.1 to 9.9pF	* 1pF
		СΔ	ERB/GQM	5.1 to 9.9pF	* 1pF
G	±2%	СΔ	GJM	≥10pF	E12 Series
G		СΔ	GQM	≥10pF	E24 Series
	±5%	CΔ-SL	GRM/GA3	≥10pF	E12 Series
J		СΔ	ERB/GQM/GJM	≥10pF	E24 Series
K	1100/	D D VZD VED ZLAA	GRM/GR7/GA3	E6	Series
ĸ	±10%	B, R, X7R, X5R, ZLM	GR4	E12	2 Series
		Z5U	GRM	E3	Series
M	±20%	B, R, X7R, X7S	GRM/GMA/LLL/LLA/LLM	E6	Series
		X7R	GA2	E3	Series
Z	+80%, -20%	F, Y5V	/5V GRM E3 Series		
R	Depends on individual standards.				

^{*} E24 series is also available.

9Individual Specification Code

Expressed by three figures.

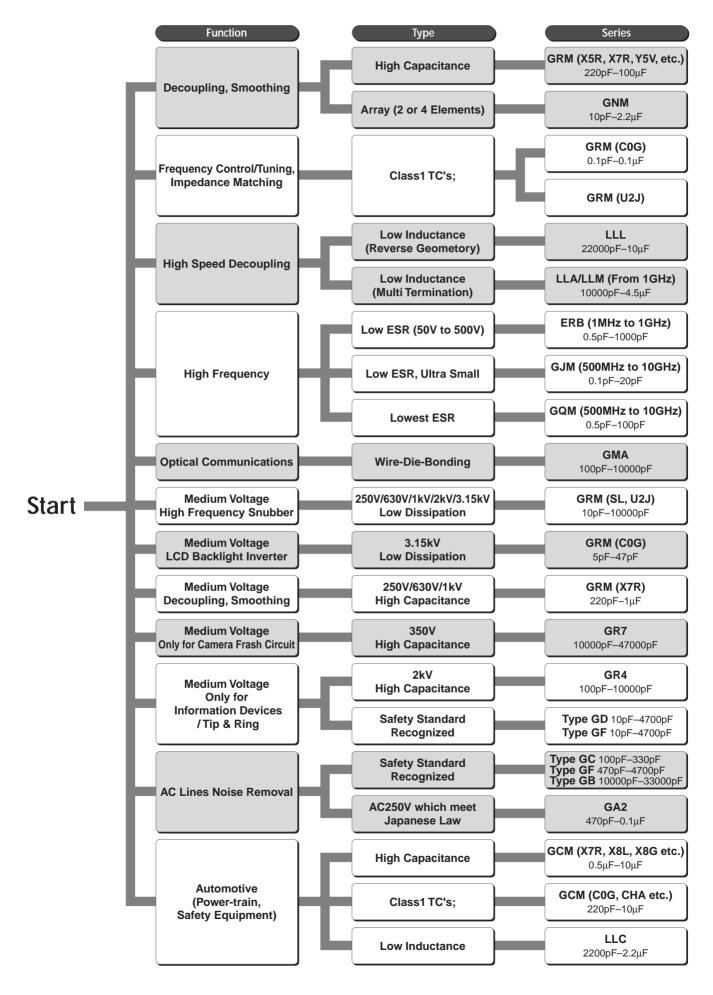
Packaging

Code	Packaging			
L	ø180mm Embossed Taping			
D	ø180mm Paper Taping			
K	ø330mm Embossed Taping			
J	ø330mm Paper Taping			
В	Bulk			
С	Bulk Case			
Т	Bulk Tray			

Please check MURATA home page (http://www.murata.com/index.html) in case you can not find the part number on the catalog.



Selection Guide of Chip Monolithic Ceramic Capacitors



sales representatives or product engineers before ordering.

• This PDF catalog has only typical specifications because there is no space for detailed specifications. Therefore, please approve our product specifications or transact the approval sheet for product specifications before ordering.

Chip Monolithic Ceramic Capacitors



for General Purpose GRM15/18/21/31 Series

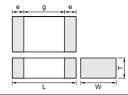
■ Features

- 1. Terminations are made of metal highly resistant to migration.
- 2. A wide selection of sizes is available, from the miniature LxW: 1.0x0.5mm to LxW: 3.2x1.6mm. GRM18, 21 and GRM31 types are suited to flow and reflow soldering.
 - GRM15 type is applied to only reflow soldering.
- 3. Smaller size and higher capacitance value
- 4. High reliability and no polarity
- 5. Excellent pulse responsibility and noise reduction due to the low impedance at high frequency.
- 6. Ta replacement

■ Applications

General electronic equipment





Part Number		Dir	nensions (n	nm)	
Part Number	L	W	Т	е	g min.
GRM155	1.0 ±0.05	0.5 ±0.05	0.5 ±0.05	0.15 to 0.35	0.3
GRM185	1.6 ±0.1	0.8 ±0.1	0.5 +0/-0.1	0.2 to 0.5	0.5
GRM188*	1.0 ±0.1	0.6 ±0.1	0.8 ±0.1	0.2 10 0.5	0.5
GRM216			0.6 ±0.1		
GRM219	2.0 ±0.1	1.25 ±0.1	0.85 ±0.1	0.2 to 0.7	0.7
GRM21A	2.0 ±0.1	1.23 ±0.1	1.0 +0/-0.2	0.2 10 0.7	0.7
GRM21B			1.25 ±0.1		
GRM316			0.6 ±0.1		
GRM319	3.2 ±0.15	1.6 ±0.15	0.85 ±0.1	0.3 to 0.8	1.5
GRM31M			1.15 ±0.1	0.3 10 0.6	1.5
GRM31C	3.2 ±0.2	1.6 ±0.2	1.6 ±0.2		

^{*} Bulk Case: 1.6 ±0.07(L) × 0.8 ±0.07(W) × 0.8 ±0.07(T)

Temperature Compensating Type GRM15 Series (1.00x0.50mm) 50/25V

Part Number				GR	M15			
L x W [EIA]				1.0x0.	5 [0402]			
тс	COG (5C)	P2H (6P)	R2H (6R)	S2H (6S)		SL 1X)	T2H (6T)	U2J (7U)
Rated Volt.	50 (1H)	50 (1H)	50 (1H)	50 (1H)	50 (1H)	25 (1E)	50 (1H)	50 (1H)
Capacitance (Cap	pacitance part n	numbering code)	and T (mm) Dim	ension (T Dimen	sion part number	ering code)		
3.0pF(3R0)	0.5 (5)	0.5(5)	0.5 (5)	0.5 (5)			0.5 (5)	0.5(5)
4.0pF(4R0)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)			0.5 (5)	0.5(5)
5.0pF(5R0)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)			0.5 (5)	0.5(5)
6.0pF(6R0)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)			0.5 (5)	0.5(5)
7.0pF(7R0)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)			0.5 (5)	0.5(5)
8.0pF(8R0)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)			0.5 (5)	0.5(5)
9.0pF(9R0)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)			0.5 (5)	0.5(5)
10pF(100)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)			0.5 (5)	0.5(5)
12pF(120)	0.5 (5)	0.5(5)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)	0.5(5)
15pF(150)	0.5 (5)	0.5(5)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)	0.5(5)
18pF(180)	0.5 (5)	0.5(5)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)	0.5(5)
22pF(220)	0.5 (5)	0.5(5)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)	0.5(5)
27pF(270)	0.5 (5)	0.5(5)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)
33pF(330)	0.5 (5)		0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)
39pF(390)	0.5 (5)			0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)
47pF(470)	0.5 (5)				0.5 (5)	0.5 (5)	0.5 (5)	0.5 (5)
56pF(560)	0.5 (5)				0.5 (5)	0.5 (5)	0.5 (5)	0.5(5)
68pF(680)	0.5 (5)				0.5 (5)	0.5 (5)	0.5 (5)	0.5(5)
82pF(820)	0.5 (5)				0.5 (5)	0.5 (5)	0.5 (5)	0.5(5)
100pF(101)	0.5 (5)				0.5 (5)	0.5 (5)	0.5 (5)	0.5(5)
120pF(121)	0.5 (5)				0.5(5)	0.5 (5)		0.5(5)
150pF(151)	0.5(5)				0.5 (5)	0.5 (5)		0.5(5)
180pF(181)	0.5(5)				0.5 (5)	0.5 (5)		0.5(5)
220pF(221)	0.5 (5)					0.5 (5)		
270pF(271)	0.5 (5)					0.5 (5)		

Part Number				GR	M15			
L x W [EIA]				1.0x0.5	5 [0402]			
тс	C0G (5C)	P2H (6P)	R2H (6R)	S2H (6S)	(**	SL 1X)	T2H (6T)	U2J (7U)
Rated Volt.	50 (1H)	50 (1H)	50 (1H)	50 (1H)	50 (1H)	25 (1E)	50 (1H)	50 (1H)
Capacitance (Ca	pacitance part n	numbering code)	and T (mm) Dim	ension (T Dimen	sion part numb	ering code)		
330pF(331)	0.5(5)					0.5(5)		
390pF(391)	0.5(5)					0.5(5)		
470pF(471)	0.5(5)							
560pF(561)	0.5(5)							
680pF(681)	0.5(5)							
820pF(821)	0.5 (5)							
1000pF(102)	0.5(5)							

The part numbering code is shown in $\ (\).$

Dimensions are shown in mm and Rated Voltage in Vdc.

Temperature Compensating Type GRM18 Series (1.60x0.80mm) 100/50V

Part Number							GR	M18						
L x W [EIA]							1.6x0.8	3 [0603]						
тс	C(5			2H P)		2H R)		2H S)	S (1	X)		2H T)		2J U)
Rated Volt.	100 (2A)	50 (1H)												
Capacitance (Ca	pacitance	e part nui	mbering c	ode) and	T (mm) D	imension	(T Dimen	sion part	numberin	g code)				
0.50pF(R50)	0.8(8)													
3.0pF(3R0)	0.8(8)		0.8(8)		0.8(8)		0.8(8)				0.8(8)			
4.0pF(4R0)	0.8(8)		0.8(8)		0.8(8)		0.8(8)				0.8(8)			
5.0pF(5R0)	0.8(8)		0.8(8)		0.8(8)		0.8(8)				0.8(8)			
6.0pF(6R0)	0.8(8)		0.8(8)		0.8(8)		0.8(8)				0.8(8)			
7.0pF(7R0)	0.8(8)		0.8(8)		0.8(8)		0.8(8)				0.8(8)			
8.0pF(8R0)	0.8(8)		0.8(8)		0.8(8)		0.8(8)				0.8(8)			
9.0pF(9R0)	0.8(8)		0.8(8)		0.8(8)		0.8(8)				0.8(8)			
10pF(100)	0.8(8)		0.8(8)		0.8(8)		0.8(8)				0.8(8)		0.8(8)	
12pF(120)	0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)	
15pF(150)	0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)	
18pF(180)	0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)	
22pF(220)	0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)	
27pF(270)	0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)	
33pF(330)	0.8(8)		0.8(8)	0.8(8)	0.8(8)		0.8(8)		0.8(8)		0.8(8)		0.8(8)	
39pF(390)	0.8(8)		0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)		0.8(8)		0.8(8)		0.8(8)	
47pF(470)	0.8(8)		0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)				0.8(8)	
56pF(560)	0.8(8)		0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)				0.8(8)	
68pF(680)	0.8(8)		0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)				0.8(8)	
82pF(820)	0.8(8)		0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)				0.8(8)	
100pF(101)	0.8(8)		0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)				0.8(8)	
120pF(121)	0.8(8)		0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)	0.8(8)			0.8(8)	0.8(8)	
150pF(151)	0.8(8)			0.8(8)	0.8(8)	0.8(8)		0.8(8)	0.8(8)			0.8(8)	0.8(8)	
180pF(181)	0.8(8)					0.8(8)		0.8(8)	0.8(8)			0.8(8)	0.8(8)	
220pF(221)	0.8(8)							0.8(8)	0.8(8)	0.8(8)		0.8(8)	0.8(8)	0.8(8)
270pF(271)	0.8(8)								0.8(8)	0.8(8)		0.8(8)	0.8(8)	0.8(8)
330pF(331)	0.8(8)								0.8(8)	0.8(8)		0.8(8)	0.8(8)	0.8(8)
390pF(391)	0.8(8)								0.8(8)	0.8(8)		0.8(8)	0.8(8)	0.8(8)
470pF(471)	0.8(8)									0.8(8)		0.8(8)		0.8(8)
560pF(561)	0.8(8)									0.8(8)				0.8(8)
680pF(681)	0.8(8)									0.8(8)				0.8(8)
820pF(821)	0.8(8)									.,				. ,

Part Number		•			<u> </u>	•	GR	M18		•		_		
L x W [EIA]							1.6x0.8	3 [0603]						
тс		0G C)		2H 6 P)		2H iR)		2H (S)		X)		2H T)	U: (7	2J 'U)
Rated Volt.	100 (2A)	50 (1H)												
Capacitance (Ca	apacitanc	e part nur	mbering o	g code) and T (mn		imension	(T Dimen	sion part	numberin	g code)				
1000pF(102)	0.8(8)									0.8(8)				0.8(8)
1200pF(122)		0.8(8)								0.8(8)				0.8(8)
1500pF(152)		0.8(8)								0.8(8)				0.8(8)
1800pF(182)		0.8(8)								0.8(8)				0.8(8)
2200pF(222)		0.8(8)								0.8(8)				0.8(8)
2700pF(272)		0.8(8)								0.8(8)				0.8(8)
3300pF(332)										0.8(8)				0.8(8)
3900pF(392)										0.8(8)				0.8(8)
4700pF(472)										0.8(8)				0.8(8)
5600pF(562)										0.8(8)				0.8(8)
6800pF(682)										0.8(8)				0.8(8)
8200pF(822)										0.8(8)				0.8(8)
10000pF(103)										0.8(8)				0.8(8)

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

Temperature Compensating Type GRM21 Series (2.00x1.25mm) 100/50V

Part Number							GR	M21						
L x W [EIA]							2.0x1.2	5 [0805]						
тс)G C)		2H P)		2H iR)		2H S)		X)		2H T)		2J 'U)
Rated Volt.	100 (2A)	50 (1H)												
Capacitance (Ca	apacitance	e part nui	mbering c	ode) and	T (mm) D	imension	(T Dimen	sion part	numberin	g code)	·			
33pF(330)				0.6(6)										
39pF(390)				0.6(6)		0.6(6)								
47pF(470)				0.6(6)		0.6(6)		0.6(6)			1.25(B)			
56pF(560)				0.6(6)		0.6(6)		0.6(6)			1.25(B)			
68pF(680)				0.6(6)		0.6(6)		0.6(6)			1.25(B)			
82pF(820)				0.6(6)		0.6(6)		0.6(6)			1.25(B)			
100pF(101)				0.6(6)		0.6(6)		0.6(6)			1.25(B)			
120pF(121)				0.6(6)		0.6(6)		0.6(6)			1.25(B)	0.6(6)		
150pF(151)			0.85(9)	0.6(6)		0.6(6)	0.85(9)	0.6(6)			1.25(B)			
180pF(181)			0.85(9)	0.85(9)	0.85(9)	0.6(6)	0.85(9)	0.6(6)			1.25(B)			
220pF(221)			0.85(9)	0.85(9)	0.85(9)	0.85(9)	0.85(9)	0.6(6)		0.6(6)	1.25(B)			0.6(6)
270pF(271)			0.85(9)	0.85(9)	0.85(9)	0.85(9)	0.85(9)			0.6(6)				0.6(6)
330pF(331)			0.85(9)	0.85(9)	0.85(9)	0.85(9)	0.85(9)			0.6(6)				0.6(6)
390pF(391)			1.25(B)	1.25(B)	0.85(9)	0.85(9)	0.85(9)			0.6(6)				0.6(6)
470pF(471)			1.25(B)	1.25(B)	0.85(9)	0.85(9)	0.85(9)		0.85(9)	0.6(6)			0.85(9)	0.6(6)
560pF(561)				1.25(B)	1.25(B)	0.85(9)	1.25(B)	0.85(9)	0.85(9)	0.6(6)		1.25(B)	0.85(9)	0.6(6)
680pF(681)	0.6(6)					1.25(B)		1.25(B)	0.85(9)	0.6(6)		1.25(B)	0.85(9)	0.6(6)
820pF(821)	0.6(6)							1.25(B)	1.25(B)	0.6(6)		1.25(B)	1.25(B)	0.6(6)
1000pF(102)	0.85(9)								1.25(B)	0.6(6)		1.25(B)	1.25(B)	0.6(6)
1200pF(122)	0.85(9)	0.6(6)							1.25(B)	0.6(6)		1.25(B)	1.25(B)	0.6(6)
1500pF(152)	0.85(9)	0.6(6)							1.25(B)	0.85(9)		1.25(B)	1.25(B)	0.85(9
1800pF(182)		0.6(6)							1.25(B)	0.85(9)		1.25(B)	1.25(B)	0.85(9)
2200pF(222)		0.6(6)								0.85(9)				0.85(9)
2700pF(272)		0.6(6)								1.25(B)				1.25(B
3300pF(332)		0.6(6)								1.25(B)				1.25(B
3900pF(392)		0.6(6)												

Z Continued from	trie preceu	ing page.												
Part Number							GR	M21						
L x W [EIA]							2.0x1.2	5 [0805]						
тс		0G C)		2H i P)		2H iR)		2H S)	(1	SL X)		2H i T)		2J 'U)
Rated Volt.	100 (2A)	50 (1H)												
Capacitance (Ca	pacitanc	e part nur	mbering c	ode) and	T (mm) D	imension	(T Dimen	sion part	numberir	ng code)		,		•
4700pF(472)		0.6(6)												
5600pF(562)		0.85(9)												
6800pF(682)		0.85(9)												
8200pF(822)		0.85(9)												
10000pF(103)		0.85(9)								0.6(6)				0.6(6)
12000pF(123)		0.85(9)								0.6(6)				0.6(6)
15000pF(153)		0.85(9)								0.6(6)				0.6(6)
18000pF(183)		1.25(B)								0.6(6)				0.6(6)
22000pF(223)		1.25(B)								0.85(9)				0.85(9)
27000pF(273)										0.85(9)				0.85(9)
33000pF(333)										1.0(A)				1.0(A)
39000pF(393)										1.25(B)				1.25(B)
47000pF(473)										1.25(B)				1.25(B)

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

Temperature Compensating Type GRM31 Series (3.20x1.60mm) 100/50/25V

Part Number								GRM31							
L x W [EIA]							3.2	2x1.6 [12	06]						
тс		C0G (5C)			2H P)		2H R)		2H S)		X)		2H T)	U2 (7 0	
Rated Volt.	100 (2A)	50 (1H)	25 (1E)	100 (2A)	50 (1H)										
Capacitance (Ca	pacitano	e part nu	umbering	code) aı	nd T (mm) Dimens	ion (T Di	mension	part nun	nbering c	ode)			'	
47pF(470)												0.85(9)			
56pF(560)												0.85(9)			
68pF(680)												0.85(9)			
82pF(820)												0.85(9)			
100pF(101)												1.15(M)			
120pF(121)												1.15(M)			
150pF(151)												1.15(M)			
180pF(181)					0.6(6)							1.15(M)			
220pF(221)					0.6(6)		0.6(6)					1.15(M)			
270pF(271)					0.6(6)		0.6(6)		0.6(6)			1.15(M)			
330pF(331)					0.6(6)		0.6(6)		0.6(6)			1.15(M)			
390pF(391)				0.85(9)			0.6(6)		0.6(6)			1.15(M)			
470pF(471)				0.85(9)					0.6(6)			1.15(M)			
560pF(561)				0.85(9)		0.85(9)		0.85(9)	0.85(9)						
680pF(681)				0.85(9)		0.85(9)	0.85(9)	0.85(9)	0.85(9)						
820pF(821)				0.85(9)		0.85(9)	0.85(9)	0.85(9)	0.85(9)	0.85(9)			1.15(M)	0.85(9)	
1000pF(102)				1.15(M)		1.15(M)	1.15(M)	0.85(9)	0.85(9)	0.85(9)			1.15(M)	0.85(9)	
1200pF(122)				1.15(M)		1.15(M)	1.15(M)	1.15(M)	1.15(M)	0.85(9)			1.15(M)	0.85(9)	
1500pF(152)					1.15(M)		1.15(M)	1.15(M)	1.15(M)	0.85(9)			1.15(M)	0.85(9)	
1800pF(182)	0.85(9)								1.15(M)	0.85(9)			1.15(M)	0.85(9)	
2200pF(222)	0.85(9)									1.15(M)			1.15(M)	1.15(M)	
2700pF(272)	0.85(9)									1.15(M)			1.15(M)	1.15(M)	
3300pF(332)	0.85(9)									1.15(M)			1.15(M)	1.15(M)	
3900pF(392)	0.85(9)									1.15(M)			1.15(M)	1.15(M)	
4700pF(472)	0.85(9)									1.15(M)				1.15(M)	
5600pF(562)	0.85(9)														

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		51 5													
Part Number								GRM31							
L x W [EIA]							3.2	2x1.6 [12	06]						
тс		C0G (5C)			2H P)		2H R)	S2 (6			X)		2H T)		12J 'U)
Rated Volt.	100 (2A)	(1H) (1E) itance part numbering 0.85(9)		100 (2A)	50 (1H)										
Capacitance (Ca	pacitano	ce part nu	ımbering	code) aı	nd T (mm) Dimens	sion (T Di	mension	part nun	bering o	ode)				
18000pF(183)		0.85(9)													
22000pF(223)		0.85(9)													
27000pF(273)		0.85(9)													
33000pF(333)		0.85(9)													
39000pF(393)		1.15(M)													
47000pF(473)		1.15(M)													
56000pF(563)		1.6(C)									0.85(9)				0.85(9)
68000pF(683)		1.6(C)									1.15(M)				1.15(M)
82000pF(823)		1.6(C)									1.15(M)				1.15(M)
0.10μF(104)			1.6(C)								1.15(M)				1.15(M)

The part numbering code is shown in ().

High Dielectric Constant Type X5R (R6) Characteristics

тс										X5R (R6)									
Part Number			GRM15	5				GRM18	3			GR	M21				GRM31	l	
L x W [EIA]		1.0	x0.5 [0	402]			1.62	x0.8 [0	603]		2	2.0x1.2	5 [0805	5]		3.2	x1.6 [1:	206]	
Rated Volt.	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	4 (0G)
Capacitance (Ca	pacita	nce pa	rt numl	pering o	code) a	nd T (n	nm) Din	nensio	n (T Din	nensio	n part r	number	ing coc	le)					
1000pF (102)	0.5 (5)	0.5 (5)																	
2200pF (222)	0.5 (5)	0.5 (5)																	
4700pF (472)	0.5 (5)	0.5 (5)																	
10000pF (103)						0.8 (8)													
22000pF (223)			0.5 (5)			0.8 (8)													
33000pF (333)			0.5 (5)	0.5 (5)															
47000pF (473)			0.5 (5)	0.5 (5)															
68000pF (683)			0.5 (5)	0.5 (5)															
0.10μF (104)			0.5 (5)	0.5 (5)			0.8 (8)												
0.15μF (154)				0.5* (5)	0.5* (5)														
0.22μF (224)				0.5* (5)	0.5* (5)		0.8 (8)	0.8 (8)											
0.33μF (334)				0.5* (5)	0.5* (5)														
0.47μF (474)				0.5* (5)	0.5* (5)		0.8* (8)	0.8* (8)											
0.68μF (684)				0.5* (5)	0.5* (5)														

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Dimensions are shown in mm and Rated Voltage in Vdc.

TC										X5R (R6)									
Part Number			GRM15	5				GRM18	}			GRI	M21				GRM31	l	
L x W [EIA]		1.0	x0.5 [0	402]			1.6	x0.8 [0	503]		2	.0x1.2	5 [0805	5]		3.2	x1.6 [1	206]	
Rated Volt.	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	4 (0G)
Capacitance (Ca	pacita	nce pa	rt numk	pering o	code) a	nd T (m	nm) Dir	nensior	(T Din	nensio	n part n	umber	ing cod	le)	ı				ı
1.0μF (105)				0.5* (5)	0.5* (5)		0.8* (8)	0.8* (8)											
2.2μF (225)								0.8* (8)	0.8* (8)	0.8* (8)	1.25* (B)					1.15 (M)			
3.3μF (335)									0.8* (8)		1.25* (B)	1.25* (B)				1.6 (C)			
4.7μF (475)										0.8* (8)	1.25* (B)	1.25* (B)	1.25* (B)		1.6 (C)	1.6 (C)	1.6 (C)		
10μF (106)													1.25* (B)	1.25* (B)	1.6* (C)	1.6 (C)			
15μF (156)																		1.6* (C)	
22μF (226)														1.25* (B)				1.6* (C)	
47μF (476)																		1.6* (C)	
100μF (107)																		1.6* (C)	1.6* (C)

The part numbering code is shown in each ().

Dimensions are shown in mm and Rated Voltage in Vdc.

High Dielectric Constant Type X6S (C8) Characteristics

тс						X6S (C8)					
Part Number	GR	M15	GR	M18		GR	M21				
L x W [EIA]	1.0x0.5	5 [0402]	1.6x0.8	1.6x0.8 [0603]		2.0x1.2	5 [0805]		3	.2x1.6 [120	6]
Rated Volt.	6.3 (0J)	4 (0G)	6.3 (0J)			16 (1C)	6.3 (0J)	4 (0G)	10 (1A)	6.3 (0J)	4 (0G)
Capacitance (Ca	pacitance p	art number	ing code) an	d T (mm) Di	mension (T	Dimension p	art numberi	ng code)		I.	l.
0.15μF(154)	0.5*(5)										
0.22μF(224)	0.5*(5)										
0.33μF(334)	0.5*(5)										
0.47μF(474)	0.5*(5)										
0.68μF(684)		0.5*(5)	0.8(8)								
1.0μF(105)		0.5*(5)									
2.2μF(225)			0.8*(8)								
4.7μF(475)				0.8*(8)	1.25*(B)	1.25*(B)					
10μF(106)							1.25*(B)		1.15*(M)		
22μF(226)								1.25*(B)		1.6*(C)	1.6*(C)
47μF(476)											1.6*(C)

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.



 $^{3.3\}mu F$ and $4.7\mu F$, 6.3V rated are GRM21 series of L: 2 ± 0.15 , W: 1.25 ± 0.15 , T: 1.25 ± 0.15 .

T: 1.15 \pm 0.1mm is also available for GRM31 1.0 μ F for 16V.

L: 3.2 ± 0.2 , W: 1.6 ± 0.2 for GRM31 16V $1.0 \mu F$ type. Also L: 3.2 ± 0.2 , W: 1.6 ± 0.2 , T: 1.15 ± 0.15 for GRM31 16V $1.5 \mu F$ and $2.2 \mu F$ type.

^{*:} Please refer to GRM Series Specifications and Test Methods (2) (P.30).

^{*:} Please refer to GRM Series Specifications and Test Methods (2) (P.30).

High Dielectric Constant Type X7R (R7) Characteristics

TC											X (R	7R 1 7)										
Part Number			GRM1	5				GR	M18		(,		GRI	M21					GRM3	1	
L x W [EIA]			(0.5 [0				1	.6x0.8		3]			2.	0x1.2		5]				1.6 [1		
Rated Volt.	100 (2A)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	100 (2A)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	100 (2A)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	100 (2A)	50 (1H)	25 (1E)	16 (1C)	10 (1A)
Capacitance (Ca	apacita	ance p	art nu	ımberi	ng co	de) an	d T (m	m) Di	mensi	on (T I	Dimen	sion p	art nu	mberi	ng coo	de)						
220pF (221)		0.5 (5)				0.8 (8)																
330pF (331)		0.5 (5)				0.8 (8)																
470pF (471)		0.5 (5)				0.8 (8)																
680pF (681)		0.5 (5)				0.8 (8)																
1000pF (102)		0.5 (5)				0.8 (8)																
1500pF (152)		0.5 (5)				0.8 (8)																
2200pF (222)		0.5 (5)				0.8 (8)																
3300pF (332)		0.5 (5)				0.8 (8)																
4700pF (472)	0.5 (5)	0.5 (5)										0.85 (9)										
6800pF (682)		0.5 (5)	0.5 (5)									0.85 (9)										
10000pF (103)		0.5 (5)	0.5 (5)									1.25 (B)										
15000pF (153)			0.5 (5)	0.5 (5)			0.8 (8)					1.25 (B)										
22000pF (223)			0.5 (5)	0.5 (5)			0.8 (8)					1.25 (B)										
33000pF (333)			0.5 (5)	0.5 (5)	0.5 (5)		0.8 (8)					1.25 (B)										
47000pF (473)			0.5 (5)	0.5 (5)	0.5 (5)		0.8 (8)					1.25 (B)										
68000pF (683)				0.5 (5)	0.5 (5)		0.8 (8)	0.8 (8)										1.15 (M)				
0.10μF (104)				0.5 (5)	0.5 (5)		0.8 (8)	0.8 (8)														
0.15μF (154)								0.8 (8)	0.8 (8)				1.25 (B)						1.15 (M)			
0.22μF (224)								0.8 (8)	0.8 (8)	0.8 (8)		1.0 (A)	1.25 (B)						0.85 (9)			
0.33μF (334)									0.8 (8)	0.8 (8)		1.0 (A)	0.85 (9)	1.25 (B)								
0.47μF (474)								0.8* (8)	0.8 (8)	0.8 (8)	0.8 (8)		1.25 (B)	0.85 (9)					1.15 (M)			
0.68μF (684)										0.8 (8)				0.85 (9)	0.85 (9)							
1.0μF (105)									0.8* (8)	0.8* (8)	0.8* (8)			1.25 (B)	1.25 (B)			1.6 (C)	1.15 (M)	1.15 (M)		
1.5μF (155)														1.25 (B)	1.25 (B)				1.6 (C)	1.15 (M)	1.15 (M)	

Z continued from	the pre	ceding	page.																			
тс		X7R (R7)																				
Part Number		(GRM1	5			GRM18						GRI	M21				(SRM3	1		
L x W [EIA]		1.0x	0.5 [0	402]			1	.6x0.8	3 [0603	3]			2.	0x1.2	5 [080	5]			3.2x	1.6 [1	206]	
Rated Volt.	100 (2A)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	100 (2A)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	100 (2A)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	100 (2A)	50 (1H)	25 (1E)	16 (1C)	10 (1A)
Capacitance (Ca	pacita	ance part numbering code) and T (mm) Dimension (T Dimension part numbering code)																				
2.2μF (225)										0.8* (8)				1.25* (B)	1.25* (B)				1.6 (C)		1.15 (M)	
3.3µF (335)															1.25* (B)					1.6 (C)	1.6 (C)	
4.7μF (475)															1.25* (B)	1.25* (B)				1.6 (C)	1.6 (C)	1.6 (C)
10μF (106)																1.25* (B)	1.25* (B)				1.6* (C)	

The part numbering code is shown in each ().

High Dielectric Constant Type X7S (C7) Characteristics

тс		X7S (C7)	
Part Number	GRM18	GRM21	GRM31
L x W [EIA]	1.6x0.8 [0603]	2.0x1.25 [0805]	3.2x1.6 [1206]
Rated Volt.	6.3 (0J)	10 (1A)	4 (0G)
Capacitance (Ca	pacitance part numbering code) and T (mm	n) Dimension (T Dimension part numbering o	code)
2.2μF(225)	0.8*(8)		
3.3μF(335)		1.25*(B)	
22μF(226)			1.6*(C)

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

High Dielectric Constant Type Y5V (F5) Characteristics

тс			,			Y5V (F5)			,	,	
Part Number			GRM15			GR	M18	GR	M21	GRI	M31
L x W [EIA]		1	.0x0.5 [040	2]		1.6x0.8	3 [0603]	2.0x1.2	5 [0805]	3.2x1.6 [1206]	
Rated Volt.	50 (1H) (1E) (1C) (1A) (0J)					50 (1H)	25 (1E)	50 (1H)	25 (1E)	50 (1H)	6.3 (0J)
Capacitance (Ca	pacitance p	art numberi	ng code) an	d T (mm) Di	mension (T	Dimension p	art number	ing code)		,	
1000pF(102)	0.5(5)										
2200pF(222)	0.5(5)										
4700pF(472)	0.5(5)										
10000pF(103)	0.5(5)					0.8(8)					
22000pF(223)		0.5(5)				0.8(8)					
47000pF(473)		0.5(5)	0.5(5)			0.8(8)					
0.10μF(104)		0.5(5)	0.5(5)			0.8(8)		0.85(9)	0.6(6)		
0.22μF(224)			0.5(5)			0.8(8)	0.8(8)		0.85(9)		
0.47μF(474)			0.5(5)	0.5(5)			0.8(8)	0.85(9)	0.6(6)	1.15(M)	
1.0μF(105)				0.5*(5)	0.5*(5)						
100μF(107)											1.6*(C)

The part numbering code is shown in each ().

The tolerance will be changed to L: 3.2 ± 0.2 , W: 1.6 ± 0.2 for GRM31 16V $1.0\mu F$ type. Also L: 3.2 ± 0.2 , W: 1.6 ± 0.2 , T: 1.15 ± 0.15 for GRM31 16V $1.5\mu F$ and $2.2\mu F$ type. Dimensions are shown in mm and Rated Voltage in Vdc.

^{*:} Please refer to GRM Series Specifications and Test Methods (2) (P.30).

^{*:} Please refer to GRM Series Specifications and Test Methods (2) (P.30).

T: 1.25 ± 0.1 mm is also available for GRM21 25V or 16V $1.0\mu F$ type.

Dimensions are shown in mm and Rated Voltage in Vdc.

^{*:} Please refer to GRM Series Specifications and Test Methods (2) (P.30).

Chip Monolithic Ceramic Capacitors



for General Purpose GRM32 Series

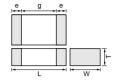
■ Features

- Terminations are made of metal highly resistant to migration.
- 2. Smaller size and higher capacitance value
- 3. High reliability and no polarity
- 4. Excellent pulse responsibility and noise reduction due to the low impedance at high frequency.
- 5. Ta replacement

■ Applications

General electronic equipment





Dort Number		D	imensions (r	nm)	
Part Number	L	W	T	е	g min.
GRM329			0.85 ±0.1		
GRM32A			1.0 +0/-0.2		
GRM32M			1.15 ±0.1		
GRM32N	3.2 +0.3	2.5 +0.2	1.35 ±0.15	0.3 min.	1.0
GRM32C	3.2 ±0.3	2.5 ±0.2	1.6 ±0.2	0.3 11111.	1.0
GRM32R			1.8 ±0.2		
GRM32D			2.0 ±0.2		
GRM32E			2.5 ±0.2		

Temperature Compensating Type GRM32 Series

Part Number	TC Code (Standard)	Rated Voltage (Vdc)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)
GRM3291X2A222JZ01	SL (JIS)	100	2200 ±5%	3.2	2.5	0.85
GRM3291X2A272JZ01	SL (JIS)	100	2700 ±5%	3.2	2.5	0.85
GRM3291X2A332JZ01	SL (JIS)	100	3300 ±5%	3.2	2.5	0.85
GRM32N1X2A562JZ01	SL (JIS)	100	5600 ±5%	3.2	2.5	1.35
GRM32N1X2A682JZ01	SL (JIS)	100	6800 ±5%	3.2	2.5	1.35

High Dielectric Constant Type GRM32 Series (3.20x2.50mm)

Part Number	TC Code (Standard)	Rated Voltage (Vdc)	Capacitance (μF)	Length L (mm)	Width W (mm)	Thickness T (mm)
GRM32ER61E226ME15	X5R (EIA)	25	22 ±20%*	3.2	2.5	2.5
GRM32ER61C226ME20	X5R (EIA)	16	22 ±20%*	3.2	2.5	2.5
GRM32ER61C476ME15	X5R (EIA)	16	47 ±20%*	3.2	2.5	2.5
GRM32ER61A226ME20	X5R (EIA)	10	22 ±20%*	3.2	2.5	2.5
GRM32ER61A476ME20	X5R (EIA)	10	47 ±20%*	3.2	2.5	2.5
GRM32DR60J226KA01	X5R (EIA)	6.3	22 ±10%*	3.2	2.5	2.0
GRM32DR60J336ME19	X5R (EIA)	6.3	33 ±20%*	3.2	2.5	2.0
GRM32ER60J476ME20	X5R (EIA)	6.3	47 ±20%*	3.2	2.5	2.5
GRM32ER60J107ME20	X5R (EIA)	6.3	100 ±20%*	3.2	2.5	2.5
GRM32DC81E106KA12	X6S(EIA)	25	10 ±10%	3.2	2.5	2.0
GRM32EC80J476ME64	X6S(EIA)	6.3	47 ±20%*	3.2	2.5	2.5
GRM32EC80G107ME20	X6S(EIA)	4	100 ±20%*	3.2	2.5	2.5
GRM32CR72A684KA01	X7R (EIA)	100	0.68 ±10%	3.2	2.5	1.6
GRM32CR72A105KA35	X7R (EIA)	100	1.0 ±10%	3.2	2.5	1.6
GRM32DR72A155KA35	X7R (EIA)	100	1.5 ±10%	3.2	2.5	2.0
GRM32ER72A225KA35	X7R (EIA)	100	2.2 ±10%*	3.2	2.5	2.5
GRM32ER71H105KA01	X7R (EIA)	50	1.0 ±10%	3.2	2.5	2.5
GRM32DR71H335KA88	X7R (EIA)	50	3.3 ±10%	3.2	2.5	2.0
GRM32ER71H475KA88	X7R (EIA)	50	4.7 ±10%	3.2	2.5	2.5
GRM32DR71E335KA01	X7R (EIA)	25	3.3 ±10%	3.2	2.5	2.0
GRM32DR71E475KA61	X7R (EIA)	25	4.7 ±10%	3.2	2.5	2.0
GRM32DR71E106KA12	X7R (EIA)	25	10 ±10%	3.2	2.5	2.0

Part Number	TC Code (Standard)	Rated Voltage (Vdc)	Capacitance (μF)	Length L (mm)	Width W (mm)	Thickness T (mm)
GRM32ER71C226ME18	X7R (EIA)	16	22 ±20%*	3.2	2.5	2.5
GRM32ER71A226ME20	X7R (EIA)	10	22 ±20%*	3.2	2.5	2.5
GRM32EF50J107ZE20	Y5V (EIA)	6.3	100 +80/-20%*	3.2	2.5	2.5

^{*:} Please refer to GRM Series Specifications and Test Methods (2) (P.30).

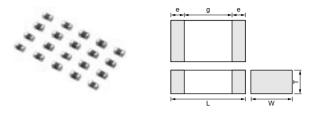
Chip Monolithic Ceramic Capacitors



Ultra-small GRM03 Series

■ Features

- 1. Small chip size (LxWxT: 0.6x0.3x0.3mm)
- 2. Terminations are made of metal highly resistant to migration.
- 3. GRM03 series is suited to only reflow soldering.
- 4. Stringent dimensional tolerances allow highly reliable, high speed automatic chip placement on
- 5. GRM03 series is suited to miniature microwave module, portable equipment and high frequency circuits.



Part Number		Dimensions (mm)									
Part Number	L	W	T	е	g min.						
GRM033	0.6 ±0.03	0.3 ±0.03	0.3 ±0.03	0.1 to 0.2	0.2						

■ Applications

- 1. Miniature microwave module
- 2. Portable equipment
- 3. High frequency circuit

Part Number						GR	M03					
LxW						0.6x0.3	[0201]					
тс	C0G (5C)	R2H (6R)	S2H (6S)	T2H (6T)		2J 'U)		5R R6)	X6S (C8)		X7R (R7)	
Rated Volt.	25 (1E)	25 (1E)	25 (1E)	25 (1E)	50 25 (1H) (1E)		10 (1A)	6.3 (0J)	4 (0G)	25 (1E)	16 (1C)	10 (1A)
Capacitance (Ca	pacitance	part numbe	ering code)	and T (mm) Dimensio	n (T Dimen	sion part n	umbering	code)			
1.0pF(1R0)	0.3(3)	0.3(3)	0.3(3)	0.3(3)								
2.0pF(2R0)	0.3(3)	0.3(3)	0.3(3)	0.3(3)								
3.0pF(3R0)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
4.0pF(4R0)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
5.0pF(5R0)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
6.0pF(6R0)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
7.0pF(7R0)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
8.0pF(8R0)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
9.0pF(9R0)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
10pF(100)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
12pF(120)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
15pF(150)	0.3(3)	0.3(3)	0.3(3)	0.3(3)	0.3(3)							
18pF(180)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)						
22pF(220)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)						
27pF(270)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)						
33pF(330)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)						
39pF(390)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)						
47pF(470)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)						
56pF(560)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)						
68pF(680)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)						
82pF(820)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)						
100pF(101)	0.3(3)	0.3(3)	0.3(3)	0.3(3)		0.3(3)				0.3(3)		
150pF(151)										0.3(3)		
220pF(221)										0.3(3)		
330pF(331)										0.3(3)		
470pF(471)										0.3(3)		
680pF(681)										0.3(3)		

Б	1
J	4

Part Number						GR	M03					
LxW				0.6x0.3 [0201]								
тс	C0G (5C)	R2H (6R)	S2H (6S)	T2H (6T)	U (7	2J U)		5R R6)	X6S (C8)		X7R (R7)	
Rated Volt.	25 (1E)	25 (1E)	25 (1E)	25 (1E)	50 (1H)	25 (1E)	10 (1A)	6.3 (0J)	4 (0G)	25 (1E)	16 (1C)	10 (1A)
Capacitance (Ca	pacitance	part numbe	ering code)	and T (mm) Dimensio	n (T Dimen	sion part n	umbering o	ode)		•	•
1000pF(102)										0.3(3)		
1500pF(152)							0.3(3)			0.3(3)		0.3(3)
2200pF(222)							0.3(3)				0.3(3)	0.3(3)
3300pF(332)							0.3(3)				0.3(3)	0.3(3)
4700pF(472)							0.3(3)					0.3(3)
6800pF(682)							0.3(3)					0.3(3)
10000pF(103)							0.3(3)					0.3(3)
15000pF(153)								0.3*(3)				
22000pF(223)								0.3*(3)				
33000pF(333)								0.3*(3)				
47000pF(473)								0.3*(3)				
68000pF(683)								0.3*(3)				
0.10μF(104)								0.3*(3)	0.3(3)			

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

^{*:} Please refer to GRM Series Specifications and Test Methods (2) (P.30).

Chip Monolithic Ceramic Capacitors

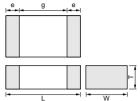


Tight Tolerance GRM03/15 Series

■ Features

- 1. Terminations are made of metal highly resistant to migration.
- 2. A wide selection of sizes is available, from the miniature LxWxT: 0.6x0.3x0.3mm or LxWxT: 1.0x0.5x0.5mm.
- 3. GRM03 type is a complete line of chip ceramic capacitors in 25V ratings, GRM15 type is a complete line of chip ceramic capacitors in 50V ratings.
- 4. These capacitors have temperature characteristics ranging C0G.
- 5. GRM03 and GRM15 type are applied to only reflow soldering.
- 6. Stringent dimensional tolerances allow highly reliable, high speed automatic chip placement on PCBs.
- 7. GRM series is available in paper tape and reel packaging for automatic placement.





Part Number		Dimensions (mm)							
Part Number	L	W	T	е	g min.				
GRM033	0.6 ±0.03	0.3 ±0.03	0.3 ±0.03	0.1 to 0.2	0.2				
GRM155	1.0 ±0.05	0.5 ±0.05	0.5 ±0.05	0.15 to 0.35	0.3				

■ Applications

General electronic equipment

Temperature Compensating Type GRM03/15 Series

Part Number		GRM03	GRM15
L x W [EIA]		0.6x0.3 [0201]	1.0x0.5 [0402]
тс		C0G (5C)	C0G (5C)
Rated Volt.		25 (1E)	50 (1H)
Capacitance, Ca	pacitance	Tolerance and T Dimension	
0.30pF(R30)	W, B	0.3(3)	0.5 (5)
0.40pF(R40)	W, B	0.3(3)	0.5(5)
0.50pF(R50)	W, B	0.3(3)	0.5 (5)
0.60pF(R60)	W, B	0.3(3)	0.5 (5)
0.70pF(R70)	W, B	0.3(3)	0.5 (5)
0.80pF(R80)	W, B	0.3(3)	0.5 (5)
0.90pF(R90)	W, B	0.3(3)	0.5 (5)
1.0pF(1R0)	W, B	0.3(3)	0.5 (5)
1.1pF(1R1)	W, B	0.3(3)	0.5 (5)
1.2pF(1R2)	W, B	0.3(3)	0.5 (5)
1.3pF(1R3)	W, B	0.3(3)	0.5 (5)
1.4pF(1R4)	W, B	0.3(3)	0.5 (5)
1.5pF(1R5)	W, B	0.3(3)	0.5 (5)
1.6pF(1R6)	W, B	0.3(3)	0.5 (5)
1.7pF(1R7)	W, B	0.3(3)	0.5 (5)
1.8pF(1R8)	W, B	0.3(3)	0.5 (5)
1.9pF(1R9)	W, B	0.3(3)	0.5 (5)
2.0pF(2R0)	W, B	0.3(3)	0.5 (5)
2.1pF(2R1)	W, B	0.3(3)	0.5 (5)
2.2pF(2R2)	W, B	0.3(3)	0.5 (5)
2.3pF(2R3)	W, B	0.3 (3)	0.5 (5)

Part Number		GRM03	GRM15
L x W [EIA]		0.6x0.3 [0201]	1.0x0.5 [0402]
тс		C0G (5C)	C0G (5C)
Rated Volt.		25 (1E)	50 (1H)
-		ee Tolerance and T Dimension	
2.4pF(2R4)	W, B	0.3(3)	0.5(5)
2.5pF(2R5)	W, B	0.3(3)	0.5(5)
2.6pF(2R6)	W, B	0.3(3)	0.5(5)
2.7pF(2R7)	W, B	0.3(3)	0.5(5)
2.8pF(2R8)	W, B	0.3(3)	0.5(5)
2.9pF(2R9)	W, B	0.3(3)	0.5(5)
3.0pF(3R0)	W, B	0.3(3)	0.5(5)
3.1pF(3R1)	W, B	0.3(3)	0.5(5)
3.2pF(3R2)	W, B	0.3(3)	0.5(5)
3.3pF(3R3) 3.4pF(3R4)	W, B	0.3(3)	0.5(5)
3.4pF(3R4) 3.5pF(3R5)	W, B W, B	0.3(3) 0.3(3)	0.5(5) 0.5(5)
3.6pF(3R6)	W, B	0.3(3)	0.5(5)
3.7pF(3R7)	W, B	0.3(3)	0.5(5)
3.8pF(3R8)	W, B	0.3(3)	0.5(5)
3.9pF(3R9)	W, B	0.3(3)	0.5(5)
4.0pF(4R0)	W, B	0.3(3)	0.5(5)
4.1pF(4R1)	W, B	0.3(3)	0.5(5)
4.2pF(4R2)	W, B	0.3(3)	0.5(5)
4.3pF(4R3)	W, B	0.3(3)	0.5(5)
4.4pF(4R4)	W, B	0.3(3)	0.5(5)
4.5pF(4R5)	W, B	0.3(3)	0.5(5)
4.6pF(4R6)	W, B	0.3(3)	0.5(5)
4.7pF(4R7)	W, B	0.3(3)	0.5(5)
4.8pF(4R8)	W, B	0.3(3)	0.5(5)
4.9pF(4R9)	W, B	0.3(3)	0.5(5)
5.0pF(5R0)	W, B	0.3(3)	0.5(5)
5.1pF(5R1)	W, B, C	0.3(3)	0.5(5)
5.2pF(5R2)	W, B, C	0.3(3)	0.5(5)
5.3pF(5R3)	W, B, C	0.3(3)	0.5(5)
5.4pF(5R4)	W, B, C	0.3(3)	0.5(5)
		0.3(3)	0.5(5)
5.6pF(5R6)	W, B, C	0.3(3)	0.5(5)
5.7pF(5R7)	W, B, C	0.3(3)	0.5(5)
5.8pF(5R8)	W, B, C	0.3(3)	0.5 (5)
		0.3(3)	0.5(5)
6.0pF(6R0)	W, B, C	0.3(3)	0.5(5)
6.1pF(6R1)	W, B, C	0.3(3)	0.5(5)
6.2pF(6R2) 6.3pF(6R3)	W, B, C W, B, C	0.3(3) 0.3(3)	0.5(5) 0.5(5)
6.4pF(6R4)	W, B, C	0.3(3)	0.5(5)
6.5pF(6R5)	W, B, C	0.3(3)	0.5(5)
6.6pF(6R6)	W, B, C	0.3(3)	0.5(5)
6.7pF(6R7)	W, B, C	0.3(3)	0.5(5)
6.8pF(6R8)	W, B, C	0.3(3)	0.5(5)
6.9pF(6R9)	W, B, C	0.3(3)	0.5(5)
7.0pF(7R0)	W, B, C	0.3(3)	0.5(5)
7.1pF(7R1)		0.3(3)	0.5(5)
7.2pF(7R2)	W, B, C	0.3(3)	0.5(5)
7.3pF(7R3)	W, B, C	0.3(3)	0.5(5)
7.4pF(7R4)	W, B, C	0.3(3)	0.5(5)
7.5pF(7R5)		0.3(3)	0.5(5)
/	· · · · ·	· · ·	<u> </u>



Part Number		GRM03	GRM15
L x W [EIA]		0.6x0.3 [0201]	1.0x0.5 [0402]
тс		C0G (5C)	C0G (5C)
Rated Volt.		25 (1E)	50 (1H)
Capacitance, Ca	apacitance Toleranc	e and T Dimension	
7.6pF(7R6)	W, B, C	0.3 (3)	0.5(5)
7.7pF(7R7)	W, B, C	0.3(3)	0.5 (5)
7.8pF(7R8)	W, B, C	0.3 (3)	0.5 (5)
7.9pF(7R9)	W, B, C	0.3(3)	0.5 (5)
8.0pF(8R0)	W, B, C	0.3(3)	0.5 (5)
8.1pF(8R1)	W, B, C	0.3(3)	0.5 (5)
8.2pF(8R2)	W, B, C	0.3(3)	0.5 (5)
8.3pF(8R3)	W, B, C	0.3(3)	0.5 (5)
8.4pF(8R4)	W, B, C	0.3(3)	0.5 (5)
8.5pF(8R5)	W, B, C	0.3(3)	0.5 (5)
8.6pF(8R6)	W, B, C	0.3(3)	0.5 (5)
8.7pF(8R7)	W, B, C	0.3(3)	0.5 (5)
8.8pF(8R8)	W, B, C	0.3(3)	0.5 (5)
8.9pF(8R9)	W, B, C	0.3 (3)	0.5 (5)
9.0pF(9R0)	W, B, C	0.3(3)	0.5 (5)
9.1pF(9R1)	W, B, C	0.3(3)	0.5 (5)
9.2pF(9R2)	W, B, C	0.3(3)	0.5 (5)
9.3pF(9R3)	W, B, C	0.3 (3)	0.5 (5)
9.4pF(9R4)	W, B, C	0.3 (3)	0.5 (5)
9.5pF(9R5)		0.3(3)	0.5 (5)
9.6pF(9R6)	W, B, C	0.3 (3)	0.5 (5)
9.7pF(9R7)	W, B, C	0.3 (3)	0.5 (5)
9.8pF(9R8)	W, B, C	0.3 (3)	0.5 (5)
9.9pF(9R9)	W, B, C	0.3(3)	0.5(5)

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

Chip Monolithic Ceramic Capacitors



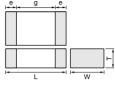
Thin Type

■ Features

- 1. This series is suited to flow and reflow soldering. Capacitor terminations are made of metal highly resistant to migration.
- 2. Large capacitance values enable excellent bypass effects to be realized.
- 3. GRM18, 21 and GRM31 types are suited to flow and reflow soldering. GRM15 and GRM32 types are applied to only reflow soldering.
- 4. Its thin package makes this series ideally suited for the production of small electronic products and for mounting underneath ICs.



Thin equipment such as IC cards



Part Number	Dimensions (mm)							
Fait Number	L	W	T	е	g min.			
GRM15X	1 0 10 05	0.5 +0.05	0.25 ±0.05	0.1 to 0.3	0.4			
GRM153	1.0 ±0.05	0.5 ±0.05	0.3 ±0.03	0.1 10 0.3	0.4			
GRM216			0.6 ±0.1					
GRM219	2.0 ± 0.1	1.25 ±0.1	0.85 ±0.1	0.2 to 0.7	0.7			
GRM21A			1.0 +0/-0.2					
GRM316	2 2 10 15	1.6 ±0.15	0.6 ±0.1	0.2 to 0.0	1.5			
GRM319	3.2 ±0.15	1.6 ±0.15	0.85 ±0.1	0.3 to 0.8	1.5			
GRM329	3.2 +0.3	2.5 +0.2	0.85 ±0.1	0.3 min.	1.0			
GRM32A	3.∠ ±0.3	2.5 ±0.2	1.0 +0/-0.2	U.S MIII.	1.0			

Temperature Compensating Type

Part Number	TC Code (Standard)	Rated Voltage (Vdc)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	EIA
GRM1535C1H1R0CDD5	C0G (EIA)	50	1.0 ±0.25pF	1.0	0.5	0.3	0402
GRM1535C1H2R0CDD5	C0G (EIA)	50	2.0 ±0.25pF	1.0	0.5	0.3	0402
GRM1535C1H3R0CDD5	C0G (EIA)	50	3.0 ±0.25pF	1.0	0.5	0.3	0402
GRM1535C1H4R0CDD5	C0G (EIA)	50	4.0 ±0.25pF	1.0	0.5	0.3	0402
GRM1535C1H5R0CDD5	C0G (EIA)	50	5.0 ±0.25pF	1.0	0.5	0.3	0402
GRM1535C1H6R0DDD5	C0G (EIA)	50	6.0 ±0.5pF	1.0	0.5	0.3	0402
GRM1535C1H7R0DDD5	COG (EIA)	50	7.0 ±0.5pF	1.0	0.5	0.3	0402
GRM1535C1H8R0DDD5	COG (EIA)	50	8.0 ±0.5pF	1.0	0.5	0.3	0402
GRM1535C1H9R0DDD5	COG (EIA)	50	9.0 ±0.5pF	1.0	0.5	0.3	0402
GRM1535C1H100JDD5	COG (EIA)	50	10 ±5%	1.0	0.5	0.3	0402
GRM1535C1H120JDD5	COG (EIA)	50	12 ±5%	1.0	0.5	0.3	0402
GRM1535C1H150JDD5	COG (EIA)	50	15 ±5%	1.0	0.5	0.3	0402
GRM1535C1H180JDD5	COG (EIA)	50	18 ±5%	1.0	0.5	0.3	0402
GRM1535C1H220JDD5	COG (EIA)	50	22 ±5%	1.0	0.5	0.3	0402
GRM1535C1H270JDD5	COG (EIA)	50	27 ±5%	1.0	0.5	0.3	0402
GRM1535C1H330JDD5	COG (EIA)	50	33 ±5%	1.0	0.5	0.3	0402
GRM1535C1H390JDD5	COG (EIA)	50	39 ±5%	1.0	0.5	0.3	0402
GRM1535C1H470JDD5	COG (EIA)	50	47 ±5%	1.0	0.5	0.3	0402
GRM1535C1H560JDD5	COG (EIA)	50	56 ±5%	1.0	0.5	0.3	0402
GRM1535C1H680JDD5	COG (EIA)	50	68 ±5%	1.0	0.5	0.3	0402
GRM1535C1H820JDD5	COG (EIA)	50	82 ±5%	1.0	0.5	0.3	0402
GRM1535C1H101JDD5	COG (EIA)	50	100 ±5%	1.0	0.5	0.3	0402



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High Dielectric Constant Type

Part Number	TC Code (Standard)	Rated Voltage (Vdc)	Capacitance	Length L (mm)	Width W (mm)	Thickness T (mm)	EIA
GRM15XR71H221KA86	X7R (EIA)	50	220pF ±10%	1.0	0.5	0.25	0402
GRM15XR71H331KA86	X7R (EIA)	50	330pF ±10%	1.0	0.5	0.25	0402
GRM15XR71H471KA86	X7R (EIA)	50	470pF ±10%	1.0	0.5	0.25	0402
GRM15XR71H681KA86	X7R (EIA)	50	680pF ±10%	1.0	0.5	0.25	0402
GRM15XR71H102KA86	X7R (EIA)	50	1000pF ±10%	1.0	0.5	0.25	0402
GRM15XR71H152KA86	X7R (EIA)	50	1500pF ±10%	1.0	0.5	0.25	0402
GRM15XR71E222KA86	X7R (EIA)	25	2200pF ±10%	1.0	0.5	0.25	0402
GRM219R71E105KA88	X7R (EIA)	25	1.0μF ±10%	2.0	1.25	0.85	0805
GRM15XR71C332KA86	X7R (EIA)	16	3300pF ±10%	1.0	0.5	0.25	0402
GRM15XR71C472KA86	X7R (EIA)	16	4700pF ±10%	1.0	0.5	0.25	0402
GRM15XR71C682KA86	X7R (EIA)	16	6800pF ±10%	1.0	0.5	0.25	0402
GRM15XR71C103KA86	X7R (EIA)	16	10000pF ±10%	1.0	0.5	0.25	0402
GRM216C81C105KA12	X6S(EIA)	16	1.0μF ±10%	2.0	1.25	0.6*	0805
GRM316C81C225KA12	X6S(EIA)	16	2.2μF ±10%	3.2	1.6	0.6*	1206
GRM219C81C225KA12	X6S(EIA)	16	2.2μF ±10%	2.0	1.25	0.85*	0805
GRM319C81C475KA12	X6S(EIA)	16	4.7μF ±10%	3.2	1.6	0.85*	1206
GRM219C81A475KE34	X6S(EIA)	10	4.7μF ±10%	2.0	1.25	0.85*	0805
GRM219C80J475KE19	X6S(EIA)	6.3	4.7μF ±10%	2.0	1.25	0.85*	0805
GRM319C80J106KE19	X6S(EIA)	6.3	10μF ±10%	3.2	1.6	0.85*	1206
GRM219C80G106KE19	X6S(EIA)	4	10μF ±10%	2.0	1.25	0.85*	0805
GRM216R61E105KA12	X5R (EIA)	25	1.0μF ±10%	2.0	1.25	0.6*	0805
GRM316R61E225KA12	X5R (EIA)	25	2.2μF ±10%	3.2	1.6	0.6*	1206
GRM219R61E225KA12	X5R (EIA)	25	2.2μF ±10%	2.0	1.25	0.85*	0805
GRM319R61E475KA12	X5R (EIA)	25	4.7μF ±10%	3.2	1.6	0.85*	1206
GRM216R61C105KA88	X5R (EIA)	16	1.0μF ±10%	2.0	1.25	0.6*	0805
GRM316R61C225KA88	X5R (EIA)	16	2.2μF ±10%	3.2	1.6	0.6*	1206
GRM219R61C225KA88	X5R (EIA)	16	2.2μF ±10%	2.0	1.25	0.85*	0805
GRM219R61C475KE15	X5R (EIA)	16	4.7μF ±10%	2.0	1.25	0.85*	0805
GRM319R61C475KA88	X5R (EIA)	16	4.7μF ±10%	3.2	1.6	0.85*	1206
GRM319R61C106KE15	X5R (EIA)	16	10μF ±10%	3.2	1.6	0.85*	1206
GRM216R61A225KE24	X5R (EIA)	10	2.2μF ±10%	2.0	1.25	0.6*	0805
GRM219R61A225KA01	X5R (EIA)	10	2.2μF ±10%	2.0	1.25	0.85*	0805
GRM316R61A335KE19	X5R (EIA)	10	3.3μF ±10%	3.2	1.6	0.6*	1206
GRM219R61A335KE19	X5R (EIA)	10	3.3μF ±10%	2.0	1.25	0.85*	0805
GRM316R61A475KE19	X5R (EIA)	10	4.7μF ±10%	3.2	1.6	0.6*	1206
GRM219R61A475KE34	X5R (EIA)	10	4.7μF ±10%	2.0	1.25	0.85*	0805
GRM319R61A106KE19	X5R (EIA)	10	10μF ±10%	3.2	1.6	0.85*	1206
GRM219R60J475KE19	X5R (EIA)	6.3	4.7μF ±10%	2.0	1.25	0.85*	0805
GRM319R60J106KE19	X5R (EIA)	6.3	10μF ±10%	3.2	1.6	0.85*	1206

^{*:} Please refer to GRM Series Specifications and Test Methods (2) (P.30).

Below GRM Series Specifications and Test Methods (1) are applied to Non "*" PNs in capacitance table. In case "*" is added in capacitance table, please refer to GRM Series Specifications and Test Methods (2) (P.30).

			cations	eter to GRM Series Specifications and Test Methods (2) (P.30).			
No.	Item	Temperature Compensating Type	High Dielectric Type	Test Method			
1	Operating Temperature Range	-55 to +125 c		Reference temperature: 25° C (2Δ , 3Δ , 4Δ , B1, B3, F1, R1: 20° C)			
2	Rated Voltage	See the previous pages.		The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p-p} or V ^{o-p} , whichever is larger, should be maintained within the rated voltage range.			
3	Appearance	No defects or abnormalities		Visual inspection			
4	Dimensions	Within the specified dimensions	;	Using calipers (GRM02 size is based on Microscope)			
5	Dielectric Strength	No defects or abnormalities		No failure should be observed when 300%* of the rated voltage (temperature compensating type) or 250% of the rated voltage (high dielectric constant type) is applied between the terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA. *200% for 500V			
6	Insulation Resistance	C≤0.047μF: More than 10,000N C>0.047μF: 500Ω · F	MΩ C: Nominal Capacitance	The insulation resistance should be measured with a DC voltage not exceeding the rated voltage at 20/25°C and 75%RH max. and within 2 minutes of charging, provided the charge/discharge current is less than 50mA.			
7	Capacitance	Within the specified tolerance					
8	Q/ Dissipation Factor (D.F.)	30pF and over: Q≥1000 30pF and below: Q≥400+20C C: Nominal Capacitance (pF)	[R6, R7, C8] W.V.: 100V : 0.025 max. (C<0.068μF) : 0.05 max. (C≥0.068μF) W.V.: 50/25V : 0.025 max. (C≥10μF) : 0.035 max. (C≥10μF) W.V.: 16/10V: 0.035 max. W.V.: 6.3/4V : 0.05 max. (C≤3.3μF) : 0.1 max. (C≥3.3μF) [E4] W.V.: 25Vmin: 0.025 max. [F1, F5] W.V.: 25V min. : 0.05 max. (C<0.1μF) : 0.09 max. (C≥0.1μF) W.V.: 16/10V: 0.125 max. W.V.: 6.3V: 0.15 max.	The capacitance/Q/D.F. should be measured at $20/25^{\circ}$ C at the frequency and voltage shown in the table. Char. ΔC to 7U, 1X (more than 1000pF) R6, R7, C8, F5, B1, B3, F1 Frequency $1\pm 0.1 \text{MHz}$ $1\pm 0.1 \text{kHz}$ $120\pm 24 \text{kHz}$ $1\pm 0.1 \text{kHz}$ Voltage 0.5 to 5Vrms $1\pm 0.2 \text{Vrms}$ $0.5\pm 0.05 \text{Vrms}$			





Below GRM Series Specifications and Test Methods (1) are applied to Non "*" PNs in capacitance table.

Continued from the preceding page. In case "*" is added in capacitance table, please refer to GRM Series Specifications and Test Methods (2) (P.30).

	Specif						t Methods (2) (P.30).	
tem	Temperature Compensating Type	High Dielectric Type			Test Me	ethod		
No bias	Within the specified tolerance (Table A-1)	(-25 to +85°C) R1, R7: Within ±15% (-55 to +125°C) R6: Within ±15% (-55 to +85°C) E4: Within ±22/-56% (+10 to +85°C) F1: Within +30/-80% (-25 to +85°C) F5: Within +22/-82% (-30 to +85°C) C8: Within ±22%			The capacitance change should be measured after 5 min. at each specified temp. stage. (1)Temperature Compensating Type The temperature coefficient is determined using the capacitance measured in step 3 as a reference. When cycling the temperature sequentially from step 1 throug 5 (5C: +25 to +125°C/AC: +20 to +125°C: other temp. coeffs: +25 to +85°C/+20 to +85°C) the capacitance should be within the specified tolerance for the temperature coefficient and capacitance change as Table A-1. The capacitance drift is calculated by dividing the differences between the maximum and minimum measured values in the step 1, 3 and 5 by the cap. value in step 3.			
		(00 10 1 100 5)	-			•	• •	
50% of the Rated		B1: Within +10/–30% R1: Within +15/–40%	2	2	-55±3 (fo -30±3 -29	r ΔC to 7 (for F5), 5±3 (for C	U/1X/R6/R7/C8) 10±3 (for E4) other TC)	
Voltage		F1: Within +30/–95%		,			·	
			5	5	Refere	ence Tem	perature ±2	
Capacitance Drift	Within ±0.2% or ±0.05pF (Whichever is larger.) ∗Do not apply to 1X/25V	*Initial measurement for high dielectric constant type Perform a heat treatment at 150+0/-10°C for one hour and then set for 24±2 hours at room temperature. Perform the initial measurement.	value over be within the In case of a measured a	the tempine specifical applying variety 1 mm of each remark remarks re	erature range ed ranges.* voltage, the core min. with temp. stage. sperature (°C noe Temperar 3 (for R1, R7-3 (for B1, B3 for F5)/10±3 ce Temperar ±3 (for R1, F3 (for B1, B3 F1, F5, E4) sperature (°C noe Temperar 55±3 (for B1, B3 F1, F5, E4) sperature (°C noe Temperar 55±3 (for B1, B3 F1, F5, E4) sperature range	s shown apacitance applying) ture ±2 , R6) , F1) (for E4) ture ±2 R7)/ , R6 ture ±2)/ =1) ture ±2)/	in the table should ce change should be	
_	No removal of the terminations or other defect should occur. C Solder resist Baked electrode or copper foil		Fig. 1a usin parallel with The soldering is soldering is *1N (GRM GRM02 GRM03 GRM15 GRM15 GRM21	ng an euth h the test ing should and s s uniform (02), 2N (02) pe	ectic solder. jig for 10±1: d be done eit hould be con and free of d	Then app sec. her with a ducted we fects su (GRM15, 0.56 0.9 1.5 3.0	10N* force in 2 2 2 2 2 2 2 2 2	
	50% of the Rated Voltage	No bias Within the specified tolerance (Table A-1) Solve Strength ination Temperature Compensating Type Within the specified tolerance (Table A-1) Within ±0.2% or ±0.05pF (Whichever is larger.) *Do not apply to 1X/25V	No bias No bias Within the specified tolerance (Table A-1) Within ±10% (-55 to +85°C) R1, R7: Within ±15% (-55 to +85°C) R6: Within ±15% (-55 to +85°C) E4: Within ±30/-80% (-51 to +85°C) F1: Within ±30/-80% (-50 to +85°C) F3: Within ±22/-56% (-30 to +85°C) F3: Within ±22/-65% (-55 to +105°C) S0% of the Rated Voltage Within ±0.2% or ±0.05pF (Whichever is larger.) *Do not apply to 1X/25V Within ±15/-40% F1: Within ±15/	Temperature Compensating Type B1, B3: Within ±10% (-25 to +85°C) R1, R7: Within ±15% (-55 to +125°C) R6: Within ±15% (-55 to +125°C) R6: Within ±22/-56% (+10 to +85°C) F1: Within ±30/-80% (-25 to +86°C) F1: Within ±22/-82% (-30 to +85°C) C8: Within ±22% (-30 to +85°C) C8: Within ±30/-95% B1: Within ±10/-30% R1: Within ±10/-30% R1: Within ±10/-30% R1: Within ±10/-95% S1. Within ±10/-2% or ±0.05pF (Whichever is larger) **Do not apply to 1X/25V Within ±10/-2% or ±0.05pF (Whichever is larger) **Do not apply to 1X/25V No removal of the terminations or other defect should occur. F1. Within ±10/-10/-10/-10/-10/-10/-10/-10/-10/-10/-	Temperature Compensating Type B1, B3: Within ±10% (-25 to +85°C) R1, R7: Within ±15% (-25 to +125°C) R6: Within ±15% (-55 to +125°C) R6: Within ±22′–56% (-75 to +85°C) F1: Within ±0.2~6% (-75 to +85°C) F2: Within ±22′–82% (-75 to +85°C) F3: Within ±22′–82% (-75 to +105°C) F3: Within ±22′–82% (-75 to +85°C) F3: Within ±10″–95% F3: Within ±22′–82% (-75 to +85°C) F3: Within ±22′–82% (-75 to +85°C) F3: Within ±22′–82% (-75 to ±105°C) F3: Within ±22′–20% (-75 to ±105°C) F3: Within ±22′	Temperature Compensating Type High Dielectric Type	Temperature Componsating Type	



Below GRM Series Specifications and Test Methods (1) are applied to Non "*" PNs in capacitance table. In case "*" is added in capacitance table, please refer to GRM Series Specifications and Test Methods (2) (P.30). Continued from the preceding page.

	Continued fr	om the prec		d in capacitance table, please re	efer to GRM Series S	Specifications	and Test Met	hods (2) (P.30).
			Specifi	ications				
No.	Ite	em	Temperature Compensating Type	High Dielectric Type		Test Me	ethod	
		Appearance	No defects or abnormalities					
		Capacitance	Within the specified tolerance					
11	Vibration Resistance	Q/D.F.	30pF and over: Q≥1000 30pF and below: Q≥400+20C C: Nominal Capacitance (pF)	[B1, B3, R6, R7, C8] W.V.: 100V : 0.025 max. (C<0.068μF) : 0.05 max. (C≥0.068μF) W.V.: 50/25V : 0.025 max. (C<10μF) : 0.035 max. (C≥10μF) W.V.: 16/10V: 0.035 max. W.V.: 6.3/4V : 0.05 max. (C≥3.3μF) : 0.1 max. (C≥3.3μF) [E4] W.V.: 25Vmin: 0.025 max. [F1, F5] W.V.: 25V min. : 0.05 max. (C<0.1μF) : 0.09 max. (C≥0.1μF) W.V.: 16/10V: 0.125 max. W.V.: 6.3V: 0.15 max.	Solder the capacitor on the test jig (glass epoxy board) in same manner and under the same conditions as (10). The capacitor should be subjected to a simple harmonic relaying a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz frequency range, from 10 to 55Hz and return to 10Hz, sho be traversed in approximately 1 minute. This motion should applied for a period of 2 hours in each of 3 mutually perpendicular directions (total of 6 hours).			
			No crack or marked defect shou	ed defect should occur.		eutectic solde Fig. 3a for 5± method and s	hould be cond	
12	12 Deflection		Pressurizing speed: 1.0mm/sec. Pressurize R230 Flection			100 Fig.	\$4.5	
			Capacitance r	meter	GRM02 GRM03	0.2	0.56	0.23
			45	45	GRM15	0.4	1.5	0.5
				ı	GRM18	1.0	3.0	1.2
			Fig. 3a		GRM21	1.2	4.0	1.65
					GRM31	2.2	5.0	2.0
					GRM32	2.2	5.0	2.9
					GRM43	3.5	7.0	3.7
					GRM55	4.5	8.0	5.6 (in mm)
13	Solderability of Termination		75% of the terminations are to be soldered evenly and continuously.		(in mm) Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion) . Preheat at 80 to 120°C for 10 to 30 seconds. After preheating, immerse in an eutectic solder solution for 2±0.5 seconds at 230±5°C or Sn-3.0Ag-0.5Cu solder solution for 2±0.5 seconds at 245±5°C.			





Below GRM Series Specifications and Test Methods (1) are applied to Non "*" PNs in capacitance table.

Continued from the preceding page. In case "*" is added in capacitance table, please refer to GRM Series Specifications and Test Methods (2) (P.30).

			Specif	ications					
No.	lt∈	em	Temperature Compensating Type	High Dielectric Type	Test Method				
			The measured and observed cl specifications in the following ta	naracteristics should satisfy the able.					
		Appearance	No defects or abnormalities						
		Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	B1, B3, R1, R6, R7, C8 : Within ±7.5% F1, F5, E4: Within ±20%					
to	Soldering	Q/D.F.	30pF and over: Q≥1000 30pF and below: Q≥400+20C C: Nominal Capacitance (pF)	[B1, B3, R6, R7, C8] W.V.: 100V : 0.025 max. (C<0.068μF) : 0.05 max. (C≥0.068μF) W.V.: 50/25V : 0.025 max. (C<10μF) : 0.035 max. (C≥10μF) W.V.: 16/10V: 0.035 max. W.V.: 6.3/4V : 0.05 max. (C<3.3μF) : 0.1 max. (C≥3.3μF)	Preheat the capacitor at 120 to 150°C for 1 minute. Immerse the capacitor in an eutectic solder or Sn-3.0Ag-0.50 solder solution at 270±5°C for 10±0.5 seconds. Set at room temperature for 24±2 hours, then measure. •Initial measurement for high dielectric constant type Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement. •Preheating for GRM32/43/55				
				W.V.: 25Vmin: 0.025 max.	Step Temperature Time 1 100 to 120℃ 1 min.				
					[F1, F5] W.V.: 25V min. : 0.05 max. (C<0.1μF) : 0.09 max. (C≧0.1μF) W.V.: 16/10V: 0.125 max. W.V.: 6.3V: 0.15 max.	2 170 to 200°C 1 min.			
		I.R.	More than $10,000\text{M}\Omega$ or 500Ω	F (Whichever is smaller)					
		Dielectric Strength	No defects						
			The measured and observed cl specifications in the following to	naracteristics should satisfy the able.					
		Appearance	No defects or abnormalities		1				
		Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	B1, B3, R1, R6, R7, C8 : Within ±7.5% F1, F5, E4: Within ±20%	Fix the capacitor to the supporting jig in the same manner and under the same conditions as (10). Perform the five cycles according to the four heat treatments				
				[R6, R7, C8] W.V.: 100V	shown in the following table. Set for 24±2 hours at room temperature, then measure.				
				: 0.05 max. (C<0.068µF)	Step 1 2 3 4				
				: 0.075 max. (C≧0.068µF) W.V.: 50/25/16/10V	Min. Room Max. Room				
				: 0.05 max.	Temp. (°C) Operating Temp. Operating Temp. Temp. Temp.				
15	Temperature Cycle		30pF and over: Q≧1000	W.V.: 6.3/4V : 0.075 max. (C<3.3µF)	Time (min.) 30±3 2 to 3 30±3 2 to 3				
	2,5.0	Q/D.F.	30pF and below: Q≧400+20C	: 0.125 max. (C≥3.3μF)	•Initial measurement for high dielectric constant type				
			C: Nominal Capacitance (pF)	[E4] W.V.: 25Vmin: 0.05 max. [F1, F5] W.V.: 25V min. : 0.05 max. (C<0.1μF) : 0.09 max. (C≥0.1μF)	Perform a heat treatment at 150+0/−10°C for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement.				
				W.V.: 16/10V: 0.125 max. W.V.: 6.3V: 0.15 max.					
		I.R.	More than 10,000M Ω or 500 Ω		-				
		Dielectric	-	,	-				
		Strength	No defects						





Below GRM Series Specifications and Test Methods (1) are applied to Non "*" PNs in capacitance table. In case "*" is added in capacitance table, please refer to GRM Series Specifications and Test Methods (2) (P.30). Continued from the preceding page.

			Specif	ications			
lo.	Ite	m	Temperature Compensating Type	High Dielectric Type	Test Method		
			The measured and observed of specifications in the following to	•			
		Appearance	No defects or abnormalities				
16		Capacitance Change	Within ±5% or ±0.5pF (Whichever is larger)	B1, B3, R1, R6, R7, C8 : Within ±12.5% F1, F5, E4: Within ±30%			
	Humidity (Steady State)	Q/D.F.	30pF and over: Q≥350 10pF and over 30pF and below: Q≥275+2.5C 10pF and below: Q≥200+10C C: Nominal Capacitance (pF)	[R6, R7, C8] W.V.: 100V : 0.05 max. (C<0.068μF) : 0.075 max. (C≥0.068μF) W.V.: 50/25/16/10V : 0.05 max. W.V.: 6.3/4V : 0.075 max. (C≥3.3μF) : 0.125 max. (C≥3.3μF) [E4] W.V.: 25Vmin: 0.05 max. [F1, F5] W.V.: 25V min. : 0.075 max. (C<0.1μF) : 0.125 max. (C≥0.1μF) W.V.: 16/10V: 0.15 max. W.V.: 6.3V: 0.2 max.	Set the capacitor at $40\pm2^{\circ}$ C and in 90 to 95% humidity for 500±12 hours. Remove and set for 24±2 hours at room temperature, then measure.		
		I.R.	More than $1,000M\Omega$ or $50\Omega \cdot F$	· · · · · · · · · · · · · · · · · · ·			
			The measured and observed characteristics should satisfy the specifications in the following table.				
		Appearance	No defects or abnormalities				
		Capacitance Change	Within ±7.5% or ±0.75pF (Whichever is larger)	B1, B3, R1, R6, R7, C8 : Within ±12.5% F1, F5, E4: Within ±30% [W.V.: 10V max.] F1, F5: Within +30/-40%			
17	Humidity Load	Q/D.F.	30pF and over: Q≥200 30pF and below: Q≥100+10C/3 C: Nominal Capacitance (pF)	[B1, B3, R6, R7, C8] W.V.: 100V : 0.05 max. (C<0.068μF) : 0.075 max. (C≥0.068μF) W.V.: 50/25/16/10V : 0.05 max. W.V.: 6.3/4V : 0.075 max. (C<3.3μF) : 0.125 max. (C≥3.3μF) [E4] W.V.: 25Vmin: 0.05 max. [F1, F5] W.V.: 25V min. : 0.075 max. (C<0.1μF) : 0.125 max. (C≥0.1μF) W.V.: 16/10V: 0.15 max. W.V.: 6.3V: 0.2 max.	Apply the rated voltage at 40±2°C and 90 to 95% humidity fo 500±12 hours. Remove and set for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA. •Initial measurement for F1, F5/10V max. Apply the rated DC voltage for 1 hour at 40±2°C. Remove and set for 24±2 hours at room temperature. Perform initial measurement.		
					1		





Below GRM Series Specifications and Test Methods (1) are applied to Non "*" PNs in capacitance table.

Continued from the preceding page. In case "*" is added in capacitance table, please refer to GRM Series Specifications and Test Methods (2) (P.30).

			Specif	ications	
No.	lt∈	em	Temperature Compensating Type	High Dielectric Type	Test Method
			The measured and observed characteristics should satisfy the specifications in the following table.		
		Appearance	No defects or abnormalities		
		Capacitance Change	Within ±3% or ±0.3pF (Whichever is larger)	B1, B3, R1, R6, R7, C8 : Within ±12.5% F1, F5, E4: Within ±30% [Except 10V max. and. C≥1.0µF] F1, F5: Within +30/-40% [10V max. and C≥1.0µF]	Apply 200%* of the rated voltage at the maximum operating temperature ±3℃ for 1000±12 hours.
18	High Temperature Load	Q/D.F.	30pF and over: Q≥350 10pF and over 30pF and below: Q≥275+2.5C 10pF and below: Q≥200+10C C: Nominal Capacitance (pF)	[B1, B3, R6, R7, C8] W.V.: 100V : 0.05 max. (C<0.068μF) : 0.075 max. (C≥0.068μF) W.V.: 50/25/16/10V : 0.05 max. W.V.: 6.3/4V : 0.075 max. (C<3.3μF) : 0.125 max. (C≥3.3μF) [E4] W.V.: 25Vmin: 0.05 max. [F1, F5] W.V.: 25V min. : 0.075 max.(C<0.1μF) : 0.125 max.(C≥0.1μF) W.V.: 16/10V: 0.15 max. W.V.: 6.3V: 0.2 max.	Set for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA. •Initial measurement for high dielectric constant type. Apply 200% of the rated DC voltage at the maximum operating temperature ±3°C for one hour. Remove and set for 24±2 hours at room temperature. Perform initial measurement. *150% for 500V
		I.R.	More than 1,000M Ω or 50 Ω \cdot F	(Whichever is smaller)	

Table A-1

(1)								
		Capacitance Change from 25℃ (%)						
Char.	Nominal Values (ppm/℃)*1	-55		-30		-10		
		Max.	Min.	Max.	Min.	Max.	Min.	
5C	0± 30	0.58	-0.24	0.40	-0.17	0.25	-0.11	
6C	0± 60	0.87	-0.48	0.59	-0.33	0.38	-0.21	
6P	-150± 60	2.33	0.72	1.61	0.50	1.02	0.32	
6R	-220± 60	3.02	1.28	2.08	0.88	1.32	0.56	
6S	-330± 60	4.09	2.16	2.81	1.49	1.79	0.95	
6T	-470± 60	5.46	3.28	3.75	2.26	2.39	1.44	
7U	-750±120	8.78	5.04	6.04	3.47	3.84	2.21	
1X	+350 to -1000	_	_	_	_	_	_	

^{*1:} Nominal values denote the temperature coefficient within a range of 25°C to 125°C (for ΔC)/85°C (for other TC).

(2)

		Capacitance Change from 20°C (%)						
Char.	Nominal Values (ppm/℃)*2	_	-55		-25		-10	
		Max.	Min.	Max.	Min.	Max.	Min.	
2C	0± 60	0.82	-0.45	0.49	-0.27	0.33	-0.18	
3C	0±120	1.37	-0.90	0.82	-0.54	0.55	-0.36	
4C	0±250	2.56	-1.88	1.54	-1.13	1.02	-0.75	
2P	-150± 60	_	_	1.32	0.41	0.88	0.27	
3P	-150±120	_	_	1.65	0.14	1.10	0.09	
4P	-150±250	_	_	2.36	-0.45	1.57	-0.30	
2R	-220± 60	_	_	1.70	0.72	1.13	0.48	
3R	-220±120	_	_	2.03	0.45	1.35	0.30	
4R	-220±250	_	_	2.74	-0.14	1.83	-0.09	
2S	-330± 60	_	_	2.30	1.22	1.54	0.81	
3S	-330±120	_	_	2.63	0.95	1.76	0.63	
4S	-330±250	_	_	3.35	0.36	2.23	0.24	
2T	-470± 60	_	_	3.07	1.85	2.05	1.23	
3T	-470±120	_	_	3.40	1.58	2.27	1.05	
4T	-470±250	_	_	4.12	0.99	2.74	0.66	
3U	-750±120	_	_	4.94	2.84	3.29	1.89	
4U	-750±250	_	_	5.65	2.25	3.77	1.50	

^{*2:} Nominal values denote the temperature coefficient within a range of 20°C to 125°C (for ΔC)/85°C (for other TC).

Below GRM Series Specifications and Test Methods (2) are applied to "*" PNs in capacitance table. In case "*" is not added in capacitance table, please refer to GRM Series Specifications and Test Methods (1) (P.24).

No.	Ite	em	Specifications		Test Method		
1	Operating Temperating Range	•	B1, B3, F1: -25 to +85°C R6: -55 to +85°C R7, C7: -55 to +125°C F5: -30 to +85°C C8: -55 to +105°C,	Reference (B1, B3, F1	temperature: 25℃ : 20℃)		
2	Rated Voltage		See the previous pages.	The rated voltage is defined as the maximum voltage whice may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p,p} or V whichever is larger, should be maintained within the rated voltage range.			
3	Appearar	nce	No defects or abnormalities	Visual insp	ection		
4	Dimensio	ns	Within the specified dimensions	Using calip	ers		
5	Dielectric	: Strength	No defects or abnormalities	No failure should be observed when 250% of the rated volis applied between the terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA.			
6	Insulation Resistance		More than 50Ω · F	The insulation resistance should be measured with a DC volta not exceeding the rated voltage at reference temperature and 75%RH max. and within 1 minutes of charging, provided the charge/discharge current is less than 50mA.			
7	Capacita	nce	Within the specified tolerance		tance/D.F. should be measured		
8	Dissipation Factor (D.F.)		B1, B3, R6* ² , R7, C7, C8: 0.1 max. F1, F5: 0.2 max.	C≦10μF (10V min.)*¹ 1±0.1kHz 1.0± C≤10μF (6.3V max.) 1±0.1kHz 0.5±		Voltage 1.0±0.2Vrms 0.5±0.1Vrms 0.5±0.1Vrms	
		No bias	B1, B3: Within ±10% (−25 to +85°C) F1 : Within +30/−80% (−25 to +85°C) R6 : Within ±15% (−55 to +85°C) R7 : Within ±15% (−55 to +125°C) F5 : Within +22/−82% (−30 to +85°C) C7 : Within ±22% (−55 to +125°C) C8 : Within ±22% (−55 to +105°C)	c) each specified The ranges of reference tem shown in the t		perature ranges ecified ranges.* ce change should be	
					31/R6 0J/1A 336/476 only: 1.0±	Applying Voltage (V)	
				Step 1	Temperature (°C) Reference temperature ±2	Applying voltage (v)	
9	Capacitance Temperature			2	-55±3 (for R6, C7, C8)/ -25±3 (for B1, B3, F1) -30±3 (for F5)		
	Characteristics			3	Reference temperature ±2	No bias	
		50% of the Rated Voltage	B1: Within +10/-30% F1: Within +30/-95%	4	85±3 (for B1, B3, F1, R6, F5) 125±3 (for C7)/ 105±3 (for C8)		
				5	20±2		
				6	-25±3 (for B1, F1)	50% of the rated	
				7	20±2	voltage	
				8	85±3 (for B1, F1)		
				Perform a l	isurement for high dielectric con neat treatment at 150 +0/-10° r 24±2 hours at room temperate e initial measurement.	C for one hour and	

*2: GRM31CR60J107: 0.15 max.

Continued on the following page. $\begin{tabular}{|c|c|c|c|}\hline \end{tabular}$





Below GRM Series Specifications and Test Methods (2) are applied to "*" PNs in capacitance table.

7	Continued from the preceding page. In case "*" is not added in capacitance table, please refer to GRM Series Specifications and Test Methods (1) (
No.	Ite	em	Specifications		Test Me	ethod		
10	Adhesive Strength of Termination		No removal of the terminations or other defects should occur.	Solder the capacitor on the test jig (glass epoxy board) show in Fig. 1a using an eutectic solder. Then apply 10N* force in parallel with the test jig for 10±1sec. The soldering should be done either with an iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. *5N: GRM15/GRM18, 2N: GRM03 Type a b c GRM02 0.2 0.56 0.23 GRM03 0.3 0.9 0.3 GRM15 0.4 1.5 0.5				
			Baked electrode or	GRM18 GRM21	1.0	3.0 4.0	1.2 1.65	
			copper foil	GRM31	2.2	5.0	2.0	
			Fig. 1a	GRM32	2.2	5.0	2.9	
				GRM43 GRM55	3.5 4.5	7.0 8.0	3.7 5.6	
						0.0		
		Appearance	No defects or abnormalities	Solder the capacit	or on the test ji	g (glass epoxy	board) in the	
		Capacitance	Within the specified tolerance	same manner and under the same conditions as (10).			•	
11	Vibration	D.F.	B1, B3, R6* ² , R7, C7, C8: 0.1 max. F1, F5: 0.2 max.	The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of 3 mutually perpendicular directions (total of 6 hours).				
			No cracking or marking defects should occur.	Solder the capacit	-		·	
			20 50 Pressurizing speed: 1.0mm/sec. Pressurize R230 Flexure: ≤1		in Fig. 2a using an eutectic solder. Then apply a force in direction shown in Fig. 3a for 5±1 sec. The soldering sh done by the reflow method and should be conducted wit so that the soldering is uniform and free of defects such shock.			
12	Deflection	A Capacitance meter			Fig. 2a	,	t: 1.6mm	
			45 45		1 ig. 20		103/15: t: 0.8mm)	
				Туре	а	b	C	
			Fig.3a	GRM02	0.2	0.56	0.23	
				GRM03	0.3	0.9	0.3	
				GRM15	0.4	1.5	0.5	
				GRM18	1.0	3.0	1.2	
				GRM21 GRM31	1.2 2.2	4.0 5.0	1.65 2.0	
				GRM32	2.2	5.0	2.9	
				GRM43	3.5	7.0	3.7	
				GRM55	4.5	8.0	5.6	
							(in mm)	
13	Solderability of Termination		75% of the terminations is to be soldered evenly and continuously.	Immerse the capacitor in a solution of ethanol (JIS-K-810 rosin (JIS-K-5902) (25% rosin in weight proportion) . Preheat at 80 to 120°C for 10 to 30 seconds. After preheating, immerse in an eutectic solder solution for 2±0.5 seconds at 230±5°C or Sn-3.0Ag-0.5Cu solder solution for 2±0.5 seconds at 245±5°C.			solution for	

*2: GRM31CR60J107: 0.15 max.



Below GRM Series Specifications and Test Methods (2) are applied to "*" PNs in capacitance table. Continued from the preceding page. In case "*" is not added in capacitance table, please refer to GRM Series Specifications and Test Methods (1) (P.24).

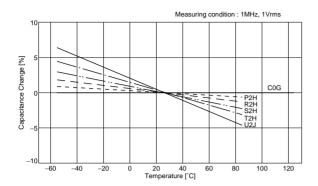
No.	Item		Specifications		Test Method				
	F	earance acitance nge	No defects or abnormalities B1, B3, R6, R7, C7, C8: Within ±7.5% F1, F5: Within ±20%	Immerse the solder solution	Preheat the capacitor at 120 to 150°C for 1 minute. Immerse the capacitor in an eutectic solder or Sn-3.0Ag-0.5C solder solution at 270±5°C for 10±0.5 seconds. Set at room temperature for 24±2 hours, then measure. *Do not apply to GRM02.				
	D.F	F.	B1, B3, R6* ² , R7, C7, C8: 0.1 max. F1, F5: 0.2 max.						
Resista	ance I.R		More than 50Ω · F		•Initial measurement for high dielectric constant type				
to Solderi Heat	Die	electric	No defects	then set at ro Perform the	Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement. *Preheating for GRM32/43/55				
	Stre	ength		Step		erature	Ti	me	
				1		o 120℃	1 :	min.	
				2	170 t	o 200℃	1 1	min.	
	Арр	earance	No defects or abnormalities	-	Fix the capacitor to the supporting jig in the same manner and under the same conditions as (10). Perform the five cycles according to the four heat treatments shown in the following table.				
	Capa Char	acitance nge	B1, B3, R6, R7, C7, C8: Within ±7.5% F1, F5: Within ±20%	Perform the					
	D.F	F.	B1, B3, R6*2, R7, C7, C8: 0.1 max. F1, F5: 0.2 max.	Set for 24±2	Set for 24±2 hours at room temperature				
Tempera	ature I.R	2.	More than $50\Omega \cdot F$	Step	Min.	2	Max.	4	
15 Sudden Change				Temp. (℃)		Room Temp.	Operating Temp. +3/-0	Room Temp.	
		electric ength	No defects	•Initial meas Perform a he then set at ro	Time (min.) 30±3 2 to 3 30±3 2 to 3 •Initial measurement for high dielectric constant type Perform a heat treatment at 150+0/−10°C for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement.				
	App	earance	No defects or abnormalities		Apply the rated voltage at 40±2°C and 90 to 95% humidity for				
High	Capa Char	acitance nge	B1, B3, R6, R7, C7, C8: Within ±12.5% F1, F5: Within ±30%		■ 500±12 hours. The charge/discharge current is less than 50r ■ Initial measurement Perform a heat treatment at 150+0/−10°C for one hour and then let sit for 24±2 hours at room temperature. Perform the initial measurement.				
Tempera 16 High Humidity	D.I	F.	B1, B3, R6, R7, C7, C8: 0.2 max. F1, F5: 0.4 max.	Perform a he then let sit fo					
(Steady)	l.R	.	More than 12.5 Ω · F	Perform a he	•Measurement after test Perform a heat treatment at 150+0/−10℃ for one hour and then let sit for 24±2 hours at room temperature, then meas				
	Арр	earance	No defects or abnormalities		of the rated volt	•			
	Capa Char	acitance nge	B1, B3, R6, R7, C7, C8: Within ±12.5% F1, F5: Within ±30%	room temper	maximum operating temperature ±3°C. Let sit for 24± room temperature, then measure. The charge/discharge current is less than 50mA.		±2 hours		
	D.F	F.	B1, B3, R6, R7, C7, C8: 0.2 max. F1, F5: 0.4 max.	•Initial meas	Ü	10 1000			
17 Durabi	ility I.R		More than $25\Omega \cdot F$	then let sit for initial measureme	Perform a heat treatment at 150+0/-10°C then let sit for 24±2 hours at room temper initial measurement. •Measurement after test		mperature. Peri	orm the	
					at treatment at r 24±2 hours at				

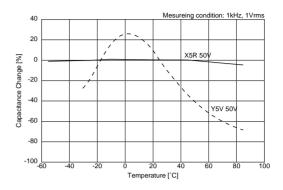
*2: GRM31CR60J107: 0.15 max.



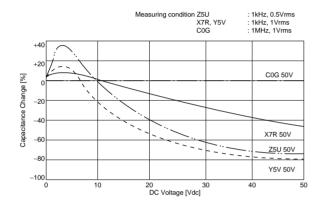
GRM Series Data

■ Capacitance - Temperature Characteristics

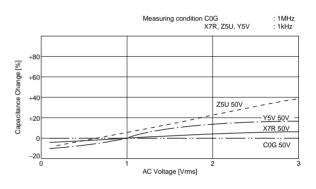




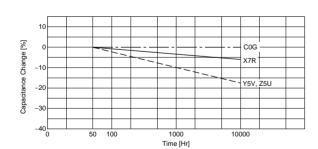
■ Capacitance - DC Voltage Characteristics



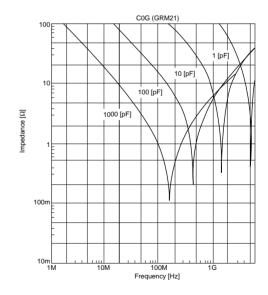
■ Capacitance - AC Voltage Characteristics



■ Capacitance Change - Aging



■ Impedance - Frequency Characteristics



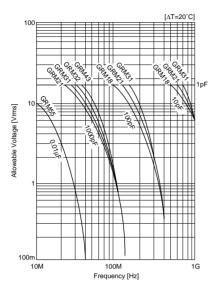




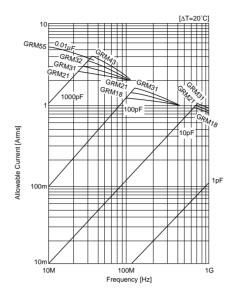
GRM Series Data

Continued from the preceding page.

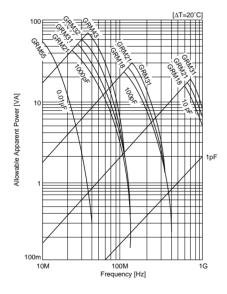
■ Allowable Voltage - Frequency



■ Allowable Current - Frequency



■ Allowable Apparent Power - Frequency





Chip Monolithic Ceramic Capacitors



Microchips GMA Series

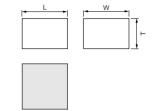
■ Features

- 1. Better microwave characteristics
- 2. Suitable for by-passing
- 3. High density mounting

■ Applications

- 1. Optical device for telecommunication
- 2. IC, IC packaging built-in
- 3. Measuring equipment





Part Number	Dimensions (mm)					
	L	W	T			
GMA05X	0.5 ±0.05	0.5 ±0.05	0.35 ±0.05			
GMA085	0.8 ±0.05	0.8 ±0.05	0.5 ±0.1			

Part Number	TC Code (Standard)	Rated Voltage (Vdc)	Capacitance	Length L (mm)	Width W (mm)	Thickness T (mm)
GMA05XR72A101MD01	X7R (EIA)	100	100pF ±20%	0.5	0.5	0.35
GMA05XR72A151MD01	X7R (EIA)	100	150pF ±20%	0.5	0.5	0.35
GMA05XR72A221MD01	X7R (EIA)	100	220pF ±20%	0.5	0.5	0.35
GMA05XR72A331MD01	X7R (EIA)	100	330pF ±20%	0.5	0.5	0.35
GMA085R72A331MD01	X7R (EIA)	100	330pF ±20%	0.8	0.8	0.5
GMA085R72A471MD01	X7R (EIA)	100	470pF ±20%	0.8	0.8	0.5
GMA085R72A681MD01	X7R (EIA)	100	680pF ±20%	0.8	0.8	0.5
GMA085R72A102MD01	X7R (EIA)	100	1000pF ±20%	0.8	0.8	0.5
GMA05XR71H161MD01	X7R (EIA)	50	160pF ±20%	0.5	0.5	0.35
GMA05XR71H331MD01	X7R (EIA)	50	330pF ±20%	0.5	0.5	0.35
GMA05XR71H471MD01	X7R (EIA)	50	470pF ±20%	0.5	0.5	0.35
GMA05XR71C431MD01	X7R (EIA)	16	430pF ±20%	0.5	0.5	0.35
GMA05XR71C471MD01	X7R (EIA)	16	470pF ±20%	0.5	0.5	0.35
GMA05XR71C681MD01	X7R (EIA)	16	680pF ±20%	0.5	0.5	0.35
GMA05XR71C102MD01	X7R (EIA)	16	1000pF ±20%	0.5	0.5	0.35
GMA085R71C102MD01	X7R (EIA)	16	1000pF ±20%	0.8	0.8	0.5
GMA05XR71C152MD01	X7R (EIA)	16	1500pF ±20%	0.5	0.5	0.35
GMA085R71C152MD01	X7R (EIA)	16	1500pF ±20%	0.8	0.8	0.5
GMA05XR71C222MD01	X7R (EIA)	16	2200pF ±20%	0.5	0.5	0.35
GMA085R71C222MD01	X7R (EIA)	16	2200pF ±20%	0.8	0.8	0.5
GMA085R71C332MD01	X7R (EIA)	16	3300pF ±20%	0.8	0.8	0.5
GMA085R71C472MD01	X7R (EIA)	16	4700pF ±20%	0.8	0.8	0.5
GMA085R71C682MD01	X7R (EIA)	16	6800pF ±20%	0.8	0.8	0.5
GMA085R71C103MD01	X7R (EIA)	16	10000pF ±20%	0.8	0.8	0.5

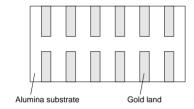
Rated Voltage See the previous pages. No before is superinged on Dic Voltage, Whither AC voltage is superingeded on Dic Voltage, Whither AC voltage is supplied between the both termination seconds, provided the charge/discharge current is 6 stored. Dielectric Strength No defects or abnormalities No latine should be observed when a voltage of 256 rated voltage is applied between the both termination seconds, provided the charge/discharge current is 6 stored. The insulation resistance should be measured with voltage not exceeding the rated voltage at normal termination and humidity and within 2 minutes of charging. The capacitance Should be measured at refere temperature and the requestion of the regular shown in the ratios behould be within the specified rate of the regular shown in the stable should be within the specified rate of the regular shown in the stable should be within the specified rate of the regular shown in the stable should be within the specified rate of the regular shown in the stable should be within the specified rate of the regular shown in the stable should be within the specified rate of the regular shown in the stable should be within the specified rate of the regular shown in the stable should be within the specified rate of the regular shown in the stable should be within the specified rate of the regular shown in the stable should be within the specified rate of the regular shown in the stable should be within the specified rate of the regular shown in the stable should be within the specified rate of the regular should resistance change measured after the respectation of the specified rate of the regular shown in the stable should be within the specified rate of the regular shown in the stable should be within the specified rate of the regular shown in the stable should be withi	No.	Ite	em	Specifications	Test Method				
Rated Voltage See the previous pages. When AC voltage is supering-sed on DC voltage, whichever is larger, should be maintained within the range. Appearance Disnosions Within the specified dimensions Visual inspection No failure should be observed when a voltage of 256 rated voltage is applied between the both termination scondars, provided the chargodischarge current is to Soma. The insulation resistance should be measured with voltage not exceeding the rated voltage at normal at emperature. The capacitance and humidity and without 2 minutes of the ranging. To Capacitance Vithin the specified tolerance The capacitance Should be measured at reference temperature at the reference and humidity and without 2 minutes of the ranging. The capacitance CF. should be measured at reference temperature at the request year of the respective of the respective and the requestive at the requestive and the	1	Temperat	•	R7: -55 to +125℃	Reference Temperature: 25°C				
Directric Strength No defects or abnormalities Visual inspection	2	Rated Vo	ltage	See the previous pages.	When AC voltage is superimposed on DC voltage, VP-P or VO-P, whichever is larger, should be maintained within the rated voltage				
Dielectric Strength No defects or abnormalities South	3	Appearar	nce	No defects or abnormalities	Using calipers				
Dielectric Strength No defects or abnormalities Tareted voltage is applied between the both the mination seconds, provided the charge/discharge current is le soma.	4	Dimensio	ns	Within the specified dimersions	Visual inspection				
Insulation Resistance 10,000M2 min. voltage not exceeding the rated voltage at normal te and humidity and within 2 minutes of charging.	5	Dielectric	Strength	No defects or abnormalities	No failure should be observed when a voltage of 250% of the rated voltage is applied between the both terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA.				
Bond Strength Perform a heat treatment at 150 +00-10°C for one then let sit for 24±2 hours at room temperature.	6	Insulation	Resistance	10,000MΩ min.	The insulation resistance should be measured with a DC voltage not exceeding the rated voltage at normal temperature and humidity and within 2 minutes of charging.				
Bossipation Factor (D.F.) R7: 0.035 max. Frequency 1±0.1kHz Voltage 1±0.2Vms	7	Capacita	nce	Within the specified tolerance	The capacitance/D.F. should be measured at reference temperature at the frequency and voltage shown in the table.				
Post of the content of the conten	8	•	n Factor	R7: 0.035 max.					
Capacitance Temperature Characteristics No bias R7: Within +/-15% (-55 to +125°C) Temperature R7: Within +/-15% (-55 to +125°C) R7: Within +/-15% (-55 to +12					 The ranges of capacitance change compared with the Reference Temperature value over the temperature ranges shown in the table should be within the specified ranges.* In case of applying voltage, the capacitance change should be measured after 1 more min. with applying voltage in equilibration of each temp. stage. 				
Temperature Characteristics No bias R7: Within +/-15% (-55 to +125°C) 2		Canacitanco		No bias	No bias		1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1		
Strength Bond Strength Pull force: 0.03N min. MilSTD-883 Method 2011 Condition D Mount the capacitor terminal using an ultrasonic ball bond. Then Strength Die Shear force: 2N min. MilSTD-883 Method 2019 Mount the capacitor terminal using an ultrasonic ball bond. Then MilSTD-883 Method 2019 Mount the capacitor terminal using an ultrasonic ball bond. Then MilSTD-883 Method 2019 Mount the capacitor terminal using an ultrasonic ball bond. Then MilSTD-883 Method 2019 Mount the capacitor terminal using an ultrasonic ball bond. Then MilSTD-883 Method 2019 Mount the capacitor terminal using an ultrasonic ball bond. Then MilSTD-883 Method 2019 Mount the capacitor terminal using an ultrasonic ball bond. Then MilSTD-883 Method 2019 Mount the capacitor terminal using an ultrasonic ball bond. Then MilSTD-883 Method 2019 Mount the capacitor terminal using an ultrasonic ball bond. Then MilSTD-883 Method 2019 Mount the capacitor terminal using an ultrasonic ball bond. Then MilSTD-883 Method 2019 MilSTD-883 Method 2019 Mount the capacitor terminal using an ultrasonic ball bond. Then MilSTD-883 Method 2019 Mount the capacitor terminal using an ultrasonic ball bond. Then MilSTD-883 Method 2019 Mount the capacitor terminal using an ultrasonic ball bond. Then MilSTD-883 Method 2019 Mount the ca	9	Temperature				No bias	No bias	R7: Within +/–15% (–55 to +125°C)	
Mechanical Strength Bond Strength Pull force: 0.03N min. MilSTD-883 Method 2011 Condition D Mount the capacitor on a gold metallized alumina sub Au-Sn (80/20) and bond a 25μm (0.0008 inch) gold w capacitor terminal using an ultrasonic ball bond. Then MilSTD-883 Method 2011 Condition D Mount the capacitor on a gold metallized alumina sub Au-Sn (80/20) and bond a 25μm (0.0008 inch) gold w capacitor terminal using an ultrasonic ball bond. Then MilSTD-883 Method 2019 Mount the capacitor on a gold metallized alumina sub Au-Sn (80/20) and bond a 25μm (0.0008 inch) gold w capacitor terminal using an ultrasonic ball bond. Then MilSTD-883 Method 2019 Mount the capacitor on a gold metallized alumina sub Au-Sn (80/20). Apply the force parallel to the sub with Au-Sn (80/20). Apply the force parallel to the sub visit and									
Perform a heat treatment at 150 +0/-10°C for one in the let sit for 24±2 hours at room temperature. Perform the initial measurement. Pull force: 0.03N min. MIL-STD-883 Method 2011 Condition D Mount the capacitor on a gold metallized alumina sub Au-Sn (80/20) and bond a 25μm (0.0008 inch) gold w capacitor terminal using an ultrasonic ball bond. Then MIL-STD-883 Method 2019 Mount the capacitor on a gold metallized alumina sub Au-Sn (80/20). Apply the force parallel to the su with Au-Sn (80/20). Apply the force parallel to the su with Au-Sn (80/20). Apply the force parallel to the su with Au-Sn (80/20). Apply the force parallel to the su with Au-Sn (80/20). Apply the force parallel to the su manufacture apply this motion for a period of 2 hours in each of 3 perpendicular directions (total 6 hours).									
Mount the capacitor on a gold metallized alumina sub Au-Sn (80/20) and bond a 25μm (0.0008 inch) gold w capacitor terminal using an ultrasonic ball bond. Then MIL-STD-883 Method 2019 Mount the capacitor on a gold metallized alumina sub Au-Sn (80/20) and bond a 25μm (0.0008 inch) gold w capacitor terminal using an ultrasonic ball bond. Then MIL-STD-883 Method 2019 Mount the capacitor on a gold metallized alumina sub Au-Sn (80/20). Apply the force parallel to the sub with Au-Sn (80/20). Apply the force parallel to the sub w					·				
Die Shear Strength Die Shear Strength Die Shear Strength Die Shear force: 2N min. Appearance Appearance Die Shear force: 2N min. Appearance No defects or abnormalities Capacitance D.F. R7: 0.035 max. Appearance Appearance D.F. R7: Within ±7.5% Temperature Cycle Dielectric Dielectric Dielectric Die Shear force: 2N min. MIL-STD-883 Method 2019 Mount the capacitor on a gold metallized alumina su with Au-Sn (80/20). Apply the force parallel to the su with Au-Sn (80/20). Apply the fo	10			Pull force: 0.03N min.	MIL-STD-883 Method 2011 Condition D Mount the capacitor on a gold metallized alumina substrate with Au-Sn (80/20) and bond a 25μm (0.0008 inch) gold wire to the capacitor terminal using an ultrasonic ball bond. Then, pull wire.				
1 minute. Amplitude: 1.5 mm (0.06 inch) max. total of Apply this motion for a period of 2 hours in each of 3 perpendicular directions (total 6 hours). Appearance R7: 0.035 max.		Strength		Die Shear force: 2N min.	MIL-STD-883 Method 2019 Mount the capacitor on a gold metallized alumina substrate with Au-Sn (80/20). Apply the force parallel to the substrate.				
Resistance Capacitance Capacitance Capacitance D.F.		\#I !!	Appearance	No defects or abnormalities	Ramp frequency from 10 to 55Hz then return to 10Hz all within				
D.F. R7: 0.035 max. Appearance No defects or abnormalities The capacitor should be set for 24±2 hours at room temperature after one hour heat of treatment at 150 then measure for the initial measurement. Fix the capacitor should be set for 24±2 hours at room temperature after one hour heat of treatment at 150 then measure for the initial measurement. Fix the capacitor should be set for 24±2 hours at room temperature after one hour heat of treatment at 150 then measure for the initial measurement. Fix the capacitor should be set for 24±2 hours at room temperature after one hour heat of treatment at 150 then measure for the initial measurement. Fix the capacitor should be set for 24±2 hours at room temperature after one hour heat of treatment at 150 then measure for the initial measurement. Fix the capacitor should be set for 24±2 hours at room temperature after one hour heat of treatment at 150 then measure for the initial measurement. Fix the capacitor should be set for 24±2 hours at 150 then measure for the initial measurement. Fix the capacitor should be set for 24±2 hours at room temperature after one hour heat of treatment at 150 then measure for the initial measurement. Fix the capacitor should be set for 24±2 hours at room temperature after one hour heat of treatment at 150 then measure for the initial measurement. Fix the capacitor should be set for 24±2 hours at room temperature after one hour heat of treatment at 150 then measure for the initial measurement. Fix the capacitor should be set for 24±2 hours at room temperature after one hour heat of treatment at 150 then measure for the initial measurement. Fix the capacitor should be set for 24±2 hours at room temperature after one hour heat of the supporting jig in the same manner and under the conditions as (11) and conduct the five cycles according to the supporting jig in the same manner and under the conditions as (11) and conduct the five cycles according to the supporting jig in the same manner and under the conditions as (11) and conduct the f	11	l Canacitance		Within the specified tolerance	1 minute. Amplitude: 1.5 mm (0.06 inch) max. total excursion. Apply this motion for a period of 2 hours in each of 3 mutually				
temperature after one hour heat of treatment at 150 then measure for the initial measurement. Fix the cather supporting jig in the same manner and under the conditions as (11) and conduct the five cycles accorditions as (11) and conduct the five cycles accorditemperatures and time shown in the following table. 12		22.2.400	D.F.	R7: 0.035 max.	1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1				
then measure for the initial measurement. Fix the cather supporting jig in the same manner and under the conditions as (11) and conduct the five cycles accorditions as (12) and conduct the five cycles accorditions as (13) and conduc			Appearance	No defects or abnormalities	The capacitor should be set for 24±2 hours at room				
D.F. R7: 0.035 max. I.R. 10,000MΩ min. I.R. 10,000MΩ min. Dielectric No defects Temperature Cycle Dielectric No defects D.F. R7: 0.035 max. conditions as (11) and conduct the five cycles according temperatures and time shown in the following table. 48±4 hours at room temperature, then measure. Step 1 2 3 Temp (%) Min. Operating Room Max. Operating				R7: Within ±7.5%	then measure for the initial measurement. Fix the capacitor to				
Cycle Cycle 1.R. 10,000M32 min. 48±4 hours at room temperature, then measure. Step 1 2 3 Temp (%) Min. Operating Room Max. Operating			D.F.	R7: 0.035 max.	conditions as (11) and conduct the five cycles according to the				
Dielectric No defects Step 1 2 3 Temp (%) Min. Operating Room Max. Operating			I.R.	10,000M Ω min.	temperatures and time shown in the following table. Set it for				
Dielectric No defects Temp (°C) Min. Operating Room Max. Operating		- Juli							
Strength Strength 1 - 1 - 3 1 - 1 - 3 1 - 1 - 3 1 - 1 - 3 1 - 1 - 3 1 - 1 - 3 1 - 1 - 3 1 - 1 - 3 1 - 1 - 3 1 - 1 - 3 1 - 1 - 3 1 - 1 - 3 1			Dielectric Strength	No defects					
Time (min.) 30±3 2 to 3 30±3					Time (min.) 30±3 2 to 3 30±3 2 to 3				

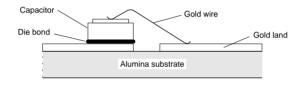


Continued from the preceding page.

No.	Ite	em	Specifications	Test Method
		Appearance	No defects or abnormalities	
13	Humidity (Stoody State)	Capacitance Change	R7: Within ±12.5%	Set the capacitor for 500±12 hours at 40±20°C, in 90 to 95% humidity.
	(Steady State)	D.F.	R7: 0.05 max.	Take it out and set it for 24±2 hours at room temperature, then measure.
		I.R.	1,000M Ω min.	
		Appearance	No defects or abnormalities	
14	Humidity	Capacitance Change	R7: Within ±12.5%	Apply the rated voltage for 500±12 hours at 40±2°C, in 90 to 95% humidity and set it for 24±2 hours at room
	Load	D.F.	R7: 0.05 max.	temperature,then measure. The charge/discharge current is less than 50mA.
		I.R.	500M $Ω$ min.	
		Appearance	No defects or abnormalities	A voltage treatment should be given to the capacitor, in which a
	High 15 Temperature Load	Capacitance Change	R7: Within ±12.5%	DC voltage of 200% the rated voltage is applied for one hour at the maximum operating temperature ±3°C then it should be set for 24±2 hours at room temperature and the initial measurement
15		D.F.	R7: 0.05 max.	should be conducted.
		I.R.	1,000MΩ min.	Then apply the above mentioned voltage continuously for 1000±12 hours at the same temperature, remove it from the bath, and set it for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA.

Mounting for testing: The capacitors should be mounted on the substrate as shown below using die bonding and wire bonding when tests No.11 to 15 are performed.





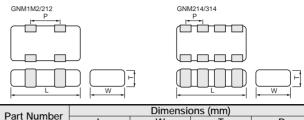
Capacitor Arrays GNM Series

■ Features

- 1. High density mounting due to mounting space saving
- 2. Mounting cost saving

■ Applications

General electronic equipment



Part Number	Dimensions (mm)						
Part Number	L	W	T	Р			
GNM1M2	1.37 ±0.15	1.0 ±0.15	0.6 ±0.1	0.64 +0.05			
GNIVITIVIZ	1.37 ±0.15	1.0 ±0.15	0.8 +0/-0.15	0.04 ±0.05			
GNM212	2.0 ±0.15	1.25 ±0.15	0.85 ±0.1	1.0 ±0.1			
GNM214	2.0 ±0.15	1.25 ±0.15	0.6 ±0.1	0.5 ±0.05			
GNM314	3.2 ±0.15	1.6 ±0.15	0.8 ±0.1	0.8 +0.1			
GINIVIS 14	3.2 ±0.15	1.0 ±0.15	1.0 ±0.1	U.0 <u>T</u> U.1			

Temperature Compensating Type

Part Number		GNM1M	GNM21	GNI	W31
LxW		1.37x1.0	2.0x1.25	3.2)	< 1.6
тс		C0G (5C)	C0G (5C)	C0 (5	OG C)
Rated Volt.		50 (1H)	50 (1H)	100 (2A)	50 (1H)
Capacitance, Ca	pacitano	e Tolerance and T Dimension			
10pF(100)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
15pF(150)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
22pF(220)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
27pF(270)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
33pF(330)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
39pF(390)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
47pF(470)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
68pF(680)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
100pF(101)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
150pF(151)	K	0.6(2)	0.6(4)	0.8(4)	0.8(4)
220pF(221)	K	0.6(2)	0.6(4)		0.8(4)
270pF(271)	K				0.8(4)
330pF(331)	K				0.8(4)

The part numbering code is shown in each (). The (4) code in T (mm) means number of elements (four). Dimensions are shown in mm and Rated Voltage in Vdc.

High Dielectric Constant Type GNM1M Series

Part Number		GNM1M							
LxW					1.37x1.0				
тс			X5R (R6)			X7R (R7)			
Rated Volt.		16 (1C)	10 (1A)	6.3 (0J)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	
Capacitance, Ca	pacitanc	e Tolerance and	T Dimension		1			'	
1000pF(102)	М				0.6(2)				
2200pF(222)	K, M					0.6(2)			
4700pF(472)	K, M					0.6(2)			
10000pF(103)	М					0.6(2)			
22000pF(223)	K, M	0.6(2)	0.6(2)				0.6(2)	0.6(2)	

Note • This PDF catalog is downloaded from the website of Murata Manufacturing co., ltd. Therefore, it's specifications are subject to change or our products in it may be discontinued without advance notice. Please check with our sales representatives or product engineers before ordering.

• This PDF catalog has only typical specifications because there is no space for detailed specifications. Therefore, please approve our product specifications or transact the approval sheet for product specifications before ordering.

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Part Number		GNM1M						
LxW					1.37x1.0			
тс		X5R (R6)			X7R (R7)			
Rated Volt.		16 (1C)	10 (1A)	6.3 (0J)	50 (1H)	25 (1E)	16 (1C)	10 (1A)
Capacitance, Ca	pacitano	e Tolerance and	T Dimension	T.				
47000pF(473)	K, M	0.6(2)	0.6(2)				0.6(2)	0.6(2)
0.10μF(104)	М		0.6(2)					
1.0μF(105)	М	0.8(2)	0.8(2)	0.8(2)				

The part numbering code is shown in each (). The (2) code in T (mm) means number of elements (two).

High Dielectric Constant Type GNM21 Series

Part Number			GNM21					
LxW				2.0x1.25				
тс			X5R (R6)		X7R (R7)			
Rated Volt.		16 10 50 25 (1C) (1A) (1H) (1E)				16 (1C)		
Capacitance, Ca	pacitano	e Tolerance and T Dime	nsion					
1000pF(102)	М			0.6(4)				
2200pF(222)	K, M				0.6(4)			
4700pF(472)	K, M				0.6(4)			
10000pF(103)	М				0.6(4)			
22000pF(223)	K, M					0.85(4)		
47000pF(473)	K, M					0.85(4)		
0.10μF(104)	М					0.85(4)		
0.47μF(474)	М	0.85(2)						
1.0μF(105)	М	0.85(2)	0.85(4)					
2.2μF(225)	K, M		0.85(2)					

The part numbering code is shown in each (). The (2) code in T (mm) means number of elements (two).

High Dielectric Constant Type GNM31 Series

Part Number			GNM31					
LxW			3.2	x1.6				
тс			X7R (R7)		X5R (R6)			
Rated Volt. 100 (2A)			50 (1H)	16 (1C)	10 (1A)			
Capacitance, Ca	pacitano	e Tolerance and T Dimension						
220pF(221)	K, M	0.8(4)						
330pF(331)	K, M	0.8(4)						
470pF(471)	K, M	0.8(4)	0.8(4)					
680pF(681)	K, M	0.8(4)	0.8(4)					
1000pF(102)	K, M	0.8(4)	0.8(4)					
1500pF(152)	K, M	0.8(4)	0.8(4)					
2200pF(222)	K, M	0.8(4)	0.8(4)					
3300pF(332)	K, M	0.8(4)	0.8(4)					
4700pF(472)	K, M	0.8(4)	0.8(4)					
6800pF(682)	K, M		0.8(4)					
10000pF(103)	K, M		0.8(4)					

Dimensions are shown in mm and Rated Voltage in Vdc.

Please refer to Specifications and Test Methods (2) about $1.0\mu F$ products.

Dimensions are shown in mm and Rated Voltage in Vdc.

Please refer to Specifications and Test Methods (2) about X5R, 10V products.

Continued from the preceding page.

Part Number			GNM31						
LxW			3	3.2x1.6					
тс			X7R (R7)						
Rated Volt.		100 (2A)	50 (1H)	16 (1C)	10 (1A)				
Capacitance, Ca	pacitano	e Tolerance and T Dimension							
15000pF(153)	K, M		0.8(4)						
22000pF(223)	K, M			0.8(4)					
33000pF(333)	K, M			0.8(4)					
47000pF(473)	K, M			1.0(4)					
68000pF(683)	K, M			1.0(4)					
0.10μF(104)	K, M			1.0(4)					
1.0μF(105)	М				0.85(4)				

The part numbering code is shown in each (). The (4) code in T (mm) means number of elements (four). Dimensions are shown in mm and Rated Voltage in Vdc.

				Specifications						
No.	Ite	em	Temperature Compensating Type	High Dielectric Type	Test Method					
1	Operating Tempera Range		5C: -55 to +125°C	R7: -55 to +125°C R6: -30 to +85°C						
2	Rated Vo	ltage	See the previous page	ges.	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p-p} or V ^{o-p} , whichever is larger, should be maintained within the rated voltage range.					
3	Appearar	nce	No defects or abnorr	malities	Visual inspection					
4	Dimensio	ons	Within the specified	dimensions	Using calipers					
5	Dielectric	Strength	No defects or abnorr	nalities	No failure should be observed when 300% of the rated voltag (5C) or 250% of the rated voltage (R7) is applied between the terminations for 1 to 5 seconds, provided the charge/discharg current is less than 50mA.	e				
6	Insulation Resistant	-	More than 10,000Ms (Whichever is smalle		The insulation resistance should be measured with a DC voltage not exceeding the rated voltage at 25°C and 75%RH max. and within 2 minutes of charging.					
7	Capacita	nce	Within the specified	tolerance	The capacitance/Q/D.F. should be measured at 25°C at the					
			30pF min.: Q≧1000 30pF max.:	Char. 25V min. 16V 10V 6.3V	frequency and voltage shown in the table. Char.					
8	Q/ Dissipation	on Factor	Q≧400+20C	R7, R6 0.025 0.035 0.035 0.05	Item 5C R7					
	(D.F.)		C: Nominal	max. max. max. max.	Frequency 1±0.1MHz 1±0.1kHz Voltage 0.5 to 5Vrms 1.0±0.2Vrms	_				
			Capacitance (pF)							
		Capacitance Change	Within the specified tolerance (Table A) Within the	Char. Temp. Range Reference Temp. Cap. Change R7 -55°C to +125°C Within ±15% R6 -55°C to +85°C 25°C	The capacitance change should be measured after 5 min. at each specified temperature stage. (1) Temperature Compensating Type The temperature coefficient is determined using the capacitance measured in step 3 as a reference. When cycling the temperature sequentially from step1 through 5, the capacitans should be within the specified tolerance for the temperature coefficient and capacitance change as Table A. The capacitance drift is calculated by dividing the differences	nce				
9	Capacitance Temperature	Temperature Coefficent	specified tolerance (Table A)		between the maximum and minimum measured values in the steps 1, 3 and 5 by the cap. value in step 3.	1				
	Characteristics	Capacitance Drift	Within ±0.2% or ±0.05pF (Whichever is larger.)		Step Temperature (°C) 1 25±2 2 -55±3 (for 5C/R7), -30±3 (for F5) 3 25±2 4 125±3 (for 5C/R7), 85±3 (for F5) 5 20±2 (2) High Dielectric Constant Type The ranges of capacitance change compared with the above 25°C value over the temperature ranges shown in the table	- - - -				
			No removal of the to	rminations or other defeat should see u	should be within the specified ranges.					
10	Adhesive of Termir	Strength nation	GNM	GNM 2 GNM 2 GNM C2 Solder resist Copper foil	Solder the capacitor to the test jig (glass epoxy board) shown in Fig.1 using a eutectic solder. Then apply 5N force in parallel with the test jig for 10±1 sec. The soldering should be done either with an iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Type a b c d GNM1M2 0.5 1.6 0.32 0.32 GNM212 0.6 1.8 0.5 0.5 GNM214 0.6 2.0 0.25 0.25 GNM314 0.8 2.5 0.4 0.4 (in mm)	th 				
					Fig. 1					





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N/ -				Specifications	Total Martin
No.	Ite	em	Temperature Compensating Type	High Dielectric Type	Test Method
		Appearance	No defects or abnorr	nalities	Solder the capacitor to the test jig (glass epoxy board) in the
		Capacitance	Within the specified t	olerance	same manner and under the same conditions as (10). The capacitor should be subjected to a simple harmonic motion
11	Vibration Resistance	Q/D.F.	30pF min.: Q≥1000 30pF max.: Q≥400+20C C: Nominal Capacitance (pF)	Char. 25V min. 16V 10V 6.3V R7, R6 0.025 max. 0.035 max. 0.035 max. 0.05 max.	having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of 3 mutually perpendicular directions (total of 6 hours).
			No cracking or marki	ng defects should occur.	Solder the capacitor on the test jig (glass epoxy board) shown
			•GNM□4	•GNM□□2	in Fig. 2 using a eutectic solder. Then apply a force in the direction shown in Fig. 3 for 5±1 sec. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.
12	Deflection	n	5.0 / 100	5.0	50 Pressurizing speed : 1.0mm/sec. Pressurize
			GNM212 2 GNM214 2	t=0.8mm a b c d 0.0±0.05 0.5±0.05 0.32±0.05 0.32±0.05 0.0±0.05 0.6±0.05 0.5±0.05 0.5±0.05 0.0±0.05 0.7±0.05 0.3±0.05 0.2±0.05 0.5±0.05 0.8±0.05 0.4±0.05 0.4±0.05 (in mm)	Capacitance meter 45 45 Fig. 3
				Fig. 2	Immerse the conscitor in a solution of othersel (IIC K 9101) and
13	Solderab Terminati	•	75% of the termination continuously.	ons are to be soldered evenly and	Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at 80 to 120°C for 10 to 30 seconds. After preheating, immerse in eutectic solder solution for 2±0.5 seconds at 230±5°C or Sn-3.0Ag-0.5Cu solder solution for 2±0.5 seconds at 245±5°C.
	Resistanc Soldering		The measured and o	bserved characteristics should satisfy the following table.	
		Appearance	No marking defects		
		Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	R7, R6: Within ±7.5%	Preheat the capacitor at 120 to 150°C for 1 minute. Immerse the capacitor in a eutectic solder or Sn-3.0Ag-0.5Cu solder solution at 270±5°C for 10±0.5 seconds. Let sit at room
14	Q/D.F.		30pF min.: Q≥1000 30pF max.: Q≥400+20C C: Nominal Capacitance (pF)	Char. 25V min. 16V 10V 6.3V R7, R6 0.025 max. 0.035 max. 0.035 max. 0.05 max.	Initial measurement for high dielectric constant type Perform a heat treatment at 150+0/-10°C for one hour and then let sit for 24±2 hours at room temperature. Perform the initial measurement.
		I.R.	More than 10,000Ms	2 or 500Ω · F (Whichever is smaller)	
		Dielectric Strength	No failure		

Continued on the following page.



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				Specifications							
No.	Ite	em	Temperature Compensating Type	High Dielectric Type	Test Method						
	Temperat Cycle	ure	The measured and o	bserved characteristics should satisfy the following table.	Fix the capacitor to the supporting jig in the same manner and						
		Appearance	No marking defects	· · ·	under the same conditions as (10). Perform the five cycles according to the four heat treatments listed in the following						
		Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)	R7, R6: Within ±7.5%	table. Let sit for 24±2 hours (temperature compensating type) or 48±4 hours (high dielectric constant type) at room temperature, then measure.						
15		Q/D.F.	30pF min.: Q≥1000 30pF max.: Q≥400+20C	Char. 25V min. 16V 10V 6.3V R7, R6 0.025 max. 0.035 max. 0.035 max. 0.05 max.	Step 1 2 3 4 Temp. (°C) Min. Operating Temp. +0/-3 Room Temp. Temp. Max. Operating Temp. +3/-0 Room Temp. Time (min.) 30±3 2 to 3 30±3 2 to 3						
		I.R.	Capacitance (pF)	or 500Ω · F (Whichever is smaller)	Initial measurement for high dielectric constant type Perform a heat treatment at 150+0/-10°C for one hour and the object of the control of the						
		Dielectric Strength	No failure	t of occit i (willows) to situation	then let sit for 24±2 hours at room temperature. Perform the initial measurement.						
	Humidity State		The measured and o	bserved characteristics should satisfy the following table.							
		Appearance	No marking defects	<u> </u>							
		Capacitance Change	Within ±5% or ±0.5pF (Whichever is larger)	R7, R6: Within ±12.5%							
16		Q/D.F.	30pF and over: Q≥350 10pF and over, 30pF and below: Q≥275+5C/2 10pF and below: Q≥200+10C C: Nominal Capacitance (pF)	Char. 25V min. 16V 10V/6.3V R7, R6 0.05 max. 0.05 max. max.	Sit the capacitor at 40±2°C and 90 to 95% humidity for 500±12 hours. Remove and let sit for 24±2 hours at room temperature, then measure.						
		I.R.	More than 1,000MΩ	or 50Ω · F (Whichever is smaller)	1						
		Dielectric Strength	No failure								
	Humidity	Load	The measured and o specifications in the	bserved characteristics should satisfy the following table.							
		Appearance	No marking defects								
		Capacitance Change	Within ±7.5% or ±0.75pF (Whichever is larger)	R7, R6: Within ±12.5%	Apply the rated voltage at 40±2°C and 90 to 95% humidity for						
17		Q/D.F.	30pF and over: Q≥200 30pF and below: Q≥100+10C/3 C: Nominal Capacitance (pF)	Char. 25V min. 16V 10V/6.3V R7, R6 0.05 max. 0.05 max. max.	 500±12 hours. Remove and let sit for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA. 						
		I.R.		$25\Omega \cdot F$ (Whichever is smaller)	-						
		Dielectric Strength	No failure	· (vinoleve is smaller)							



Continued from the preceding page

	Continued II	om the prec	eding page.		
				Specifications	
No.	ITE	em	Temperature Compensating Type	High Dielectric Type	Test Method
	High Tem Load	perature	The measured and o	observed characteristics should satisfy the following table.	
		Appearance	No marking defects		
	10	Capacitance Change	Within ±3% or ±0.3pF (Whichever is larger)	R7, R6: Within ±12.5%	Apply 200% of the rated voltage for 1000±12 hours at the maximum operating temperature ±3°C. Let sit for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA.
18		Q/D.F.	30pF and over: Q≥350 10pF and over, 30pF and below: Q≥275+5C/2 10pF and below: Q≥200+10C C: Nominal Capacitance (pF)	Char. 25V min. 16V 10V/6.3V R7, R6 0.04 max. 0.05 max. 0.05 max.	Initial measurement for high dielectric constant type. Apply 200% of the rated DC voltage for one hour at the maximum operating temperature ±3°C. Remove and let sit for 24±2 hours at room temperature. Perform initial measurement.
		I.R.	More than 1,000MΩ	or $50\Omega \cdot F$ (Whichever is smaller)	

Table A

	Name in all Malana	Capacitance Change from 25℃ (%)									
Char.	Nominal Values (ppm/℃) Note 1	-5	5℃	-3	0℃	−10 ℃					
	(ppin/c) Note i	Max.	Min.	Max.	Min.	Max.	Min.				
5C	0±30	0.58	-0.24	0.40	-0.17	0.25	-0.11				

Note 1: Nominal values denote the temperature coefficient within a range of 25 to 125°C.

No.	Ite	em		Spe	cifications			Test Method					
1	Operating Temperati	ure Range	R6: -55°C	to +85°C									
2	Rated Vo	Itage	See the pre	evious pages.			The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, vP-P or VO-P, whichever is larger, should be maintained within the rated voltage range.						
3	Appearar	nce	No defects	or abnormalities			Visual inspection						
4	Dimensio	ns	Within the s	specified dimension	on		Using calipers						
5	Dielectric	Strength	No defects	or abnormalities			No failure should be is applied between the provided the charge.	ne terminations for 1	to 5 secon	nds,			
6	Insulation	Resistance	50Ω · F min	n.			The insulation resists voltage not exceedin max. and within 1 mi	g the rated voltage					
7	Capacita		Within the s	specified toleranc	е		The capacitance/D.F frequency and voltage			at the			
8	Dissipation (D.F.)	on Factor	0.1 max.				Capacitance R6	Frequency 1±0.1kHz		tage 0.1Vrms			
9	Capacitar Temperat Character	ure	Char.	Temp. Range -55 to +85°C	Reference Temp. 25°C	Cap. Change Within ±15%	The capacitance change should be measured affter 5 min.at each specified temperature stage. Step						
							 Initial measurement for high dielectric constant type. Perform a heat treatment at 150+0/-10°C for one hour and then set for 24±2 hours at room temperature. Perform the initial measurement. 						
10	Adhesive of Termir	3	No removal	of the terminatio	ns or other defe	ects should occur.	Solder the capacitor to the test jig (glass epoxy board) shown in Fig. 1 using a eutectic solder. Then apply 5N force in parallel with the test jig for 10±1 sec. The soldering should be done either with an iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Type a b c d GNM1M2 0.5 1.6 0.32 0.32						
					Fig. 1		<u>GNM212</u>	0.6 1.8	0.5	(in mm)			
		Appearance	No defects	or abnormalities			Solder the capacitor	to the test iia (alass	epoxy bos	ard) in			
		Capacitance		specified tolerance	e		the same manner an	d under the same of	onditions a	s (10).			
11	Vibration	D.F.	0.1 max.		-		The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of 3 mutually perpendicular directions (total of 6 hours).						





sales representatives or product engineers before ordering.

• This PDF catalog has only typical specifications because there is no space for detailed specifications. Therefore, please approve our product specifications or transact the approval sheet for product specifications before ordering.

GNM Series Specifications and Test Methods (2)

Continued from the preceding page Specifications No Item Test Method No cracking or marking defects should occur. Solder the capacitor to the test jig (glass epoxy board) shown in Fig. 2 using a eutectic solder. Then apply a force in the direction shown in Fig. 3. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Pressurizing speed : 1.0mm/sec (35) Pressurize R230 Thickness: 0.8mm 100 5.0 Deflection Flexure : ≤1 l.b. Type Fig. 3 GNM1M2 2.0±0.5 0.5±0.05 0.32±0.05 0.32±0.05 2.0±0.05 0.6±0.05 0.5±0.05 0.5±0.05 GNM212 (in mm) Fig. 2 Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at Solderability of 75% of the terminations are to be soldered evenly 80 to 120°C for 10 to 30 seconds. After preheating, immerse in Termination and continuously. eutectic solder solution for 2±0.5 seconds at 230±5°C or Sn-3.0Ag-0.5Cu solder solution for 2±0.5 seconds at 245±5°C. Appearance No marking defects Preheat the capacitor at 120 to 150°C for 1 minute. Immerse the capacitor in a eutectic solder or Sn-3.0Ag-0.5Cu solder Canacitance R6: Within ±7.5% solution at 270±5°C for 10±0.5 seconds. Change Resistance Let sit at room temperature for 24±2 hours, then measure. to Soldering D.F. 0.1 max Initial measurement Heat I.R. $50\Omega \cdot F min.$ Perform a heat treatment at 150 +0/-10°C for one hour and then let sit for 24±2 hours at room temperature. Perform Dielectric No failure the initial measurement. Strenath Fix the capacitor to the supporting jig in the same manner and Appearance No marking defects under the same conditions as (10). Capacitance Perform the five cycles according to the four heat treatments R6: Within ±12.5% Change listed in the following table. D.F. Let sit for 24±2 hours at room temperature, then measure. 0.1 max Step $50\Omega \cdot F min.$ I.R Temperature Min. Operating Room Max. Operating Room 15 Temp. (℃) Cycle Temp. Temp. Temp. Temp. Time (min.) 30 ± 3 2 to 3 30 ± 3 2 to 3 Dielectric No failure Initial measurement Strength Perform a heat treatment at 150 +0/-10 °C for one hour and then let sit for 24±2 hours at room temperature. Perform the initial measurement. Appearance No marking defects Apply the rated voltage at 40±2°C and 90 to 95% humidity for 500±12 hours. The charge/discharge current is less than 50mA. Capacitance R6: Within ±12.5% High Initial measurement Change Temperature Perform a heat treatment at 150 +0/-10°C for one hour High D.F 0.2 max. and then let sit for 24±2 hours at room temperature. Perform the initial measurement. Humidity I.R. $12.5\Omega \cdot F min.$ (Steady) Measurement after test Perform a heat treatment at 150 +0/-10°C for one hour Dielectric No failure and then let sit for 24±2 hours at room temperature, then Strength measure Apply 125% of the rated voltage for 1000±12 hours at the Appearance No marking defects maximum operating temperature ±3°C. Let sit for 24±2 hours Capacitance R6: Within ±12.5% at room temperature, then measure. Change The charge/discharge current is less than 50mA. D.F. 0.2 max. Initial measurement Perform a heat treatment at 150 +0/-10°C for one hour Durability I.R $25\Omega \cdot F min.$ 17 and then let sit for 24±2 hours at room temperature. Perform the initial measurement. Measurement after test Dielectric No failure Perform a heat treatment at 150 +0/-10°C for one hour Strenath and then let sit for 24±2 hours at room temperature, then measure

Chip Monolithic Ceramic Capacitors



for Ultrasonic Sensors GRM Series

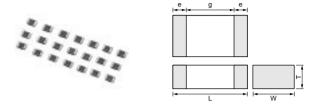
■ Features

- 1. Proper to compensate for ultrasonic sensor
- 2. Small chip size and high cap. value

■ Applications

Ultrasonic sensor

(Back sonar, Corner sonar, etc.)



Part Number		Dimensions (mm)										
Part Number	L	W	T	е	g min.							
GRM219	2.0 ±0.1	1.25 ±0.1	0.85 ±0.1	0.2 to 0.7	0.7							

Part Number	TC Code	Rated Voltage (Vdc)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)
GRM2199E2A102KD42	ZLM (Murata)	100	1000 ±10%	2.0	1.25	0.85
GRM2199E2A152KD42	ZLM (Murata)	100	1500 ±10%	2.0	1.25	0.85

No.	Ite	em	Specifications		Test Method					
1	Operating Temperat	e e	−25 to +85°C	Reference Tempera	ature: 20°C					
2	Rated Vo	ltage	See the previous pages.	may be applied con When AC voltage is	s defined as the maximum voltage which ntinuously to the capacitor. s superimposed on DC voltage, $V^{\text{P-P}}$ or V^{O} , should be maintained within the rated vo	D-P,				
3	Appearar	псе	No defects or abnormalities	Visual inspection						
4	Dimensio	ns	Within the specified dimensions	Using calipers						
5	Dielectric	Strength	No defects or abnormalities	is applied between	e observed when 300% of the rated volta the terminations for 1 to 5 seconds, provi harge current is less than 50mA.	-				
6	Insulation (I.R.)	Resistance	More than 10,000MΩ	The insulation resistance should be measured with a DC volt age not exceeding the rated voltage at 20°C and 75%RH may and within 2 minutes of charging.						
7	Capacita	nce	Within the specified tolerance	The constitutes/D						
8	Dissipatio (D.F.)	n Factor	0.01 max.		.F. should be measured at 20°C with ency and 1±0.2Vrms in voltage.					
9	Capacitar Temperat Character	ure	Within $-4,700^{+1}.2000^{+1}.2000^{+1}$ ppm/°C (at -25 to $+20$ °C) Within $-4,700^{+5}.000^{+5}$ ppm/°C (at $+20$ to $+85$ °C)	capacitance measu When cycling the te 5, the capacitance of the temperature con The capacitance ch	1 20±2 2 -25±3					
				4	85±3					
				5 20±2						
10	Adhesive of Termin		No removal of the terminations or other defect should occur.	Fig.1 using a eutec direction of the arro The soldering shou reflow method and	or to the test jig (glass epoxy board) show titic solder. Then apply 10N force in the low. Ild be done either with an iron or using the should be conducted with care so that then and free of defects such as heat shock. Solder resist Baked electrode or copper foil 1.2 4.0 1.65 (in mn	e				
		Annearance	No defects or abnormalities	Solder the capacite	or to the test jig (glass epoxy board) in the					
		Appearance Capacitance	Within the specified tolerance		under the same conditions as (10).	-				
11	Vibration Resistance	D.F.	0.01 max.	having a total ampli uniformly between the frequency range, from be traversed in applied for a period	The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of 3 mutually perpendicular directions (total of 6 hours).					





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Specifications and Test Methods

Continued from the preceding page Specifications No Item Test Method Solder the capacitor to the test jig (glass epoxy boards) shown No cracking or marking defects should occur. in Fig. 2 using a eutectic solder. Then apply a force in the direction shown in Fig. 3. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 50 Pressurizing speed: 1.0mm/sec. _Pressurize Deflection 12 R230 t: 1.6mm 100 Type а h C Capacitance meter GRM21 1.2 4.0 1.65 45 (in mm) (in mm) Fig. 2 Fig.3 Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at Solderability of 75% of the terminations are to be soldered evenly and 80 to 120°C for 10 to 30 seconds. After preheating, immerse in 13 Termination continuously. eutectic solder solution for 2±0.5 seconds at 230±5℃ or Sn-3.0Ag-0.5Cu solder solution for 2±0.5 seconds at 245±5°C. Appearance No defects or abnormalities Capacitance Within ±7.5% Preheat the capacitor at 120 to 150°C for 1 minute. Immerse the Change Resistance capacitor in a eutectic solder or Sn-3.0Ag-0.5Cu solder solution 14 to Soldering D.F 0.01 max at 270±5°C for 10±0.5 seconds. Let sit at room temperature for Heat More than $10,000M\Omega$ I.R. 24±2 hours, then measure. Dielectric No failure Strength Appearance No defects or abnormalities Fix the capacitor to the supporting jig in the same manner and under the same conditions as (11). Capacitance Within ±7.5% Perform the five cycles according to the four heat treatments Change listed in the following table. Let sit for 24±2 hours at room tem-Temperature perature, then measure. D.F. 0.01 max 15 Cycle Step I.R. More than $10,000M\Omega$ 2 3 4 85⁺³_o -25±3 Room Temp. Room Temp. Temp. (℃) Dielectric No failure 30±3 2 to 3 30±3 Time (min.) 2 to 3 Strength Appearance No defects or abnormalities Capacitance Within ±12.5% Sit the capacitor at 40±2℃ and 90 to 95% humidity for 500±12 Change Humidity, Steady D.F. 0.02 max Remove and let sit for 24±2 hours at room temperature, then State I.R. More than 1,000M Ω measure Dielectric No failure Strength Appearance No defects or abnormalities Apply the rated voltage at 40±2℃ and 90 to 95% humidity for Capacitance Within ±12.5% Humidity 500±12 hours. Remove and let sit for 24±2 hours at room tem-Change 17 Load perature, then measure. The charge/discharge current is less D.F. 0.02 max. than 50mA. I.R. More than $500M\Omega$ No defects or abnormalities Appearance Capacitance Apply 200% of the rated voltage for 1,000±12 hours at 85±3℃. Within ±12.5% Change Let sit for 24±2 hours at room temperature, then measure. 18 Temperature The charge/discharge current is less than 50mA. Load D.F. 0.02 max I.R. More than $1,000M\Omega$





Low ESL LLL/LLA/LLM Series

- Features (Reversed Geometry Low ESL Type)
- 1. Low ESL, good for noise reduction for high frequency
- 2. Small, high cap
- Applications
- 1. High speed microprocessor
- 2. High frequency digital equipment



Part Number		Dimensions (mm))		
r art ivumber	L	W	T		
LLL153	0.5 ±0.05	1.0 ±0.05	0.3 ±0.05		
LLL185	0.8 ±0.1	1.6 ±0.1	0.6 max.		
LLL215			0.5 +0/-0.15		
LLL216	1.25 ±0.1	2.0 ±0.1	0.6 ±0.1		
LLL219			0.85 ±0.1		
LLL315			0.5 +0/-0.15		
LLL317	1.6 +0.15	3.2 ±0.15	0.7 ±0.1		
LLL31M	1.6 ±0.15	3.2 ±0.15	1.15 ±0.1		
LLL31B			1.25 +0.15/-0.05		

Reversed Geometry Low ESL Type

Part Number	LLL15			LL	L18					LLI	L21					LLI	L31		
LxW	0.5x1.0			0.8	x1.6					1.25	x2.0					1.6	x3.2		
тс	X6S (C8)			X7R (R7)			X7S (C7)			X7R (R7)			X7S (C7)			X7R (R7)			X7S (C7)
Rated Volt.	6.3 (0J)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	4 (0G)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	4 (0G)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	4 (0G)
Capacitance (Ca	apacita	nce pa	rt numl	pering (code) a	nd T (n	nm) Dir	nensior	T Din (T	nensior	part r	umber	ing cod	le)					
2200pF (222)		0.5 (5)																	
4700pF (472)		0.5 (5)						0.6 (6)											
10000pF (103)			0.5 (5)					0.6 (6)						0.7 (7)					
22000pF (223)			0.5 (5)					0.6 (6)						0.7 (7)					
47000pF (473)				0.5 (5)					0.6 (6)					0.7 (7)					
0.10μF (104)	0.3 (3)				0.5 (5)				0.6 (6)					1.15 (M)	0.7 (7)				
0.22μF (224)						0.5 (5)				0.85 (9)	0.6 (6)				1.15 (M)	0.7 (7)			
0.47μF (474)							0.5 (5)				0.85 (9)				1.15 (M)	0.7 (7)			
1.0µF (105)							0.5 (5)					0.85 (9)				1.15 (M)	0.7 (7)		
2.2μF (225)							0.5 (5)						0.85 (9)				1.15 (M)	0.7 (7)	
4.7μF (475)																		1.15 (M)	
10μF (106)																			1.25 (B)

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

Please refer to Specifications and Test Method (2) about LLL15 Series and LLL18 Series $1.0\mu F/2.2\mu F$ type.

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Reversed Geometry Low ESL Type Low Profile

Part Number		LLI	L18				LL	L21				LLL31			
LxW		0.83	x1.6		1.25x2.0							1.6x3.2			
тс	X7R (R7) (C7)						X7R (R7)		X7S (C7)	X7R (R7)					
Rated Volt.	25 (1E)	16 (1C)	10 (1A)	4 (0G)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	4 (0G)	50 (1H)	25 (1E)	16 (1C)	10 (1A)	
Capacitance (Ca	pacitanc	e part nur	mbering c	ode) and	T (mm) D	imension	(T Dimen	sion part	numberin	g code)					
1000pF(102)					0.5(5)										
2200pF(222)					0.5(5)										
4700pF(472)					0.5(5)										
10000pF(103)	0.5(5)				0.5(5)						0.5(5)				
22000pF(223)		0.5(5)				0.5(5)					0.5(5)				
47000pF(473)		0.5(5)					0.5(5)					0.5(5)			
0.10μF(104)			0.5(5)				0.5(5)					0.5(5)			
0.22μF(224)				0.5(5)				0.5(5)					0.5(5)		
0.47μF(474)									0.5(5)					0.5(5)	
1.0μF(105)										0.5(5)					

The part numbering code is shown in ().

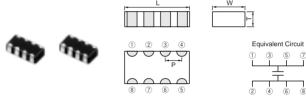
Dimensions are shown in mm and Rated Voltage in Vdc.

■ Features (Eight Terminals Low ESL Type)

- 1. Low ESL(100pH), suitable to decoupling capacitor for 1GHz clock speed IC.
- 2. Small, large cap

■ Applications

- 1. High speed microprocessor
- 2. High frequency digital equipment



			. , ,				
Part Number	Dimensions (mm)						
Part Number	L	W	T	Р			
LLA185	1.6 ±0.1	0.8 ±0.1	0.5 +0.05/-0.1	0.4 ±0.1			
LLA215	2.0 ±0.1	1.25 ±0.1	0.5 +0.05/-0.1	0.5 ±0.05			
LLA219	2.0 ±0.1	1.25 ±0.1	0.85 ±0.1	0.5 ±0.05			
LLA315	3.2 ±0.15	1.6 ±0.15	0.5 +0.05/-0.1	0.8 ±0.1			
LLA319	3.2 ±0.15	1.6 ±0.15	0.85 ±0.1	0.8 ±0.1			
LLA31M	3.2 ±0.15	1.6 ±0.15	1.15±0.1	0.8 ±0.1			

Eight Terminals Low ESL Type

Part Number	LLA18			LLA21				LLA31	
LxW	1.6x0.8			2.0x1.25				3.2x1.6	
TC	X7S (C7)			7R R7)		X7S (C7)		X7R (R7)	
Rated Volt.	4 (0G)	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	4 (0G)	16 (1C)	10 (1A)	4 (0G)
Capacitance (Ca	pacitance par	t numbering co	ode) and T (mr	n) Dimension (1	Dimension pa	rt numbering o	ode)	'	<u>'</u>
10000pF(103)		0.85(9)							
22000pF(223)		0.85(9)							
47000pF(473)		0.85(9)							
0.10μF(104)	0.5 (5)		0.85(9)				0.85(9)		
0.22μF(224)	0.5(5)		0.85(9)				0.85(9)		
0.47μF(474)	0.5 (5)			0.85(9)			0.85(9)		
1.0μF(105)	0.5 (5)				0.85(9)			0.85(9)	
2.2μF(225)	0.5 (5)					0.85(9)		1.15(M)	0.85(9)
4.7μF(475)						0.85(9)			

The part numbering code is shown in ().

Please refer to Specifications and Test Method (2) about LLA18 Series 1.0µF/2.2µF type and LLA21 Series 4.7µF type.

Dimensions are shown in mm and Rated Voltage in Vdc.

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Eight Terminals Low ESL Type Low Profile

Part Number			LLA21				LLA31	
LxW			2.0x1.25				3.2x1.6	
тс		X7 (R			X7S (C7)		X7R (R7)	
Rated Volt.	25 (1E)	16 (1C)	10 (1A)	6.3 (0J)	4 (0G)	16 (1C)	10 (1A)	6.3 (0J)
Capacitance (Ca	pacitance part n	umbering code)	and T (mm) Dim	ension (T Dimer	sion part numbe	ring code)		
10000pF(103)	0.5(5)							
22000pF(223)	0.5(5)							
47000pF(473)		0.5(5)						
0.10μF(104)		0.5(5)				0.5(5)		
0.22μF(224)			0.5 (5)	0.5(5)		0.5(5)		
0.47μF(474)				0.5(5)			0.5(5)	
1.0μF(105)					0.5(5)			0.5(5)
2.2μF(225)					0.5(5)			0.5(5)
4.7μF(475)					0.5(5)			

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

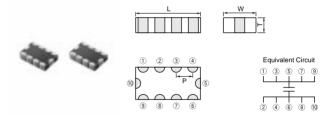
Please refer to Specifications and Test Method (2) about LLA21 Series (Low Profile) $2.2\mu F/4.7\mu F$ type.

■ Features (Ten Terminals Low ESL Type)

- 1. Low ESL(45pH), suitable to decoupling capacitor for 2GHz clock speed IC.
- 2. Small, large cap

■ Applications

- 1. High speed microprocessor
- 2. High frequency digital equipment



Part Number		Dimensions (mm)					
Part Number	L	W	Т	Р			
LLM215	2.0 ±0.1	1.25 ±0.1	0.5 +0.05/-0.1	0.5 ±0.05			
LLM315	3.2 ±0.15	1.6 ±0.15	0.5 +0.05/-0.1	0.8 ±0.1			

Ten Terminals Low ESL Type Low Profile

Part Number		LLI	W21			LLM31	
LxW		2.0x1.25				3.2x1.6	
TC		X7R (R7)		X7S (C7)		X7R (R7)	
Rated Volt.	25 (1E)	16 (1C)	6.3 (0J)	4 (0G)	16 (1C)	10 (1A)	6.3 (0J)
Capacitance (Ca	pacitance part nui	mbering code) and	T (mm) Dimension	(T Dimension part	numbering code)		
10000pF(103)	0.5 (5)						
22000pF(223)	0.5 (5)						
47000pF(473)		0.5 (5)					
0.10μF(104)		0.5 (5)			0.5 (5)		
0.22μF(224)			0.5 (5)		0.5 (5)		
0.47μF(474)			0.5 (5)			0.5(5)	
1.0μF(105)				0.5 (5)			
2.2μF(225)				0.5 (5)			0.5 (5)

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

Please refer to Specifications and Test Method (2) about LLM21 Series (Low Profile) $2.2\mu\text{F}$ type.

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LLL/LLA/LLM Series Specifications and Test Methods (1)

Specifications No Item Test Method Operating R7, C7: -55 to +125°C Temperature Range The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, VP-P or VO-P, Rated Voltage See the previous pages. whichever is larger, should be maintained within the rated voltage range. 3 **Appearance** No defects or abnormalities Visual inspection Using calipers 4 Dimensions Within the specified dimension No failure should be observed when 250% of the rated voltage Dielectric Strength No defects or abnormalities is applied between the terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA The insulation resistance should be measured with a DC voltage Insulation More than $10{,}000M\Omega$ or $500\Omega \cdot F$ not exceeding the rated voltage at 25°C and 75%RH max. and 6 Resistance (Whichever is smaller) within 2 minutes of charging. Within the specified tolerance 7 Capacitance The capacitance/D.F. should be measured at 25°C at the frequency and voltage shown in the table. Capacitance Frequency Voltage W.V.: 25V min.; 0.025 max. **Dissipation Factor** C≦10µF (10V min.) 1±0.1kHz 1.0±0.2Vrms 8 (D.F.) W.V.: 16V max.; 0.035 max. *1 C≦10µF (6.3V max.) 1±0.1kHz 0.5±0.1Vrms 120±24Hz C>10µF 0.5 ± 0.1 Vrms The capacitance change should be measured after 5 min. at each specified temperature stage Step Temperature (°C) 25±2 Reference Temp. Range 2 -55±3 Capacitance Char Cap.Change (°C) Temp. Temperature 3 25+2-55 to +125 Within ±15% R7 25°C Characteristics 4 125±3 -55 to +125 25°C Within ±22% C7 5 25±2 The ranges of capacitance change compared with the 25°C value over the temperature ranges shown in the table should be within the specified ranges. Solder the capacitor to the test jig (glass epoxy board) using a eutectic solder. Then apply 10N* force in parallel with the test Adhesive Strength jig for 10±1 sec. The soldering should be done either with an 10 No removal of the terminations or other defect should occur. of Termination iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as *LLL18 and LLA/LLM Series: 5N heat shock Appearance No defects or abnormalities Solder the capacitor to the test jig (glass epoxy board) in the same manner and under the same conditions as (10). The Capacitance Within the specified tolerance capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied Vibration 11 uniformly between the approximate limits of 10 and 55Hz. The Resistance W.V.: 25V min.; 0.025 max. frequency range, from 10 to 55Hz and return to 10Hz, should D.F. W.V.: 16V max.; 0.035 max. *1 be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of 3 mutually perpendicular directions (total of 6 hours). Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at Solderability of 75% of the terminations are to be soldered evenly 12 80 to 120°C for 10 to 30 seconds. After preheating, immerse in Termination and continuously eutectic solder solution for 2±0.5 seconds at 230±5°C, or Sn-3.0Ag-0.5Cu solder solution for 2±0.5 seconds at 245±5°C. Appearance No marking defects Preheat the capacitor at 120 to 150°C for 1 minute. Immerse the capacitor in a eutectic solder or Sn-3.0Ag-0.5Cu solder Capacitance Within ±7.5% solution at 270±5°C for 10±0.5 seconds. Let sit at room Change Resistance temperature for 24±2 hours, then measure. W.V.: 25V min.; 0.025 max. 13 to Soldering D.F. W.V.: 16V max.; 0.035 max. *1 Initial measurement. Heat More than $10,000M\Omega$ or $500\Omega \cdot F$ (Whichever is smaller) I.R. Perform a heat treatment at 150^{+o}_{-1o}°C for one hour and then let sit for 24±2 hours at room temperature. Perform the initial Dielectric No failure measurement.

Continued on the following page.





Strength

LLL/LLA/LLM Series Specifications and Test Methods (1)

Continued from the preceding page.

No.	Ite	em	Specifications		Test Method				
		Appearance Capacitance Change	No marking defects Within ±7.5% *1	under the san Perform the fi	Fix the capacitor to the supporting jig in the same manner as under the same conditions as (10). Perform the five cycles according to the four heat treatments listed in the following table. Let sit for 24±2 hours at room				
		D.F.	W.V.: 25V min.; 0.025 max. W.V.: 16V max.; 0.035 max. *1	temperature,	•	2	3	4	
14	Temperature Cycle	I.R.	More than 10,000M Ω or 500 Ω · F (Whichever is smaller)	Temp. (°C)	Min. Operating Temp. ±3		Max. Operating Temp. ±3		
	, .,	Dielectric Strength	No failure		30±3 rement. eat treatment a		30±3		
		Annogrange	No marking defeate	measuremer		m tempe	rature. Perform	tne initial	
15	Humidity (Steady	Appearance Capacitance Change	No marking defects Within ±12.5% *1	•			95% humidity		
	State)	D.F.	0.05 max. *1		hours. Remove and let sit for 24±2 hours at room temper then measure.		inporataro,		
		I.R.	More than 1,000M Ω or 50 Ω · F (Whichever is smaller)		1				
		Appearance	No marking defects						
		Capacitance Change	Within ±12.5% *1	Apply the rate	d voltage at 40)+2°C an	ıd 90 to 95% hu	ımidity for	
16	Humidity	D.F.	0.05 max. *1	500±12 hours	s. Remove and	let sit for	r 24±2 hours at	room	
	Load	I.R.	More than 500M Ω or 25 Ω · F *1 (Whichever is smaller)	temperature, less than 50m		The chai	ge/discharge c	urrent is	
		Dielectric Strength	No failure						
		Appearance	No marking defects	Apply 200% o	f the rated volt	age for 1	000±12 hours	at the	
		Capacitance Change	Within ±12.5% *1	maximum ope	Apply 200% of the rated voltage for 1000±12 hours at the maximum operating temperature ±3°C. Let sit for 24±2 hours at room temperature, then measure. The charge/discharge				
17	High Temperature	D.F.	W.V.: 25V min.; 0.04 max. W.V.: 16V max.; 0.05 max. *1	current is less					
	Load			Apply 200% maximum op	of the rated DO perating temper	rature ±3	for one hour at 8°C. Remove ar		
	Dielectric Strength No failure		24±2 hours at room temperature. Perform initial measurement. (*1)						

^{*1:} The figure indicates typical inspection.Please refer to individual specifications.

LLL/LLA/LLM Series Specifications and Test Methods (2)

No.	Ite	em		Spe	cifications		Т	est Method	
1	Operating Temperat Range		R7, C7: -55 C8: -55 to -						
2	Rated Vo	ltage	See the prev	vious pages.			The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{P,P} or V ^{OP} , whichever is larger, should be maintained within the rated voltage range.		
3	Appearar	ice	No defects of	or abnormalities			Visual inspection		
4	Dimensio	ns	Within the sp	pecified dimension	n		Using calipers		
5	Dielectric	Strength	No defects of	or abnormalities			No failure should be observing applied between the term provided the charge/discharge	ninations for 1 to	5 seconds,
6	Insulation Resistant		50Ω · F min.				The insulation resistance s not exceeding the rated vo within 1 minute of charging	Itage at 25°C and	•
7	Capacita	nce	Within the s	pecified tolerance	9		The capacitance/D.F. shou frequency and voltage show		at 25°C at the
8	Dissipatio (D.F.)	n Factor	R7, C7, C8:	0.120 max.			Capacitance C≤10μF (10V min.) C≤10μF (6.3V max.) C>10μF	Frequency 1±0.1kHz 1±0.1kHz 120±24Hz	Voltage 1.0±0.2Vrms 0.5±0.1Vrms 0.5±0.1Vrms
9	Capacitar Temperat Character	ure	Char. R7 C7 C8	Temp. Range (°C) -55 to +125 -55 to +125 -55 to +105	Reference Temp. 25°C	Cap.Change Within ±15% Within ±22% Within ±22%	The capacitance change should be measured after 5 min. at each specified temperature stage. The ranges of capacitance change compared with the 25°C value over the temperature ranges shown in the table should be within the specified ranges. Solder the capacitor to the test jig (glass epoxy board) using a		
10	Adhesive of Termin	•	No removal	of the termination	ns or other defe	ct should occur.	eutectic solder. Then apply jig for 10±1 sec. The solde iron or using the reflow me care so that the soldering is heat shock.	ring should be do thod and should s uniform and fre	one either with an be conducted with
		Appearance	No defects of	or abnormalities			Solder the capacitor to the	test jig (glass ep	oxy board) in
		Capacitance	Within the sp	pecified tolerance	9		the same manner and under the same conditions as (10). The capacitor should be subjected to a simple harmonic motion		
11	Vibration	D.F.	R7, C7, C8:	0.120 max.			having a total amplitude of uniformly between the appl frequency range, from 10 t be traversed in approximat applied for a period of 2 ho perpendicular directions (to	1.5mm, the frequency from the frequency of the frequency	uency being varied 10 and 55Hz. The n to 10Hz, should s motion should be
12	Solderab Terminati	•	75% of the terminations are to be soldered evenly and continuously.		Immerse the capacitor in a rosin (JIS-K-5902) (25% ro 80 to 120°C for 10 to 30 se eutectic solder solution for Sn-3.0Ag-0.5Cu solder sol	sin in weight propections. After prefections at 2±0.5 seconds at	portion). Preheat at neating, immerse in at 230±5°C, or		
		Appearance No marking defects		Preheat the capacitor at 12					
	Resistance	Capacitance Change R7, C7, C8: Within ±7.5%		the capacitor in a eutectic s solution at 270±5°C for 10: Let sit at room temperature	±0.5 seconds.				
13	to Soldering	D.F.	R7, C7, C8:	0.120 max.			• Initial massure		
	Heat	I.R.	50Ω · F min.	•			Initial measurement. Perform a heat treatment	at 150±0 °C for	one hour and then
		Dielectric Strength	No failure				let sit for 24±2 hours at romeasurement.	oom temperature.	





LLL/LLA/LLM Series Specifications and Test Methods (2)

Continued from the preceding page.

Vo.	Ite	em	Specifications	Test Method
		Appearance Capacitance Change D.F.	No marking defects R7, C7, C8: Within ±12.5% R7, C7, C8: 0.120 max.	Fix the capacitor to the supporting jig in the same manner and under the same conditions as (10).Perform the five cycles according to the four heat treatments listed in the following table. Let sit for 24±2 hours at room temperature, then measure.
	Tanananahana	I.R.	50Ω · F min.	Step 1 2 3 4
14	Temperature Sudden Change	I.K.	5052 · F min.	Temp. (°C) Min. Operating Temp. ± g Temp. Room Temp. ± g Temp. Max. Operating Temp. ± g Temp. Room Temp. ± g Temp. Time (min.) 30±3 2 to 3 30±3 2 to 3
		Dielectric Strength	No failure	• Initial measurement Perform a heat treatment at 150±9° °C for one hour and the let sit for 24±2 hours at room temperature. Perform the initial measurement.
		Appearance	No marking defects	Apply the rated voltage at 40±2°C and 90 to 95% humidity fo 500±12 hours.
	High	Capacitance Change	R7, C7, C8: Within ±12.5%	The charge/discharge current is less than 50mA.
	Temperatue	D.F.	R7, C7, C8: 0.2 max.	•Initial measurement
15	High Humidity (Steady State)	I.R.	12.5Ω · F min.	Perform a heat treatment at 150±9°°C for one hour and the let sit for 24±2 hours at room temperature. Perform the initial measurement. •Measurement after test Perform a heat treatment at 150±9°°C for one hour and the let sit for 24±2 hours at room temperature, then measure.
		Appearance	No marking defects	Apply 150% of the rated voltage for 1000±12 hours at the
		Capacitance Change	R7, C7, C8: Within ±12.5%	maximum operating temperature ±3°C. The charge/discharge current is less than 50mA.
		D.F.	R7, C7, C8: 0.2 max.	•Initial measurement
16	Durability	I.R.	$25\Omega \cdot F$ min.	Perform a heat treatment at 150±\(^0\)0°C for one hour and the let sit for 24±2 hours at room temperature. Perform the initial measurement. •Measurement after test Perform a heat treatment at 150±\(^0\)0°C for one hour and the let sit for 24±2 hours at room temperature, then measure.

Chip Monolithic Ceramic Capacitors



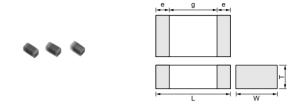
High-Q GJM Series

■ Features

- 1. Mobile telecommunications and RF module, mainly
- 2. Quality improvement of telephone call, low power consumption, yield ratio improvement

■ Applications

VCO, PA, Mobile telecommunications



Part Number	Dimensions (mm)					
Part Number	L	W	T	е	g min.	
GJM03	0.6 ±0.03	0.3 ±0.03	0.3 ±0.03	0.1 to 0.2	0.2	
GJM15	1.0 ±0.05	0.5 ±0.05	0.5 ±0.05	0.15 to 0.3	0.4	

Part Number	GJM03	GJM15
L x W [EIA]	0.6x0.3 [0201]	1.0x0.5 [0402]
тс	C0G (5C)	C0G (5C)
Rated Volt.	25 (1E)	50 (1H)
Capacitance (Ca	pacitance part numbering code) and T (mm) Dimension (T Dimen	sion part numbering code)
0.20pF(R20)	0.3(3)	
0.30pF(R30)	0.3(3)	0.5 (5)
0.40pF(R40)	0.3(3)	0.5(5)
0.50pF(R50)	0.3(3)	0.5(5)
0.60pF(R60)	0.3(3)	0.5(5)
0.70pF(R70)	0.3(3)	0.5 (5)
0.75pF(R75)	0.3(3)	0.5 (5)
0.80pF(R80)	0.3(3)	0.5 (5)
0.90pF(R90)	0.3(3)	0.5 (5)
1.0pF(1R0)	0.3(3)	0.5 (5)
1.1pF(1R1)	0.3(3)	0.5 (5)
1.2pF(1R2)	0.3(3)	0.5 (5)
1.3pF(1R3)	0.3(3)	0.5 (5)
1.4pF(1R4)	0.3(3)	0.5 (5)
1.5pF(1R5)	0.3(3)	0.5 (5)
1.6pF(1R6)	0.3(3)	0.5 (5)
1.7pF(1R7)	0.3(3)	0.5 (5)
1.8pF(1R8)	0.3(3)	0.5 (5)
1.9pF(1R9)	0.3(3)	0.5 (5)
2.0pF(2R0)	0.3(3)	0.5 (5)
2.1pF(2R1)	0.3(3)	0.5 (5)
2.2pF(2R2)	0.3(3)	0.5 (5)
2.3pF(2R3)	0.3(3)	0.5 (5)
2.4pF(2R4)	0.3(3)	0.5 (5)
2.5pF(2R5)	0.3(3)	0.5 (5)
2.6pF(2R6)	0.3(3)	0.5 (5)
2.7pF(2R7)	0.3(3)	0.5(5)
2.8pF(2R8)	0.3(3)	0.5 (5)
2.9pF(2R9)	0.3(3)	0.5 (5)
3.0pF(3R0)	0.3(3)	0.5(5)
3.1pF(3R1)	0.3(3)	0.5(5)
3.2pF(3R2)	0.3(3)	0.5 (5)
3.3pF(3R3)	0.3(3)	0.5(5)

Continued from the preceding page.

Part Number	GJM03	GJM15
L x W [EIA]	0.6x0.3 [0201]	1.0x0.5 [0402]
тс	C0G (5C)	C0G (5C)
Rated Volt.	25 (1E)	50 (1H)
Capacitance (Capacitance)	part numbering code) and T (mm) Dimension (T Din	nension part numbering code)
3.4pF(3R4)	0.3(3)	0.5(5)
3.5pF(3R5)	0.3(3)	0.5(5)
3.6pF(3R6)	0.3(3)	0.5 (5)
3.7pF(3R7)	0.3(3)	0.5(5)
3.8pF(3R8)	0.3(3)	0.5 (5)
3.9pF(3R9)	0.3(3)	0.5(5)
4.0pF(4R0)	0.3(3)	0.5(5)
4.1pF(4R1)	0.3(3)	0.5 (5)
4.2pF(4R2)	0.3(3)	0.5 (5)
4.3pF(4R3)	0.3(3)	0.5(5)
4.4pF(4R4)	0.3(3)	0.5(5)
4.5pF(4R5)	0.3(3)	0.5(5)
4.6pF(4R6)	0.3(3)	0.5(5)
4.7pF(4R7)	0.3(3)	0.5(5)
4.8pF(4R8)	0.3(3)	0.5 (5)
4.9pF(4R9)	0.3(3)	0.5 (5)
5.0pF(5R0)	0.3(3)	0.5 (5)
5.1pF(5R1)	0.3(3)	0.5 (5)
5.2pF(5R2)	0.3(3)	0.5(5)
5.3pF(5R3)	0.3(3)	0.5 (5)
5.4pF(5R4)	0.3(3)	0.5 (5)
5.5pF(5R5)	0.3(3)	0.5 (5)
5.6pF(5R6)	0.3(3)	0.5(5)
5.7pF(5R7)	0.3(3)	0.5(5)
5.8pF(5R8)	0.3(3)	0.5(5)
5.9pF(5R9)	0.3(3)	0.5(5)
6.0pF(6R0)	0.3(3)	0.5 (5)
6.1pF(6R1)	0.3(3)	0.5 (5)
6.2pF(6R2)	0.3(3)	0.5 (5)
6.3pF(6R3)	0.3(3)	0.5(5)
6.4pF(6R4)	0.3(3)	0.5 (5)
6.5pF(6R5)	0.3(3)	0.5 (5)
6.6pF(6R6)	0.3(3)	0.5 (5)
6.7pF(6R7)	0.3(3)	0.5 (5)
6.8pF(6R8)	0.3(3)	0.5 (5)
6.9pF(6R9)		0.5(5)
7.0pF(7R0)		0.5(5)
7.1pF(7R1)		0.5(5)
7.2pF(7R2)		0.5(5)
7.3pF(7R3)		0.5 (5)
7.4pF(7R4)		0.5(5)
7.5pF(7R5)		0.5(5)
7.6pF(7R6)		0.5(5)
7.7pF(7R7)		0.5(5)
7.8pF(7R8)		0.5(5)
7.9pF(7R9)		0.5(5)
8.0pF(8R0)		0.5(5)
8.1pF(8R1)		0.5 (5)
8.2pF(8R2)		0.5(5)
8.3pF(8R3)		0.5 (5)
8.4pF(8R4)		0.5 (5)
8.5pF(8R5)		0.5(5)

Continued from the preceding page.

Part Number	GJM03	GJM15
L x W [EIA]	0.6x0.3 [0201]	1.0x0.5 [0402]
тс	C0G (5C)	C0G (5C)
Rated Volt.	25 (1E)	50 (1H)
Capacitance (Capac	citance part numbering code) and T (mm) Dimension (T Dimen	sion part numbering code)
8.6pF(8R6)		0.5 (5)
8.7pF(8R7)		0.5 (5)
8.8pF(8R8)		0.5 (5)
8.9pF(8R9)		0.5 (5)
9.0pF(9R0)		0.5 (5)
9.1pF(9R1)		0.5 (5)
9.2pF(9R2)		0.5 (5)
9.3pF(9R3)		0.5 (5)
9.4pF(9R4)		0.5 (5)
9.5pF(9R5)		0.5 (5)
9.6pF(9R6)		0.5 (5)
9.7pF(9R7)		0.5 (5)
9.8pF(9R8)		0.5 (5)
9.9pF(9R9)		0.5 (5)
10pF(100)		0.5(5)
12pF(120)		0.5(5)
15pF(150)		0.5(5)
18pF(180)		0.5 (5)

The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

Chip Monolithic Ceramic Capacitors



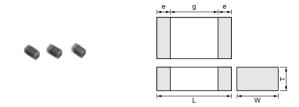
Tight Tolerance High-Q GJM Series

■ Features

- 1. Mobile telecommunications and RF module, mainly
- 2. Quality improvement of telephone call, low power consumption, yield ratio improvement

■ Applications

VCO, PA, Mobile telecommunications



Part Number	Dimensions (mm)							
Part Number	L	W	T	е	g min.			
GJM03	0.6 ±0.03	0.3 ±0.03	0.3 ±0.03	0.1 to 0.2	0.2			
GJM15	1.0 ±0.05	0.5 ±0.05	0.5 ±0.05	0.15 to 0.3	0.4			

Part Number		GJM03	GJM15
L x W [EIA]		0.6x0.3 [0201]	1.0x0.5 [0402]
тс		C0G (5C)	C0G (5C)
Rated Volt.		25 (1E)	50 (1H)
Capacitance, Ca	pacitano	e Tolerance and T Dimension	
0.10pF(R10)	W, B		0.5 (5)
0.20pF(R20)	W, B	0.3(3)	0.5 (5)
0.30pF(R30)	W, B	0.3(3)	0.5 (5)
0.40pF(R40)	W, B	0.3(3)	0.5 (5)
0.50pF(R50)	W, B	0.3(3)	0.5 (5)
0.60pF(R60)	W, B	0.3(3)	0.5 (5)
0.70pF(R70)	W, B	0.3(3)	0.5(5)
0.80pF(R80)	W, B	0.3(3)	0.5 (5)
0.90pF(R90)	W, B	0.3 (3)	0.5 (5)
1.0pF(1R0)	W, B	0.3(3)	0.5 (5)
1.1pF(1R1)	W, B	0.3(3)	0.5 (5)
1.2pF(1R2)	W, B	0.3(3)	0.5 (5)
1.3pF(1R3)	W, B	0.3(3)	0.5 (5)
1.4pF(1R4)	W, B	0.3(3)	0.5 (5)
1.5pF(1R5)	W, B	0.3(3)	0.5 (5)
1.6pF(1R6)	W, B	0.3(3)	0.5 (5)
1.7pF(1R7)	W, B	0.3(3)	0.5 (5)
1.8pF(1R8)	W, B	0.3(3)	0.5 (5)
1.9pF(1R9)	W, B	0.3(3)	0.5 (5)
2.0pF(2R0)	W, B	0.3(3)	0.5 (5)
2.1pF(2R1)	W, B	0.3(3)	0.5 (5)
2.2pF(2R2)	W, B	0.3(3)	0.5 (5)
2.3pF(2R3)	W, B	0.3(3)	0.5(5)
2.4pF(2R4)	W, B	0.3(3)	0.5 (5)
2.5pF(2R5)	W, B	0.3(3)	0.5 (5)
2.6pF(2R6)	W, B	0.3(3)	0.5 (5)
2.7pF(2R7)	W, B	0.3(3)	0.5 (5)
2.8pF(2R8)	W, B	0.3(3)	0.5 (5)
2.9pF(2R9)	W, B	0.3(3)	0.5 (5)
3.0pF(3R0)	W, B	0.3(3)	0.5 (5)
3.1pF(3R1)	W, B	0.3(3)	0.5 (5)
3.2pF(3R2)	W, B	0.3(3)	0.5(5)
3.3pF(3R3)	W, B	0.3(3)	0.5(5)

Continued from the preceding page.

Part Number L x W [EIA]		GJM03	GJM15 1.0x0.5 [0402]		
TC TC		0.6x0.3 [0201]			
		C0G (5C)	C0G (5C)		
Rated Volt.		25 (1E)	50 (1H)		
Capacitance, Ca	pacitanc	e Tolerance and T Dimension			
3.4pF(3R4)	W, B	0.3(3)	0.5 (5)		
3.5pF(3R5)	W, B	0.3(3)	0.5(5)		
3.6pF(3R6)	W, B	0.3(3)	0.5 (5)		
3.7pF(3R7)	W, B	0.3(3)	0.5(5)		
3.8pF(3R8)	W, B	0.3(3)	0.5(5)		
3.9pF(3R9)	W, B	0.3(3)	0.5(5)		
4.0pF(4R0)	W, B	0.3(3)	0.5(5)		
4.1pF(4R1)	W, B	0.3(3)	0.5(5)		
4.2pF(4R2) 4.3pF(4R3)	W, B W, B	0.3(3) 0.3(3)	0.5(5) 0.5(5)		
4.4pF(4R4)	W, B	0.3(3)	0.5(5)		
4.5pF(4R5)	W, B	0.3(3)	0.5(5)		
4.6pF(4R6)	W, B	0.3(3)	0.5(5)		
4.7pF(4R7)	W, B	0.3(3)	0.5(5)		
4.8pF(4R8)	W, B	0.3(3)	0.5(5)		
4.9pF(4R9)	W, B	0.3(3)	0.5 (5)		
5.0pF(5R0)	W, B	0.3(3)	0.5(5)		
5.1pF(5R1)	W, B, C	0.3(3)	0.5 (5)		
5.2pF(5R2)	W, B, C	0.3(3)	0.5(5)		
5.3pF(5R3)	W, B, C	0.3(3)	0.5(5)		
5.4pF(5R4)		0.3(3)	0.5(5)		
	W, B, C	0.3(3)	0.5(5)		
	W, B, C	0.3(3)	0.5(5)		
5.7pF(5R7)		0.3(3)	0.5(5)		
5.8pF(5R8)		0.3(3)	0.5(5)		
5.9pF(5R9) 6.0pF(6R0)	W, B, C	0.3(3)	0.5(5) 0.5(5)		
6.1pF(6R1)		0.3(3) 0.3(3)	0.5(5)		
6.2pF(6R2)		0.3(3)	0.5(5)		
6.3pF(6R3)		0.3(3)	0.5(5)		
6.4pF(6R4)		0.3(3)	0.5(5)		
6.5pF(6R5)		0.3(3)	0.5(5)		
6.6pF(6R6)		0.3(3)	0.5(5)		
6.7pF(6R7)	W, B, C	0.3(3)	0.5 (5)		
6.8pF(6R8)	W, B, C	0.3(3)	0.5(5)		
6.9pF(6R9)	W, B, C		0.5(5)		
7.0pF(7R0)	W, B, C		0.5(5)		
7.1pF(7R1)			0.5(5)		
7.2pF(7R2)			0.5(5)		
7.3pF(7R3)			0.5(5)		
7.4pF(7R4)			0.5(5)		
7.5pF(7R5)			0.5(5)		
7.6pF(7R6)			0.5(5)		
7.7pF(7R7)			0.5(5)		
7.8pF(7R8) 7.9pF(7R9)	W, B, C		0.5(5)		
8.0pF(8R0)			0.5(5) 0.5(5)		
8.0pF(8R0) 8.1pF(8R1)			0.5(5)		
8.2pF(8R2)			0.5(5)		
8.3pF(8R3)			0.5(5)		
8.4pF(8R4)			0.5(5)		
			U.J(J)		

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Part Number	GJM03	GJM15
L x W [EIA]	0.6x0.3 [0201]	1.0x0.5 [0402]
тс	C0G (5C)	C0G (5C)
Rated Volt.	25 (1E)	50 (1H)
Capacitance, Capacitance Tolerance	e and T Dimension	
8.6pF(8R6) W, B, C		0.5(5)
8.7pF(8R7) W, B, C		0.5 (5)
8.8pF(8R8) W, B, C		0.5 (5)
8.9pF(8R9) W, B, C		0.5 (5)
9.0pF(9R0) W, B, C		0.5 (5)
9.1pF(9R1) W, B, C		0.5 (5)
9.2pF(9R2) W, B, C		0.5 (5)
9.3pF(9R3) W, B, C		0.5 (5)
9.4pF(9R4) W, B, C		0.5 (5)
9.5pF(9R5) W, B, C		0.5 (5)
9.6pF(9R6) W, B, C		0.5(5)
9.7pF(9R7) W, B, C		0.5(5)
9.8pF(9R8) W, B, C		0.5(5)
9.9pF(9R9) W, B, C		0.5(5)

The part numbering code is shown in $\ (\).$

Dimensions are shown in mm and Rated Voltage in Vdc.

			Specifications				
No.	lt€	em	Temperature Compensating Type	Test Method			
1	Operating Temperati		−55 to +125°C	Reference Temperature: 25°C (2C, 3C, 4C: 20°C)			
2	Rated Vo	ltage	See the previous pages.	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p,p} or V ^{o,p} , whichever is larger, should be maintained within the rated voltage range.			
3	Appearar	nce	No defects or abnormalities	Visual inspection			
4	Dimensio	ns	Within the specified dimensions	Using calipers			
5	Dielectric	Strength	No defects or abnormalities	No failure should be observed when 300% of the rated voltage is applied between the terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA.			
6	Insulation (I.R.)	Resistance	10,000M Ω min. or 500 Ω · F min. (Whichever is smaller)	The insulation resistance should be measured with a DC voltage not exceeding the rated voltage at 25°C and 75%RH max. and within 2 minutes of charging.			
7	Capacita	nce	Within the specified tolerance	The capacitance/Q should be measured at 25℃ at the frequency and voltage shown in the table.			
8	Q	30pF max.: Q≥400+20C		Frequency 1±0.1MHz			
J			C: Nominal Capacitance (pF)	Voltage 0.5 to 5Vrms			
		Capacitance Change	Within the specified tolerance (Table A)	The capacitance change should be measured after 5 min. at each specified temperature stage.			
		Temperature Coefficient	Within the specified tolerance (Table A)	Temperature Compensating Type The temperature coefficient is determined using the			
9	Capacitance Temperature Characteristics Capacitan Drift	rature teristics Capacitance	emperature characteristics Capacitance Within ±0.2% or ±0.05pF		When cycling the temperature sequentially from step 1 through 5, (5C: +25 to 125°C: other temp. coeffs.: +20 to 125°C) the capacitance should be within the specified tolerance for the temperature coefficient and capacitance change as Table A. The capacitance drift is calculated by dividing the differences between the maximum and minimum measured values in steps 1, 3 and 5 by the capacitance value in step 3. Step Temperature (°C) 1 Reference Temp. ±2 2 -55±3 3 Reference Temp. ±2 4 125±3		
				4 125±3 5 Reference Temp. ±2			
10	Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor to the test jig (glass epoxy board) shown in Fig. 1 using a eutectic solder. Then apply a 5N* force in parallel with the test jig for 10±1 sec. The soldering should be done either with an iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. *2N (GJM03) Solder resist Baked electrode or copper foil Type a b c GJM03 0.3 0.9 0.3 GJM15 0.4 1.5 0.5 (in mm)			



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	Continued fr	om me prec	euing page.	Specifica	itions							
No.	Item Temperature Compensating Type				Tes	t Metho	d					
		Appearance	No defects or abno			<u> </u>	Solder the cap	pacitor to the te	est jig (gla	ass epoxy boar	d) in the	
		Capacitance	Within the specified	d tolerance			same manner	and under the	same co	onditions as (10).	
11	Vibration Resistance	Q	Q≥400+20C C: Nominal Capaci	tance (pF)			The capacitor should be subjected to a simple harmonic motior having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of 3 mutually perpendicular directions (total of 6 hours).			ng varied 55Hz. 10Hz, motion		
			No cracking or mar	king defects sh	nould occur.		in Fig. 2 using Then apply a	a eutectic solo	der. ection sh	ass epoxy board own in Fig. 3. reflow method	•	
				b	φ4.5			with care so the has heat shoc	k. ⊿50 Pres		m and free	
12	Deflection	า			4				Pressu	d : 1.0mm/sec. rize		
			ļ	100		t: 0.8mm	5	R230		2 -+		
			Туре	а	b	С			1	Flexure : ≦1		
			<u>GJM03</u> GJM15	0.3 0.4	0.9 1.5	0.3		Capacitan	ce meter			
				- .	•	(in mm)		45	45	(in mm)	
				Fig. 2			Fig. 3					
13	Solderabi Terminati		75% of the terminati continuously.	Immerse the capacitor in a solution rosin (JIS-K-5902) (25% rosin in variations are to be soldered evenly and Preheat at 80 to 120°C for 10 to 30 immerse in eutectic solder solution or Sn-3.0Ag-0.5Cu solder solution			in weigh to 30 sec ution for	t proportion). onds. After preh 2±0.5 seconds	eating, at 230±5℃			
		The measured and observed characteristics should satisfy the specifications in the following table.										
		Appearance	No marking defects									
14	Resistance to Soldering	Capacitance Change	Within ±2.5% or ±0.25pF (Whichever is larger)			Preheat the capacitor at 120 to 150°C for 1 minute. Immerse the capacitor in a eutectic solder or Sn-3.0Ag-0.5Cu solder solution at 270±5°C for 10±0.5 seconds.						
	Heat	Q	Q≧400+20C C: Nominal Capacit	tance (pF)				Let sit at room temperature for 24±2 hours.				
		I.R.	More than 10,000M	$ \Omega $ or $500\Omega \cdot F$	(Whichever i	s smaller)						
		Dielectric Strength	No failure									
			The measured and specifications in the			nould satisfy the	Fix the capacit	for to the suppo	ortina ija i	n the same mar	nner and	
		Appearance	No marking defects				Fix the capacitor to the supporting jig in the same manner and under the same conditions as (10). Perform the five cycles			/cles		
	Temperature	Capacitance Change	Within ±2.5% or ±0 (Whichever is large	•			_			isted in the follo ature, then mea	•	
15	Cycle	Q	Q≧400+20C C: Nominal Capaci				Step Temp. (℃)	1 Min. Operating		Max. Operating	4 Room	
		I.R.	More than 10,000M	1Ω or 500Ω · F	(Whichever i	s smaller)	Time (min.)	Temp. ±3 30±3	Temp.	Temp. ±3 30±3	Temp. 2 to 3	
		Dielectric Strength	No failure				Time (min.)	00±0	2103	00±0	2103	
			The measured and specifications in the			nould satisfy the						
		Appearance	No marking defects	3			Lot the comme	tor oit at 40 LO)C 02-1 00) to 050/ h	tu for	
16	Humidity, Steady	Capacitance Change	Within ±5% or ±0.5 (Whichever is large	•			Let the capaci 500±12 hours		c and 90	to 95% humidi	ту тог	
10	State	Q	10pF and over, 30p 10pF and below: Q	oF and below: 0 ≧200+10C	Q≧275+ 5 0	;		et sit for 24±2 temperature, th		emperature com sure.	pensating	
		I.R.	C: Nominal Capacit	. ,	(Whichever i	s smaller)						
		I.N.	More than 10,000M Ω or 500 Ω · F (Whichever is smaller)									





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No.	. Item		Specifications	Test Method	
140.			Temperature Compensating Type	rest method	
			The measured and observed characteristics should satisfy the specifications in the following table.		
		Appearance	No marking defects		
17	Humidity	Capacitance Change	Within ±7.5% or ±0.75pF (Whichever is larger)	Apply the rated voltage at 40±2℃ and 90 to 95% humidity for 500±12 hours.	
17	Load	Q	30pF and below: Q≧100+ 10 C C: Nominal Capacitance (pF)	Remove and let sit for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA.	
		I.R.	More than $500 \text{M}\Omega$ or $25 \Omega \cdot \text{F}$ (Whichever is smaller)		
		Dielectric Strength No failure			
		The measured and observed characteristics should satisfy specifications in the following table.			
		Appearance	No marking defects		
	High	Capacitance Change	Within ±3% or ±0.3pF (Whichever is larger)	Apply 200% of the rated voltage for 1000±12 hours at the maximum operating temperature ±3°C. Let sit for 24±2 hours	
18	Temperature Load	Q	10pF and over, 30pF and below: Q≥275+ ½ C 10pF and below: Q≥200+10C C: Nominal Capacitance (pF)	(temperature compensating type) at room temperature, then measure. The charge/discharge current is less than 50mA.	
		I.R.	More than 1,000M Ω or 50 Ω · F (Whichever is smaller)		
		Dielectric Strength	No failure		
19	ESR		0.5pF≦C≦1pF: 350mΩ below 1pF <c≦5pf: 300mω="" below<br="">5pF<c≦10pf: 250mω="" below<="" td=""><td>The ESR should be measured at room temperature, and frequency 1±0.2GHz with the equivalent of BOONTON Model 34A.</td></c≦10pf:></c≦5pf:>	The ESR should be measured at room temperature, and frequency 1±0.2GHz with the equivalent of BOONTON Model 34A.	
			10pF <c≦20pf: 400mω="" below<="" td=""><td>The ESR should be measured at room temperature, and frequency 500±50MHz with the equivalent of HP8753B.</td></c≦20pf:>	The ESR should be measured at room temperature, and frequency 500±50MHz with the equivalent of HP8753B.	

Table A

(I)									
	Temp. Coeff. (ppm/°C) *1	Capacitance Change from 25℃ Value (%)							
Char. Code		− 55℃		−30°C		−10 ℃			
		Max.	Min.	Max.	Min.	Max.	Min.		
5C	0±30	0.58	-0.24	0.40	-0.17	0.25	-0.11		

^{*1:} Nominal values denote the temperature coefficient within a range of 25 to 125°C.

(2)

(-)	Nominal Values (ppm/°C) *2	Capacitance Change from 20°C Value (%)						
Char.		_55°C		−25 ℃		−10°C		
		Max.	Min.	Max.	Min.	Max.	Min.	
2C	0±60	0.82	-0.45	0.49	-0.27	0.33	-0.18	
3C	0±120	0.37	-0.90	0.82	-0.54	0.55	-0.36	
4C	0±250	0.56	-0.88	1.54	-1.13	1.02	-0.75	

^{*2:} Nominal values denote the temperature coefficient within a range of 20 to 125°C.

Chip Monolithic Ceramic Capacitors



High Frequency GQM Series

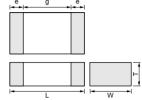
■ Features

- 1. HiQ and low ESR at VHF, UHF, Microwave
- 2. Feature improvement, low power consumption for mobile telecommunications (Base station, terminal, etc.)

■ Applications

High frequency circuit (Mobile telecommunications, etc.)





Part Number	Dimensions (mm)						
Part Number	L	W	T	е	g min.		
GQM188	1.6 ±0.1	0.8 ±0.1	0.8 ±0.1	0.2 to 0.5	0.5		
GQM219	2.0 ±0.1	1.25 ±0.1	0.85 ±0.1	0.2 to 0.7	0.7		

Part Number	GQM18	3	GQM	21	
LxW	1.6x0.8	}	2.0x1.25		
тс	C0G (5C)		C0G (5C) C0G (5C))
Rated Volt.	100 (2A)	50 (1H)	100 (2A)	50 (1H)	
Capacitance (Capacit	ance part numbering code) and	d T (mm) Dimension (T Dime	ension part numbering code)		
0.50pF(R50)	0.8(8)		0.85(9)		
0.75pF(R75)	0.8(8)		0.85(9)		
1.0pF(1R0)	0.8(8)		0.85(9)		
1.1pF(1R1)	0.8(8)		0.85(9)		
1.2pF(1R2)	0.8(8)		0.85(9)		
1.3pF(1R3)	0.8(8)		0.85 (9)		
1.5pF(1R5)	0.8(8)		0.85 (9)		
1.6pF(1R6)	0.8(8)		0.85(9)		
1.8pF(1R8)	0.8(8)		0.85(9)		
2.0pF(2R0)	0.8(8)		0.85(9)		
2.2pF(2R2)	0.8(8)		0.85(9)		
2.4pF(2R4)	0.8(8)		0.85(9)		
2.7pF(2R7)	0.8(8)		0.85(9)		
3.0pF(3R0)	0.8(8)		0.85(9)		
3.3pF(3R3)	0.8(8)		0.85(9)		
3.6pF(3R6)	0.8(8)		0.85(9)		
3.9pF(3R9)	0.8(8)		0.85(9)		
4.0pF(4R0)	0.8(8)		0.85(9)		
4.3pF(4R3)	0.8(8)		0.85(9)		
4.7pF(4R7)	0.8(8)		0.85(9)		
5.0pF(5R0)	0.8(8)		0.85(9)		
5.1pF(5R1)	0.8(8)		0.85(9)		
5.6pF(5R6)	0.8(8)		0.85 (9)		
6.0pF(6R0)	0.8(8)		0.85(9)		
6.2pF(6R2)	0.8(8)		0.85 (9)		
6.8pF(6R8)	0.8(8)		0.85 (9)		
7.0pF(7R0)		0.8(8)	0.85 (9)		
7.5pF(7R5)		0.8(8)	0.85 (9)		
8.0pF(8R0)		0.8(8)	0.85(9)		
8.2pF(8R2)		0.8(8)	0.85(9)		
9.0pF(9R0)		0.8(8)	0.85 (9)		
9.1pF(9R1)		0.8(8)	0.85 (9)		
10pF(100)		0.8(8)	0.85(9)		

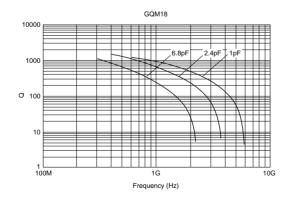
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Part Number	GQM18	3	GQM21 2.0x1.25		
LxW	1.6x0.8	3			
тс	C0G (5C)		C0G (5C)		
Rated Volt.	100 (2A)	50 (1H)	100 (2A)	50 (1H)	
Capacitance (Capacita	nce part numbering code) and	d T (mm) Dimension (T Dimer	sion part numbering code)		
11pF(110)		0.8(8)	0.85(9)		
12pF(120)		0.8(8)	0.85(9)		
13pF(130)		0.8(8)	0.85(9)		
15pF(150)		0.8(8)	0.85(9)		
16pF(160)		0.8(8)	0.85(9)		
18pF(180)		0.8(8)	0.85(9)		
20pF(200)		0.8(8)		0.85(9)	
22pF(220)		0.8(8)		0.85(9)	
24pF(240)		0.8(8)		0.85(9)	
27pF(270)		0.8(8)		0.85(9)	
30pF(300)		0.8(8)		0.85(9)	
33pF(330)		0.8(8)		0.85(9)	
36pF(360)		0.8(8)		0.85(9)	
39pF(390)		0.8(8)		0.85(9)	
43pF(430)		0.8(8)		0.85(9)	
47pF(470)		0.8(8)		0.85(9)	
51pF(510)		0.8(8)		0.85(9)	
56pF(560)		0.8(8)		0.85(9)	
62pF(620)		0.8(8)		0.85(9)	
68pF(680)		0.8(8)		0.85(9)	
75pF(750)		0.8(8)		0.85(9)	
82pF(820)		0.8(8)		0.85(9)	
91pF(910)		0.8(8)		0.85(9)	
100pF(101)		0.8(8)		0.85(9)	

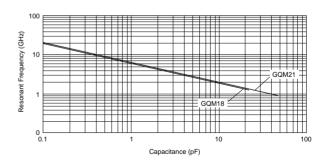
The part numbering code is shown in ().

Dimensions are shown in mm and Rated Voltage in Vdc.

■ Q - Frequency Characteristics



■ Resonant Frequency - Capacitance



No.	lte.	Item Specifications		Test Method				
1	Operating		_55 to 125℃	Reference Temperature: 25°C				
2	Temperature		See the previous page.	(2C, 3C, 4C: 20°C) The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p,p} or V ^{o,p} , whichever is larger, should be maintained within the rated voltage range.				
3	Appearar	Appearance No defects or abnormalities		Visual inspection				
4	Dimensio	n	Within the specified dimensions	Using calipers				
5	Dielectric	ectric Strength No defects or abnormalities		No failure should be observed when 300% of the rated voltage is applied between the terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA.				
6	$\label{eq:more_loss} \mbox{Insulation Resistance} \ \ \mbox{More than } 10,000M\Omega \mbox{ (Whichever is smaller)}$		The insulation resistance should be measured with a DC voltage not exceeding the rated voltage at 25℃ and 75%RH max. and within 2 minutes of charging.					
7	Capacita	nce	Within the specified tolerance	The capacitance/Q should be measured at 25℃ at the				
8	0		30pF min.: Q≥1400 30pF max.: Q≥800+20C	frequency and voltage shown in the table. Frequency 1±0.1MHz				
	Q		O New York Connections of (a F)	Voltage		0.5 to 5Vrms	 S	
			C: Nominal Capacitance (pF)					
9	Capacitance Change Temperature Coefficient Capacitance Temperature Characteristics Capacitance Drift		Within the specified tolerance (Table A)	The temperature coefficient is determined using the capacitanc measured in step 3 as a reference. When cycling the temperature sequentially from step 1 through		·		
			Within the specified tolerance (Table A)	the capacitance should be within the specified tolerance for the				
			Within ±0.2% or ±0.05pF (Whichever is larger)	temperature coefficient and capacitance change as in Table A. The capacitance drift is calculated by dividing the differences between the maximum and minimum measured values in the steps 1, 3 and 5 by the capacitance value in step 3. Step Temperature (°C) 1 Reference Temp. ±2 2 -55±3 3 Reference Temp. ±2 4 125±3 5 Reference Temp. ±2				
10	Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor to the test jig (glass epoxy board) shown in Fig. 1 using a eutectic solder. Then apply 10N* force in parallel with the test jig for 10±1 sec. The soldering should be done either with an iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. *5N (GQM188)				
				Туре	а	b	С	
				GQM18 GQM21	1.0	3.0 4.0	1.2 1.65	
			Solder resist Baked electrode or copper foil	GQIVIZI	Fig.	'	(in mm)	
11	Appearance		No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board) in the				
		Capacitance	Within the specified tolerance	same manner and under the same conditions as (10). The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of				
	Vibration Resistance	Q	30pF min.: Q≥1400 30pF max.: Q≥800+20C C: Nominal Capacitance (pF)					
			C. Terrimai Capacitarios (pr.)	3 mutually perpendicular directions (total of 6 hours).				



sales representatives or product engineers before ordering.

• This PDF catalog has only typical specifications because there is no space for detailed specifications. Therefore, please approve our product specifications or transact the approval sheet for product specifications before ordering.

Specifications and Test Methods

Continued from the preceding page Specifications No Item Test Method Solder the capacitor on the test jig (glass epoxy board) shown No crack or marked defect should occur. in Fig. 2 using a eutectic solder. Then apply a force in the direction shown in Fig. 3. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 50 Pressurizing speed: 1.0mm/sec. Pressurize Deflection 100 t: 1.6mm Flexure : ≤1 Type а h C GQM18 1.0 3.0 1.2 GQM21 4.0 1.65 45 (in mm) Fig. 2 Fig. 3 Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat at Solderability of 75% of the terminations are to be soldered evenly 80 to 120℃ for 10 to 30 seconds. After preheating, immerse in Termination and continuously. eutectic solder solution for 2±0.5 seconds at 230±5℃ or Sn-3.0Ag-0.5Cu solder solution for 2±0.5 seconds at 245±5°C. The measured and observed characteristics should satisfy the specifications in the following table. No marking defects Appearance Within $\pm 2.5\%$ or ± 0.25 pF Capacitance Change (Whichever is larger) Preheat the capacitor at 120 to 150°C for 1 minute. Immerse the Resistance capacitor in a eutectic solder or Sn-3.0Ag-0.5Cu solder solution 30pF min.: Q≥1400 to Soldering 14 at 270±5℃ for 10±0.5 seconds. Let sit at room temperature for 30pF max.: Q≥800+20C Heat 0 24±2 hours. C: Nominal Capacitance (pF) I.R. More than $10,000M\Omega$ Dielectric No failure Strength The measured and observed characteristics should satisfy the specifications in the following table. Fix the capacitor to the supporting jig in the same manner and Appearance No marking defects under the same conditions as (10). Within $\pm 2.5\%$ or ± 0.25 pF Capacitance Perform the five cycles according to the four heat treatments (Whichever is larger) Change listed in the following table. Temperature Let sit for 24±2 hours at room temperature, then measure. 30pF min.: Q≥1400 15 Cycle 30pF max.: Q≥800+20C Step Q Min. Operating Room Max. Operating Room Temp. (℃) C: Nominal Capacitance (pF) Temp. +0/-3 Temp. +3/-0 Temp. Temp. Time (min.) 30±3 30±3 I.R. More than $10,000M\Omega$ 2 to 3 Dielectric No failure Strength The measured and observed characteristics should satisfy the specifications in the following table. No marking defects Appearance Capacitance Within ±5% or ±0.5pF (Whichever is larger) Change Let the capacitor sit at 40±2°C and 90 to 95% humidity for Humidity 30pF min.: Q≥350 500±12 hours. Steady 10pF and over, 30pF and below: Q≧275+5C/2 Remove and let sit for 24±2 hours (temperature compensating State Q 10pF max.: Q≥200+10C type) at room temperature, then measure. C: Nominal Capacitance (pF)

Continued on the following page.



I.R.

Dielectric

Strength

More than $1,000M\Omega$

No failure

Specifications and Test Methods

Continued from the preceding page.

No.	Ite	em	Specifications	Test Method		
			The measured and observed characteristics should satisfy the specifications in the following table.			
		Appearance	No marking defects			
		Capacitance Change	Within ±7.5% or ±0.75pF (Whichever is larger)	Apply the rated voltage at 40±2℃ and 90 to 95% humidity for		
17	Humidity Load	Q	30pF min.: Q≧200 30pF max.: Q≥100+10C/3	500±12 hours. Remove and let sit for 24±2 hours at room temperature then measure. The charge/discharge current is less than 50mA.		
			C: Nominal Capacitance (pF)			
		I.R.	More than $500M\Omega$			
		Dielectric Strength	No failure			
			The measured and observed characteristics should satisfy the specifications in the following table.			
		Appearance	No marking defects			
		Capacitance Change	Within ±3% or ±0.3pF (Whichever is larger)	Apply 200% of the rated voltage for 1000±12 hours at the		
18	High Temperature Load	Q	30pF min.: Q≧350 10pF and over, 30pF and below: Q≧275+5C/2 10pF max.: Q≧200+10C	maximum operating temperature ±3°C. Let sit for 24±2 hours (temperature compensating type) at room temperature, then measure. The charge/discharge current is less than 50mA.		
			C: Nominal Capacitance (pF)			
		I.R.	More than 1,000M Ω			
		Dielectric Strength	No failure			

Table A

(1) Capacitance Change from 25℃ (%) **Nominal Values** Char. -55℃ **−10**°C (ppm/°C) *1 Max. Min. Max. Min. Max. Min. 5C 0±30 0.58 -0.24 0.40 -0.17 0.25 -0.11

 $[\]pm 1$: Nominal values denote the temperature coefficient within a range of 25 to 125°C.

Chip Monolithic Ceramic Capacitors



High Frequency Type ERB Series

■ Features (ERB Series)

- 1. Negligible inductance is achieved by its monolithic structure so the series can be used at frequencies above 1GHz.
- 2. Nickel barriered terminations of ERB series improve solderability and decrease solder leaching.
- 3. ERB18/21 series are designed for both flow and reflow soldering and ERB32 series are designed for reflow soldering.



Part Number		Dimen	sions (mm)		
Part Number	L	W	T max.	e min.	g min.
ERB188	1.6±0.1	0.8±0.1	0.9	0.2	0.5
ERB21B	2.0±0.3	1.25±0.3	1.35	0.25	0.7
ERB32Q	3 2+0 3	2 5+0 3	1.7	0.3	1.0

■ Applications

High frequency and high-power circuits

Part Number	ER	B18		ERE	321				ER	B32		
LxW	1.6	x0.8		2.0x	1.25			3.2x2.5				
TC COG (5C)			C0G (5C)			C0G (5C)						
Rated Volt.	250 (2E)	200 (2D)	250 (2E)	200 (2D)	100 (2A)	50 (1H)	500 (2H)	300 (YD)	250 (2E)	200 (2D)	100 (2A)	50 (1H)
Capacitance (Ca	pacitance	part numb	ering code)	and T (mm)) Dimensio	n (T Dimen	sion part n	umbering c	ode)			
0.50pF(R50)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
0.75pF(R75)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
1.0pF(1R0)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
1.1pF(1R1)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
1.2pF(1R2)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
1.3pF(1R3)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
1.5pF(1R5)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
1.6pF(1R6)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
1.8pF(1R8)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
2.0pF(2R0)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
2.2pF(2R2)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
2.4pF(2R4)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
2.7pF(2R7)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
3.0pF(3R0)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
3.3pF(3R3)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
3.6pF(3R6)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
3.9pF(3R9)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
4.0pF(4R0)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
4.3pF(4R3)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
4.7pF(4R7)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
5.0pF(5R0)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
5.1pF(5R1)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
5.6pF(5R6)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
6.0pF(6R0)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
6.2pF(6R2)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
6.8pF(6R8)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
7.0pF(7R0)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
7.5pF(7R5)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
8.0pF(8R0)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
8.2pF(8R2)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
9.0pF(9R0)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
9.1pF(9R1)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					

1.7(**Q**)

1.7(**Q**)

1.7(**Q**)

Part Number	ER	B18		ER	B21				ER	B32		
L x W	1.6	x0.8		2.0x	1.25				3.2	x2.5		
тс	C) (5	0G iC)		C((5	DG C)				C(5	0G (C)		
Rated Volt.	250 (2E)	200 (2D)	250 (2E)	200 (2D)	100 (2A)	50 (1H)	500 (2H)	300 (YD)	250 (2E)	200 (2D)	100 (2A)	50 (1H)
Capacitance (Ca	pacitance	part numb	ering code)	and T (mm) Dimensio	n (T Dimen	sion part n	umbering o	ode)	,		
10pF(100)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
11pF(110)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
12pF(120)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
13pF(130)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
15pF(150)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
16pF(160)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
18pF(180)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
20pF(200)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
22pF(220)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
24pF(240)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
27pF(270)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
30pF(300)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
33pF(330)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
36pF(360)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
39pF(390)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
43pF(430)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
47pF(470)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
51pF(510)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
56pF(560)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
62pF(620)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
68pF(680)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
75pF(750)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
82pF(820)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
91pF(910)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
100pF(101)	0.9(8)	0.9(8)	1.35(B)	1.35(B)			1.7(Q)					
110pF(111)					1.35(B)		1.7(Q)					
120pF(121)					1.35(B)		1.7(Q)					
130pF(131)					1.35(B)			1.7(Q)				
150pF(151)						1.35(B)		1.7(Q)				
160pF(161)						1.35(B)			1.7(Q)	1.7(Q)		
180pF(181)									1.7(Q)	1.7(Q)		
200pF(201)									1.7(Q)	1.7(Q)		
220pF(221)									1.7(Q)	1.7(Q)		
240pF(241)											1.7(Q)	
270pF(271)											1.7(Q)	
300pF(301)											1.7(Q)	
330pF(331)											1.7(Q)	
360pF(361)											1.7(Q)	
390pF(391)											1.7(Q)	
430pF(431)											1.7(Q)	
470pF(471)											1.7(Q)	
510pF(511)												1.7(0
560pF(561)												1.7(
620pF(621)												1.7(0
680pF(681)												1.7(
750pF(751)												1.7(
000:- 5(004)												

The part numbering code is shown in ().

820pF(**821**)

910pF(**911**)

1000pF(**102**)

Dimensions are shown in mm and Rated Voltage in Vdc.

Note • This PDF catalog is downloaded from the website of Murata Manufacturing co., ltd. Therefore, it's specifications are subject to change or our products in it may be discontinued without advance notice. Please check with our sales representatives or product engineers before ordering.

• This PDF catalog has only typical specifications because there is no space for detailed specifications. Therefore, please approve our product specifications or transact the approval sheet for product specifications before ordering.

Specifications and Test Methods

No.	Ite	em	Specifications		Test Met	hod		
1	Operating Temperati	ure Range	-55 to +125℃	Reference Temperature: 25°C				
2	2 Rated Voltage		See the previous pages.	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{p,p} or V ^{0,p} , whichever is larger, should be maintained within the rated voltage range.				
3	Appearar	nce	No defects or abnormalities	Visual inspection				
4	Dimensio	ns	Within the specified dimension	Using calipers				
5	Dielectric	: Strength	No defects or abnormalities	No failure should be observed when 300%(*) of the rated voltage is applied between the terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA. (*) 300V: 250%, 500V: 200%			5 seconds,	
6	6 Insulation Resistance (I.R.) 1,000,000MΩ min. (C≤470pF) 100,000MΩ min. (C>470pF)		The insulation resist voltage not exceedir humidity and within 2	ng the rated vo	ltage at 25℃ a			
7	Capacita	nce	Within the specified tolerance	The capacitance/Q s	should be mea	sured at 25℃	at the	
8			C≤ 220pF : Q≥10,000 220pF < C≤ 470pF : Q≥ 5,000 470pF < C≤1,000pF : Q≥ 3,000 C: Nominal Capacitance (pF)		frequency and voltage shown in the table. Frequency 1±0.1MHz Voltage 1±0.2Vrms			
		Capacitance Change	Within the specified tolerance (Table A-6)	The temperature coefficient is determined using the capacitance measured in step 3 as a reference. When cycling				
		Temperature Coefficent	Within the specified tolerance (Table A-6)	the temperature sequentially from step 1 through 5, t capacitance should be within the specified tolerance temperature coefficient and capacitance change as 1			nce for the	
9	Capacitance		Within ±0.2% or ±0.05pF (Whichever is larger)	The capacitance drift between the maximut, 3 and 5 by the capacitance drift between the maximut, 3 and 5 by the capacitance drift between the maximut, 3 and 5 by the capacitance drift between the maximum and 5 by the capacitance drift between the maximum and 5 by the capacitance drift between the capacitance drift between the capacitance drift between the capacitance drift between the maximum and 5 by the capacitance drift between the maximum and 5 by the capacitance drift between the maximum and 5 by the capacitance drift between the maximum and 5 by the capacitance drift between the maximum and 5 by the capacitance drift between the maximum and 5 by the capacitance drift between the maximum and 5 by the capacitance drift between the capacitance	t is calculated um and minimu pacitance valu	by dividing the im measured	e differences values in steps	
			No removal of the terminations or other defects should occur.	Solder the capacitor	on the test jig	(glass epoxy	board) shown	
10	Adhesive Strength of Termination		thesive Strength		in Fig. 1 using an eutectic solder. Then apply 10N* force in parallel with the test jig for 10±1se. The soldering should be done either with an iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Type a b c ERB18 1.0 3.0 1.2 ERB21 1.2 4.0 1.65 ERB32 2.2 5.0 2.9 (in mm) *5N (ERB188			



Resistance to Soldering Heat

Temperature Cycle

Humidity

Specifications and Test Methods

Continued from the preceding page.

	3 m m m m m m m m m m m m m m m m m m m						
No.	Ite	em	Specifications	Test Method			
		Appearance	No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board) in the			
		Capacitance	Within the specified tolerance	same manner and under the same conditions as (10).			
11	Vibration Resistance	Q	Satisfies the initial value. C≤ 220pF : Q≥10,000 220pF <c≤ (pf)<="" 3,000="" 470pf="" 470pf<c≤1,000pf="" 5,000="" :="" c:="" capacitance="" nominal="" q≥="" td=""><td>The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of 3 mutually perpendicular directions (total of 6 hours).</td></c≤>	The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of 3 mutually perpendicular directions (total of 6 hours).			
			No crack or marked defect should occur.	Solder the capacitor on the test jig (glass epoxy board) shown in Fig. 2a using an eutectic solder. Then apply a force in the			
12	Deflection		20 50 Pressurizing speed: 1.0mm/sec. Pressurize	direction shown in Fig. 3a. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.			
			Flexure : ≤1	Type a b c			
				ERB18 1.0 3.0 1.2			
			Capacitance meter	ERB21 1.2 4.0 1.65			
			+ 45 + 45 + 1:1.6mm Fig.3a Fig. 2a	ERB32 2.2 5.0 2.9 (in mm)			
13	Solderability of Termination 95% of the terminations are to be soldered evenly and continuously.		,	Immerse the capacitor in a solution of isopropyl alcohol and rosin (25% rosin in weight proportion). Preheat at 80 to 120°C for 10 to 30 seconds. After preheating, immerse in an eutectic solder or Sn-3.0Ag-0.5Cu solder solution for 5±0.5 seconds			

The measured and observed characteristics should satisfy the specifications in the following table.

	Item	Specifications				
	Appearance	No marked defect				
	Capacitance	Within ±2.5% or ±0.25pF				
t	Change	(Whichever is larger)				
		C≦ 220pF : Q≥10,000				
	Q	220pF <c≦ 470pf="" 5,000<="" :="" q≥="" td=""></c≦>				
		470pF <c≦1,000pf 3,000<="" :="" q≥="" td=""></c≦1,000pf>				
	Dielectric Strength	No failure				
		O. N				

C: Nominal Capacitance (pF)

at 245±5℃.

The measured			ristics shoul	d satisfy the	
specifications i	n the follow	ing table.			

Specifications
No marked defect
Within ±5% or ±0.5pF
(Whichever is larger)
C≧30pF : Q≧350
10pF≦C<30pF : Q≥275+ 5 C
C<10pF : Q≥200+10C
1,000MΩ min.
No failure

C: Nominal Capacitance (pF)

Preheat according to the conditions listed in the table below. Immerse the capacitor in an eutectic solder or Sn-3.0Ag-0.5Cu solder solution at 270±5°C for 10±0.5 seconds. Let sit at room temperature for 24±2 hours.

	Chip Size	Preheat Condition
2	2.0×1.25mm max.	1minute at 120 to 150°C
3	3.2×2.5mm	Each 1 minute at 100 to 120℃ and then 170 to 200℃

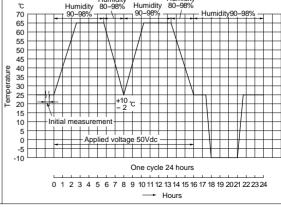
Fix the capacitor to the supporting jig in the same manner and under the same conditions as (10). Perform the five cycles according to the four heat treatments listed in the following table. Let sit for 24±2 hours at room temperature, then measure.

Step	1	2	3	4
Temp. (℃)	Min. Operating Temp. +0/-3	Room Temp.	Max. Operating Temp. +3/-0	Room Temp.
Time (min.)	30±3	5 max.	30±3	5 max.

The measured and observed characteristics should satisfy the

pecifications in the following table.			
Item	Specifications		
Appearance	No marked defect		
Capacitance	Within ±5% or ±0.5pF		
Change	(Whichever is larger)		
	C≧30pF : Q≧350		
Q	10pF≦C<30pF : Q≥275+ 5 C		
	C<10pF : Q≥200+10C		
I.R.	1,000MΩ min.		
	C: Nominal Capacitance (pF		

Apply the 24-hour heat (-10 to +65°C) and humidity (80 to 100%) treatment shown below, 10 consecutive times. Remove, let sit for 24±2 hours at room temperature, and measure.







Specifications and Test Methods

Continued from the preceding page.

No.	Item	5	pecifications	Test Method				
		The measured and observed characteristics should satisfy the specifications in the following table.						
17	High Temperature Load	Appearance Capacitance Change	Specifications No marked defect Within ±3% or ±0.3pF (Whichever is larger) C≥30pF : Q≥350 10pF≤C<30pF : Q≥275+ ½ C	Apply 200% (500V only 150%) of the rated voltage for 1,000±12 hours at 125±3°C. Remove and let sit for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA.				
		I.R. Dielectric Strength	C<10pF : Q≥200+10C 1,000MΩ min. No failure C: Nominal Capacitance (pF)					

Table A-6

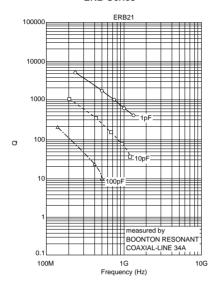
	Nominal Values (ppm/°C) Note 1	Capacitance Change from 25℃ (%)					
Char.		- 55		-30		-10	
		Max.	Min.	Max.	Min.	Max.	Min.
5C	0±30	0.58	-0.24	0.40	-0.17	0.25	-0.11

Note 1: Nominal values denote the temperature coefficient within a range of 25 to 125℃ (for 5C)

ERB Series Data

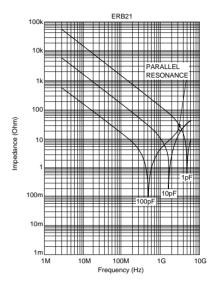
■ Q - Frequency Characteristics

ERB Series



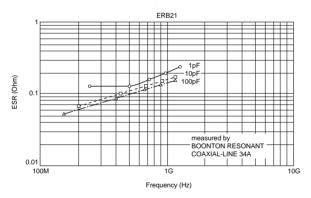
■ Impedance - Frequency Characteristics

ERB Series



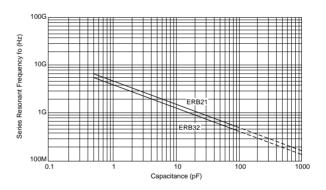
■ ESR - Frequency Characteristics

ERB Series

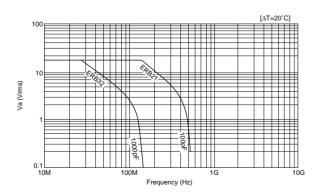


■ Resonant Frequency - Capacitance

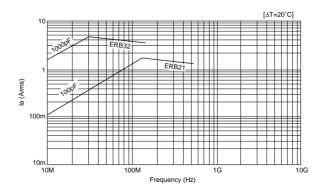
ERB Series



■ Allowable Voltage - Frequency



■ Allowable Current - Frequency



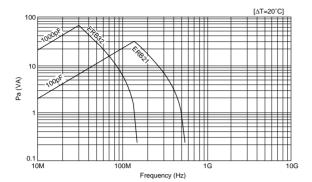




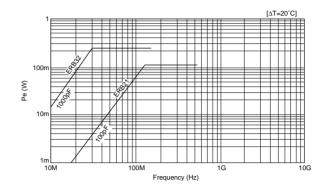
ERB Series Data

Continued from the preceding page.

■ Allowable Apparent Power - Frequency



■ Allowable Effective Power - Frequency





Package

■ Minimum Quantity Guide

-		Dim	ensions	(mm)		5 .		ty (pcs.)		
Part Nur	mber				m Reel		nm Reel	Bulk Case	Bulk Bac	
		L	W	Т	Paper Tape	Embossed Tape	Paper Tape	Embossed Tape	Duik Gusc	
Packagino	g Code				D	L	J	К	С	Bulk : B Tray : T
	GRM02	0.4	0.2	0.2	20,000	-	-	-	-	1,000
	GRM03	0.6	0.3	0.3	15,000	-	50,000	-	-	1,000
	GRM15	1.0	0.5	0.25	10,000	-	50,000	-	-	1,000
	GRIVITS	1.0	0.5	0.5	10,000	-	50,000	-	50,000	1,000
	GRM18	1.6	0.8	8.0	4,000	-	10,000	-	15,000 1)	1,000
				0.6	4,000	-	10,000	-	10,000	1,000
	GRM21	2.0	1.25	0.85/1.0	4,000	-	10,000	-	-	1,000
				1.25	-	3,000	-	10,000	5,000 2)	1,000
				0.6/0.85	4,000	-	10,000	-	-	1,000
	GRM31	3.2	1.6	1.15	-	3,000	-	10,000	-	1,000
				1.6	-	2,000	-	6,000	-	1,000
For General				0.85	-	4,000	-	10,000	-	1,000
Purpose				1.15	-	3,000	-	10,000	-	1,000
	GRM32	3.2	2.5	1.35	-	2,000	-	8,000	-	1,000
				1.6	-	2,000	-	6,000	-	1,000
				1.8/2.0 2.5	-	1,000	-	4,000	-	1,000
			3.2	1.15	-	1,000	-	5,000	-	1,000
	001140	4.5		1.35/1.6 1.8/2.0	-	1,000	-	4,000	-	1,000
	GRM43			2.5	-	500	-	2,000	-	1,000
				2.8	-	500	-	1,500	-	500
	GRM55			1.15	-	1,000	-	5,000	-	1,000
		5.7 5.0		1.35/1.6 1.8/2.0	-	1,000	-	4,000	-	1,000
			5.0	2.5	-	500	-	2,000	-	500
				3.2	-	300	-	1,500	-	500
	GJM03	0.6	0.3	0.3	15,000	-	50,000	-	-	1,000
High Power Type	GJM15	1.0	0.5	0.5	10,000	-	50,000	-	50,000	1,000
	GQM18	1.6	0.8	0.8	4,000	-	10,000	-	-	1,000
	GQM21	2.0	1.25	0.85	4,000	-	10,000	-	-	1,000
ligh Frequency	ERB18	1.6	0.8	0.9 max.	4,000	-	10,000	-	-	1,000
	ERB21	2.0	1.25	1.35 max.	-	3,000	-	10,000	-	1,000
	ERB32	3.2	2.5	1.7 max.	-	2,000	-	8,000	-	1,000
For Ultrasonic	GRM21	2.0	1.25	0.85	4,000	-	10,000	-	-	1,000
	GMA05	0.5	0.5	0.35	-	-	-	-	-	400 ³⁾
Microchip	GMA08	0.8	0.8	0.5	-	-	-	-	-	400 ³⁾
	GNM1M	1.37	1.0	0.6	4,000	-	10,000	-	-	1,000
	GNM21	2.0	1.25	0.6/0.85	4,000	_	10,000	-	-	1,000
Array				0.8	4,000	-	10,000	-	-	1,000
	GNM31	3.2	1.6	1.0	-	3,000	-	10,000	-	1,000
	LLL15	0.5	1.0	0.3	10,000	-	50,000	-	-	1,000
	LLL18	0.8	1.6	0.5	-	4,000	-	10,000	-	1,000
				0.5/0.6	-	4,000	-	10,000	-	1,000
	LLL21	1.25	.25 2.0	0.85	-	3,000	-	10,000	-	1,000
	11124			0.5/0.7	-	4,000	-	10,000	-	1,000
	LLL31	1.6	3.2	1.15	-	3,000		10,000		1,000
	LLA18	1.6	0.8	0.5	-	4,000	-	10,000	-	1,000
				0.5	-	4,000	-	10,000		1,000
Low ESL	LLA21	2.0	1.25	0.85	-	3,000	-	10,000	-	1,000
				0.5	-	4,000	-	10,000	-	1,000
	LLA31	3.2	1.6	0.85	-	3,000	-	10,000	<u> </u>	1,000
		0.2		1.15	-	3,000	-	10,000	-	1,000
				0.5	-	4,000	-	10,000	-	1,000
	LLM21	2.0	1.25	0.85	<u> </u>	-	<u> </u>	10,000	<u> </u>	1,000
		23	0.65	<u>-</u>	3,000 4,000	<u> </u>	10,000	<u> </u>	1,000	
			1							

¹⁾ $68{,}000pF/0.1\mu F$ of 50V R7 rated are not available by bulk case.





²⁾ Dimension tolerance $\pm 0.15 \text{mm}$ rated are not available by bulk case.

³⁾ Tray

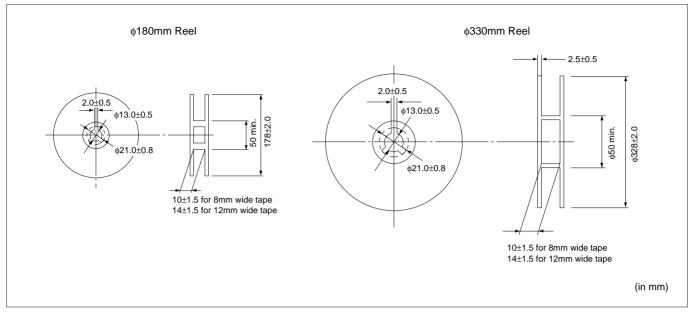
Package



Continued from the preceding page.

■ Tape Carrier Packaging

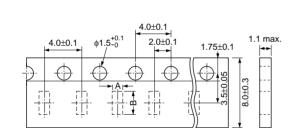
(1) Dimensions of Reel



(2) Dimensions of Paper Tape

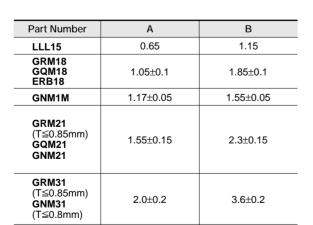
GRM32

(T≦0.85mm)



8mm width 4mm pitch Tape

Direction of Feed



2.8±0.2

3.6±0.2

8mm width 2mm pitch Tape
2.0±0.05
Direction of Feed

Part Number	A*	B*
GRM02	0.25	0.45
GJM03 GRM03	0.37	0.67
GJM15 GRM15	0.65	1.15

*Nominal Value

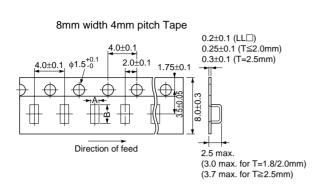
(in mm)



Package

Continued from the preceding page.

(3) Dimensions of Embossed Tape



Part Number	А	В
LLL18, LLA18	1.05±0.1	1.85±0.1
GRM21, ERB21 (T≥1.0mm) LLL21 LLA21, LLM21	1.45±0.2	2.25±0.2
GRM31 (T≥1.15mm) LLL31 LLA31, LLM31 GNM31 (T≥1.0mm)	1.9±0.2	3.5±0.2
GRM32, ERB32 (T≧1.0mm)	2.8±0.2	3.5±0.2

*Nominal Value

12mm width 8mm pitch Tape φ1.5^{+0.1} 2.0±0.1 . 1.75+0.1 4.0+0.1 5±0. Direction of feed 2.5 max for GRM43/55 (3.7 max. for T=2.5mm) (4.7 max. for T≥3.0mm)

Part Number	A*	B*
GRM43	3.6	4.9
GRM55	5.2	6.1

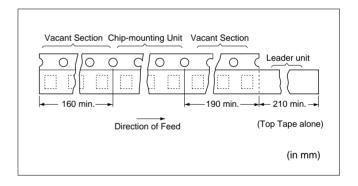
*Nominal Value

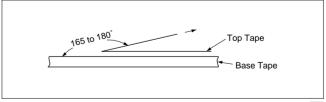
(in mm)

(4) Taping Method

- ① Tapes for capacitors are wound clockwise. The sprocket holes are to the right as the tape is pulled toward the user.
- 2 Part of the leader and part of the empty tape should be attached to the end of the tape as follows.
- 3 The top tape and base tape are not attached at the end of the tape for a minimum of 5 pitches.
- 4 Missing capacitors number within 0.1% of the number per reel or 1 pc, whichever is greater, and are not continuous.
- 5 The top tape and bottom tape should not protrude beyond the edges of the tape and should not cover sprocket holes.
- 6 Cumulative tolerance of sprocket holes, 10 pitches: ±0.3mm.
- 7 Peeling off force: 0.1 to 0.6N* in the direction shown below.

GRM03 : 0.05 to 0.5N







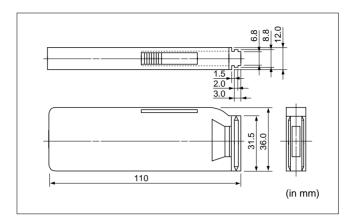


Package



Continued from the preceding page.

■ Dimensions of Bulk Case Packaging The bulk case uses antistatic materials. Please contact Murata for details.





⚠Caution

■ Storage and Operating Conditions

Chip monolithic ceramic capacitors (chips) can experience degradation of termination solderability when subjected to high temperature or humidity, or if exposed to sulfur or chlorine gases.

Storage environment must be at an ambient temperature of 5-40 degree C and an ambient humidity of 20-70%RH. Use chip within 6 months. If 6 months or more have elapsed, check solderability before use.

FAILURE TO FOLLOW THE ABOVE CAUTIONS MAY

Please contact Murata factory for the use of Sn-Zn

Use of Sn-Zn based solder will deteriorate

FAILURE TO FOLLOW THE ABOVE CAUTIONS MAY RESULT, WORST CASE, IN A SHORT CIRCUIT AND CAUSE FUMING OR PARTIAL DISPERSION WHEN THE PRODUCT IS USED.

■ Handling

1. Inspection

Thrusting force of the test probe can flex the PCB, resulting in cracked chips or open solder joints. Provide support pins on the back side of the PCB to prevent warping or flexing.

- 2. Board Separation (or depanalization)
- (1) Board flexing at the time of separation causes cracked chips or broken solder.
- (2) Severity of stresses imposed on the chip at the time of board break is in the order of: Pushback<Slitter<V Slot<Perforator.</p>
- (3) Board separation must be performed using special jigs, not with hands.

3. Reel and bulk case

reliability of MLCC.

based solder in advance.

In the handling of reel and case, please be careful and do not drop it.

Do not use chips from a case which has been dropped.

FAILURE TO FOLLOW THE ABOVE CAUTIONS MAY RESULT, WORST CASE, IN A SHORT CIRCUIT AND FUMING WHEN THE PRODUCT IS USED.



⚠Caution

■ ①Caution (Soldering and Mounting)

1. Mounting Position

Choose a mounting position that minimizes the stress imposed on the chip during flexing or bending of the board.

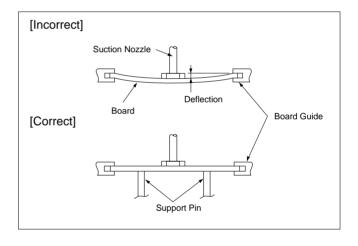
[Component Direction] Locate chip horizontal to the direction in which stress [Chip Mounting Close to Board Separation Point] Chip arrangement Perforation В Worst A-C-(B₂D) Best Α Slit

(Reference Data 2. Board bending strength for solder fillet height) (Reference Data 3. Temperature cycling for solder fillet height) (Reference Data 4. Board bending strength for board material)

2. Chip Placing

- An excessively low bottom dead point of the suction nozzle imposes great force on the chip during mounting, causing cracked chips. So adjust the suction nozzle's bottom dead point by correcting warp in the board. Normally, the suction nozzle's bottom dead point must be set on the upper surface of the board. Nozzle pressure for chip mounting must be a 1 to 3N static load.
- Dirt particles and dust accumulated between the suction nozzle and the cylinder inner wall prevent the nozzle from moving smoothly. This imposes great force on the chip during mounting, causing cracked chips. And the locating claw, when worn out, imposes uneven forces on the chip when positioning, causing cracked chips. The suction nozzle and the locating claw must be maintained, checked and replaced periodically.

(Reference Data 5. Break strength)





⚠Caution

Continued from the preceding page.

3. Reflow Soldering

- When sudden heat is applied to the components, the mechanical strength of the components should go down because remarkable temperature change causes deformity inside components. In order to prevent mechanical damage in the components, preheating should be required for both of the components and the PCB board. Preheating conditions are shown in table 1. It is required to keep temperature differential between the soldering and the components surface (ΔT) as small as possible.
- Solderability of Tin plating termination chip might be deteriorated when low temperature soldering profile where peak solder temperature is below the Tin melting point is used. Please confirm the solderability of Tin plating termination chip before use.
- When components are immersed in solvent after mounting, be sure to maintain the temperature difference (ΔT) between the component and solvent within the range shown in the table 1.

Table 1

Part Number	Temperature Differential
GRM02/03/15/18/21/31	
GJM03/15	
LLL15/18/21/31	ΔT≦190°C
ERB18/21	
GQM18/21	
GRM32/43/55	
LLA18/21/31	
LLM21/31	ΔΤ≦130℃
GNM	
ERB32	

Recommended Conditions

	Pb-Sn S	Lead Free Solder	
	Infrared Reflow	Vapor Reflow	Lead Free Solder
Peak Temperature	230-250°C	230-240°C	240-260°C
Atmosphere	Air	Air	Air or N2

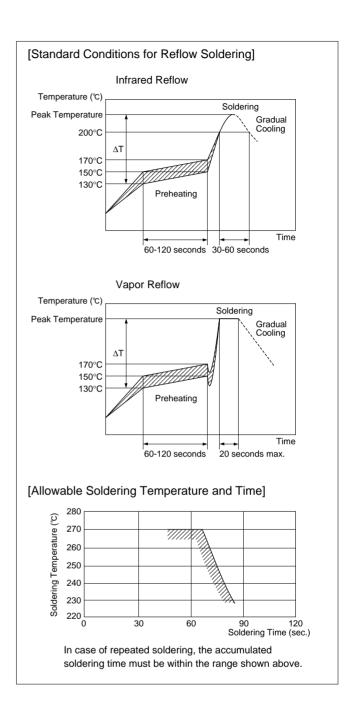
Pb-Sn Solder: Sn-37Pb Lead Free Solder: Sn-3.0Ag-0.5Cu

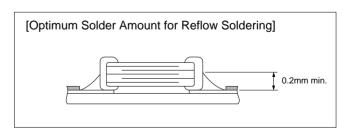
Optimum Solder Amount for Reflow Soldering

- Overly thick application of solder paste results in excessive fillet height solder.
 - This makes the chip more susceptible to mechanical and thermal stress on the board and may cause cracked chips.
- Too little solder paste results in a lack of adhesive strength on the outer electrode, which may result in chips breaking loose from the PCB.
- Make sure the solder has been applied smoothly to the end surface to a height of 0.2mm min.

Inverting the PCB

Make sure not to impose an abnormal mechanical shock on the PCB.





Continued from the preceding page

4. Leaded Component Insertion

If the PCB is flexed when leaded components (such as transformers and ICs) are being mounted, chips may crack and solder joints may break.

Before mounting leaded components, support the PCB using backup pins or special jigs to prevent warping.

5. Flow Soldering

- When sudden heat is applied to the components, the mechanical strength of the components should go down because remarkable temperature change causes deformity inside components. And an excessively long soldering time or high soldering temperature results in leaching of the outer electrodes, causing poor adhesion or a reduction in capacitance value due to loss of contact between electrodes and end termination.
- In order to prevent mechanical damage in the components, preheating shoud be required for the both components and the PCB board. Preheating conditions are shown in table 2. It is required to keep temperature differential between the soldering and the components surface (ΔT) as small as possible.

When components are immersed in solvent after mounting, be sure to maintain the temperature difference between the component and solvent within the range shown in Table 2.

Do not apply flow soldering to chips not listed in Table 2.

Table 2

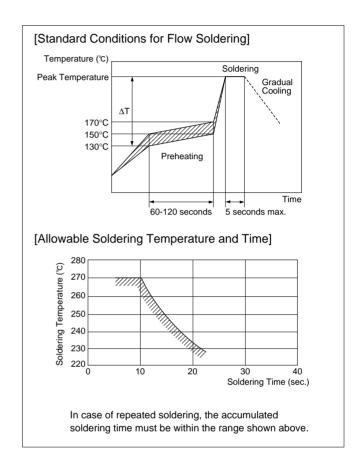
Part Number	Temperature Differential	
GRM18/21/31	1T < 450°0	
LLL21/31		
ERB18/21	ΔΤ≦150℃	
GQM18/21		

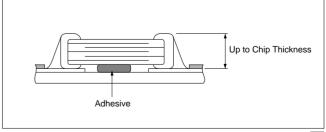
Recommended Conditions

	Pb-Sn Solder	Lead Free Solder
Peak Temperature	240-250°C	250-260°C
Atmosphere	Air	N ₂

Pb-Sn Solder: Sn-37Pb Lead Free Solder: Sn-3.0Ag-0.5Cu

 Optimum Solder Amount for Flow Soldering The top of the solder fillet should be lower than the thickness of components. If the solder amount is excessively big, the risk of cracking is higher during board bending or under any other stressful conditions.







⚠Caution

Continued from the preceding page.

6. Correction with a Soldering Iron

(1) For Chip Type Capacitors

 When sudden heat is applied to the components by soldering iron, the mechanical strength of the components should go down because remarkable temperature change causes deformity inside components. In order to prevent mechanical damage in the components, preheating should be required for both of the components and the PCB board. Preheating conditions are shown in table 3. It is required to keep temperature differential between the soldering and the components surface (ΔT) as small as possible. After soldering, it is not allowed to cool it down rapidly.

 Optimum Solder Amount when Corrections Are Made Using a Soldering Iron

The top of the solder fillet should be lower than the thickness of components. If the solder amount is excessively big, the risk of cracking is higher during board bending or under any other stressful conditions. Soldering iron ø3mm or smaller should be required. And it is necessary to keep a distance between the soldering iron and the components without direct touch. Thread solder with Ø0.5mm or smaller is required for soldering.

7. Washing

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Excessive output of ultrasonic oscillation during cleaning causes PCBs to resonate, resulting in cracked chips or broken solder. Take note not to vibrate PCBs.

FAILURE TO FOLLOW THE ABOVE CAUTIONS MAY RESULT, WORST CASE, IN A SHORT CIRCUIT AND FUMING WHEN THE PRODUCT IS USED.

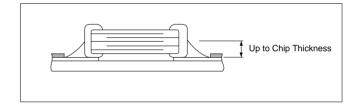
Table 3

Part Number	Temperature Differential	Peak Temperature	Atmosphere
GRM15/18/21/31 GJM15 LLL15/18/21/31 GQM18/21 ERB18/21	ΔΤ≦190℃	300°C max. 3 seconds max. / termination	Air
GRM32/43/55 GNM LLA18/21/31 LLM21/31 ERB32	ΔΤ≦130℃	270°C max. 3 seconds max. / termination	Air

*Applicable for both Pb-Sn and Lead Free Solder.

Pb-Sn Solder: Sn-37Pb

Lead Free Solder: Sn-3.0Ag-0.5Cu



■ Rating

Die Bonding/Wire Bonding (GMA Series)

- 1. Die Bonding of Capacitors
- •Use the following materials Brazing alloy: Au-Sn (80/20) 300 to 320 degree C in N2 atmosphere
- (1) Control the temperature of the substrate so that it matches the temperature of the brazing
- (2) Place brazing alloy on substrate and place the capacitor on the alloy. Hold the capacitor and gently apply the load. Be sure to complete the operation in 1 minute.

- 2. Wire Bonding
- •Wire

Gold wire:

20 micro m (0.0008 inch), 25 micro m (0.001 inch) diameter

- Bonding
- (1) Thermocompression, ultrasonic ball bonding.
- (2) Required stage temperature: 200 to 250 degree C
- (3) Required wedge or capillary weight: 0.5N to 2N.
- (4) Bond the capacitor and base substrate or other devices with gold wire.



■ Notice (Soldering and Mounting)

1. PCB Design

(1) Notice for Pattern Forms

Unlike leaded components, chip components are susceptible to flexing stresses since they are mounted directly on the substrate.

They are also more sensitive to mechanical and thermal stresses than leaded components.

Excess solder fillet height can multiply these stresses and cause chip cracking. When designing substrates, take land patterns and dimensions into consideration to eliminate the possibility of excess solder fillet height.

Pattern Forms

	Placing Close to Chassis	Placing of Chip Components and Leaded Components	Placing of Leaded Components after Chip Component	Lateral Mounting
Prohibited	Chassis Solder (ground) Electrode Pattern	Lead Wire	Soldering Iron Lead Wire	
Correct	Solder Resist	Solder Resist	Solder Resist	Solder Resist





Continued from the preceding page.

(2) Land Dimensions

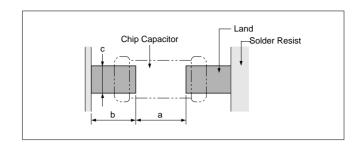


Table 1 Flow Soldering Method

Dimensions Part Number	Dimensions (LXW)	a	b	С	
GRM18 GQM18	1.6×0.8	0.6-1.0	0.8-0.9	0.6-0.8 0.8-1.1 1.0-1.4	
GRM21 GQM21	2.0×1.25	1.0-1.2	0.9-1.0		
GRM31	3.2×1.6	2.2-2.6	1.0-1.1		
LLL21	1.25×2.0	0.4-0.7	0.5-0.7	1.4-1.8	
LLL31	1.6×3.2	0.6-1.0	0.8-0.9	2.6-2.8	
ERB18	1.6×0.8	0.6-1.0	0.8-0.9	0.6-0.8	
ERB21	2.0×1.25	1.0-1.2	0.9-1.0	0.8-1.1	

(in mm)

Table 2 Reflow Soldering Method

Dimensions Part Number	Dimensions (LXW)	a	b	С	
GRM02	0.4×0.2	0.16-0.2	0.12-0.18	0.2-0.23	
GRM03 GJM03	0.6×0.3	0.2-0.3	0.2-0.35	0.2-0.4	
GRM15 GJM15	1.0×0.5	0.3-0.5	0.35-0.45	0.4-0.6	
GRM18 GQM18	1.6×0.8	0.6-0.8	0.6-0.7	0.6-0.8	
GRM21 GQM21	2.0×1.25	1.0-1.2	0.6-0.7	0.8-1.1	
GRM31	3.2×1.6	2.2-2.4	0.8-0.9	1.0-1.4	
GRM32	3.2×2.5	2.0-2.4	1.0-1.2	1.8-2.3	
GRM43	4.5×3.2	3.0-3.5	1.2-1.4	2.3-3.0	
GRM55	5.7×5.0	4.0-4.6	1.4-1.6	3.5-4.8	
LLL15	0.5×1.0	0.15-0.2	0.2-0.3	0.7-1.0	
LLL18	0.8×1.6	0.2-0.4	0.3-0.4	1.0-1.4	
LLL21	1.25×2.0	0.4-0.6	0.3-0.5	1.4-1.8	
LLL31	1.6×3.2	0.6-0.8	0.6-0.7	2.6-2.8	
ERB18	1.6×0.8	0.6-0.8	0.6-0.7	0.6-0.8	
ERB21	2.0×1.25	1.0-1.2	0.6-0.7	0.8-1.1	
ERB32	3.2×2.5	2.0-2.4	1.0-1.2	1.8-2.3	

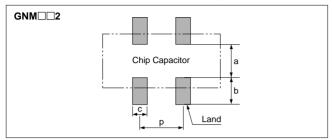
(in mm)





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GNM, LLA Series for Reflow Soldering Method



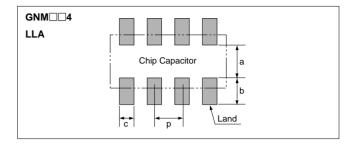


Table 3 GNM, LLA Series for Reflow Soldering Land Dimensions

Part Number	Dimensions (mm)							
rait Nullibei	L	W	a	b	С	р		
GNM1M2	1.37	1.0	0.4 to 0.5	0.35 to 0.45	0.3 to 0.35	0.64		
GNM212	2.0	1.25	0.6 to 0.7	0.5 to 0.7	0.4 to 0.5	1.0		
GNM214	2.0	1.25	0.6 to 0.7	0.5 to 0.7	0.25 to 0.35	0.5		
GNM314	3.2	1.6	0.8 to 1.0	0.7 to 0.9	0.3 to 0.4	0.8		
LLA18	1.6	0.8	0.3 to 0.4	0.25 to 0.4	0.2 to 0.28	0.4		
LLA21	2.0	1.25	0.7 to 0.8	0.4 to 0.6	0.2 to 0.3	0.5		
LLA31	3.2	1.6	0.8 to 1.0	0.7 to 0.9	0.3 to 0.4	0.8		

LLM Series for Reflow Soldering Method

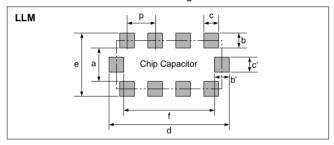


Table 4 LLM Series for Reflow Soldering Land Dimensions

Part Number	Dimensions (mm)						
	а	b, b'	c, c'	d	е	f	р
LLM21	0.6 to 0.8	(0.3 to 0.5)	0.3	2.0 to 2.6	1.3 to 1.8	1.4 to 1.6	0.5
LLM31	1.0	(0.3 to 0.5)	0.4	3.2 to 3.6	1.6 to 2.0	2.6	0.8

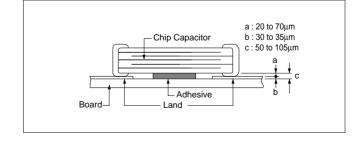
b=(c-e)/2, b'=(d-f)/2

2. Adhesive Application

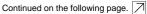
- Thin or insufficient adhesive causes chips to loosen or become disconnected when flow soldered. The amount of adhesive must be more than dimension c shown in the drawing at right to obtain enough bonding strength. The chip's electrode thickness and land thickness must be taken into consideration.
- Low viscosity adhesive causes chips to slip after mounting. Adhesive must have a viscosity of 5000Pa ·s (500ps) min. (at 25°C)

Adhesive Coverage*

Part Number	Adhesive Coverage*			
GRM18, GQM18	0.05mg min.			
GRM21, LLL21, GQM21	0.1mg min.			
GRM31, LLL31	0.15mg min.			



*Nominal Value







Notice

Continued from the preceding page.

3. Adhesive Curing

Insufficient curing of the adhesive causes chips to disconnect during flow soldering and causes deteriorated insulation resistance between outer electrodes due to moisture absorption.

Control curing temperature and time in order to prevent insufficient hardening.

Inverting the PCB

Make sure not to impose an abnormal mechanical shock on the PCB.

4. Flux Application

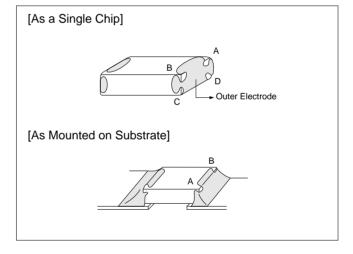
- An excessive amount of flux generates a large quantity of flux gas, causing deteriorated solderability. So apply flux thinly and evenly throughout. (A foaming system is generally used for flow soldering).
- Flux containing too high a percentage of halide may cause corrosion of the outer electrodes unless sufficiently

cleaned. Use flux with a halide content of 0.2wt% max. But do not use strong acidic flux.

Wash thoroughly because water soluble flux causes deteriorated insulation resistance between outer electrodes unless sufficiently cleaned.

5. Flow Soldering

 Set temperature and time to ensure that leaching of the outer electrode does not exceed 25% of the chip end area as a single chip (full length of the edge A-B-C-D shown below) and 25% of the length A-B shown below as mounted on substrate.



(Reference Data 6. Thermal shock) (Reference Data 7. Solder heat resistance)

■ Others

1. Resin Coating

When selecting resin materials, select those with low contraction.

2. Circuit Design

These capacitors in this catalog are not safety recognized products

3. Remarks

The above notices are for standard applications and conditions. Contact us when the products are used in special mounting conditions. Select optimum conditions for operation as they determine the reliability of the product after assembly. The data herein are given in typical values, not guaranteed ratings.



Reference Data

1. Solderability

(1) Test Method

Subject the chip capacitor to the following conditions. Then apply flux (an ethanol solution of 25% rosin) to the chip and dip it in 230℃ eutectic solder for 2 seconds. Conditions:

Expose prepared at room temperature (for 6 months and 12 months, respectively)

Prepared at high temperature (for 100 hours at 85°C) Prepared left at high humidity (for 100 hours under 90%RH to 95%RH at 40℃)

(2) Test Samples

GRM21: Products for flow/reflow soldering.

(3) Acceptance Criteria

With a 60-power optical microscope, measure the surface area of the outer electrode that is covered with solder.

(4) Results

Refer to Table 1.

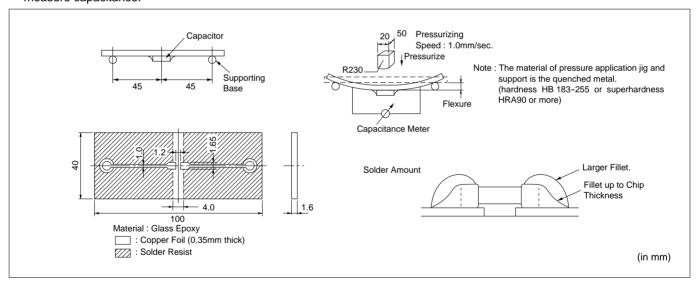
Table 1

Sample	Initial State	Prepared at Room Temperature		Prepared at High Temperature for	Prepared at High Humidity for 100 Hours at 90 to	
	Illitial State	6 months	12 months	100 Hours at 85℃	95% RH and 40°C	
GRM21 for flow/reflow soldering	95 to 100%	95 to 100%	95%	90 to 95%	95%	

2. Board Bending Strength for Solder Fillet Height

(1) Test Method

Solder the chip capacitor to the test PCB with the amount of solder paste necessary to achieve the fillet heights. Then bend the PCB using the method illustrated and measure capacitance.



(2) Test Samples

GRM21: 5C/R7/F5 Characteristics T=0.6mm

(3) Acceptance Criteria

Products should be determined to be defective if the change in capacitance has exceeded the values specified in Table 2.

Table 2

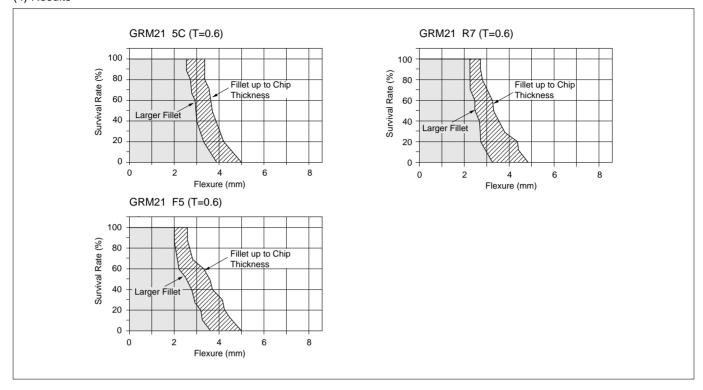
Characteristics	Change in Capacitance
5C	Within ±5% or ±0.5pF, whichever is greater
R7	Within ±12.5%
F5	Within ±20%



Reference Data

Continued from the preceding page.

(4) Results



3. Temperature Cycling for Solder Fillet Height

(1) Test Method

Solder the chips to the substrate of various test fixtures using sufficient amounts of solder to achieve the required fillet height. Then subject the fixtures to the cycle illustrated below 200 times.

(1) Solder Amount

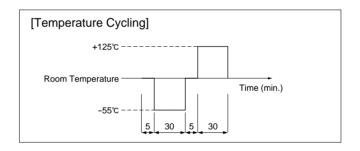
Alumina substrates are typically designed for reflow soldering.

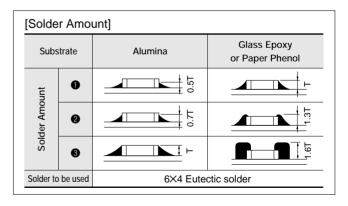
Glass epoxy or paper phenol substrates are typically used for flow soldering.

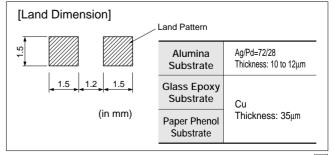
② Material

Alumina (Thickness: 0.64mm) Glass epoxy (Thickness: 1.64mm) Paper phenol (Thickness: 1.64mm)

(3) Land Dimension







Reference Data

Continued from the preceding page.

(2) Test Samples

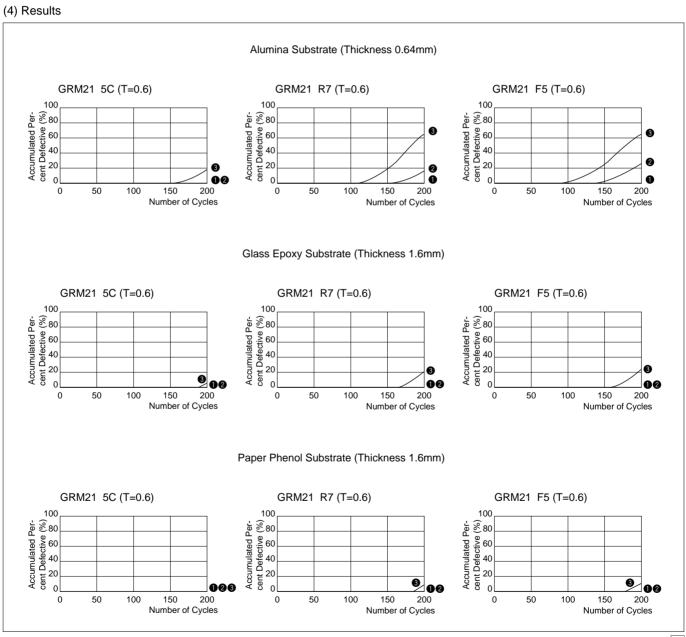
GRM21 5C/R7/F5 Characteristics T=0.6mm

(3) Acceptance Criteria

Products are determined to be defective if the change in capacitance has exceeded the values specified in Table 3.

Table 3

Characteristics Change in Capacitance				
5C	Within ±2.5% or ±0.25pF, whichever is greater			
R7	Within ±7.5%			
F5	Within ±20%			





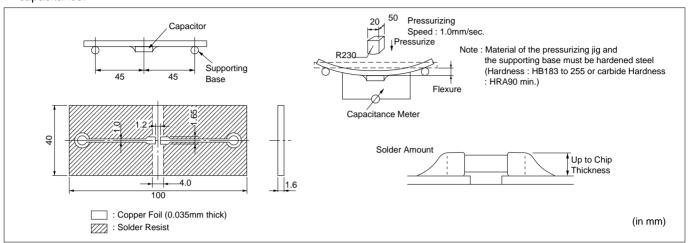
Reference Data

Continued from the preceding page.

4. Board Bending Strength for Board Material

(1) Test Method

Solder the chip to the test board. Then bend the board using the method illustrated below, to measure capacitance.



(2) Test Samples

GRM21 5C/R7/F5 Characteristics T=0.6mm typical

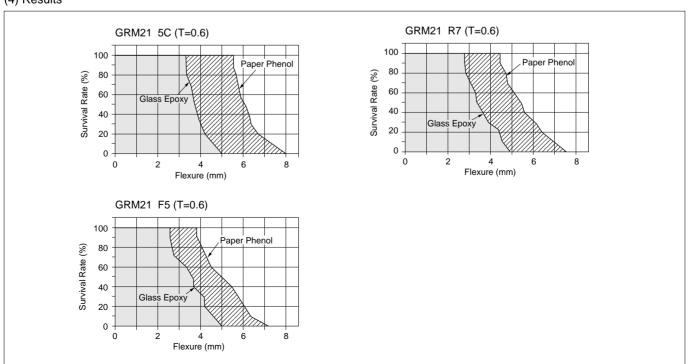
(3) Acceptance Criteria

Products should be determined to be defective if the change in capacitance has exceeded the values specified in Table 4.

Table 4

Characteristics	Change in Capacitance
5C	Within ±5% or ±0.5pF, whichever is greater
R7	Within ±12.5%
F5	Within ±20%

(4) Results



Reference Data

Continued from the preceding page.

5. Break Strength

(1) Test Method

Place the chip on a steel plate as illustrated on the right. Increase load applied to a point near the center of the test sample.

(2) Test Samples

GRM21 5C/R7/F5 Characteristics GRM31 5C/R7/F5 Characteristics

(3) Acceptance Criteria

Define the load that has caused the chip to break or crack, as the bending force.

(4) Explanation

Break strength, P, is proportionate to the square of the thickness of the ceramic element and is expressed as a curve of secondary degree.

The formula is:

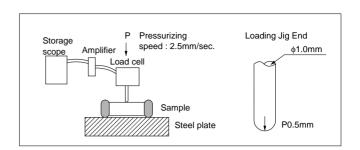
$$P = \frac{2\gamma WT^2}{3L} \quad (N)$$

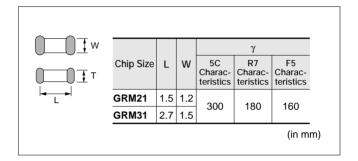
W: Width of ceramic element (mm)

T: Thickness of element (mm)

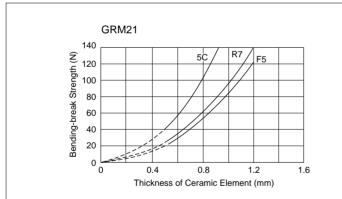
L: Distance between fulcrums (mm)

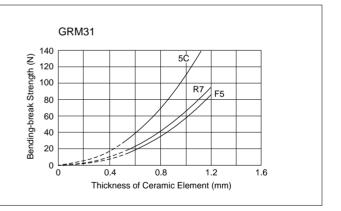
γ: Bending stress (N/mm²)





(5) Results





6. Thermal Shock

(1) Test method

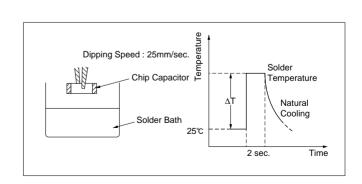
After applying flux (an ethanol solution of 25% rosin), dip the chip in a solder bath (6×4 eutectic solder) in accordance with the following conditions:

(2) Test samples

GRM21 5C/R7/F5 Characteristics T=0.6mm typical

(3) Acceptance criteria

Visually inspect the test sample with a 60-power optical microscope. Chips exhibiting breaks or cracks should be determined to be defective.

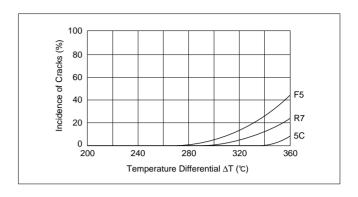




Reference Data

Continued from the preceding page.

(4) Results



7. Solder Heat Resistance

(1) Test Method

1) Reflow soldering:

Apply about 300 µm of solder paste over the alumina substrate. After reflow soldering, remove the chip and check for leaching that may have occurred on the outer electrode.

2 Flow soldering:

After dipping the test sample with a pair of tweezers in wave solder (eutectic solder), check for leaching that may have occurred on the outer electrode.

(2) Test samples

GRM21: For flow/reflow soldering T=0.6mm

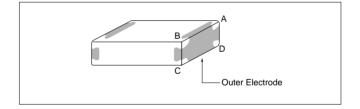
(3) Acceptance criteria

The starting time of leaching should be defined as the time when the outer electrode has lost 25% of the total edge length of A-B-C-D as illustrated:

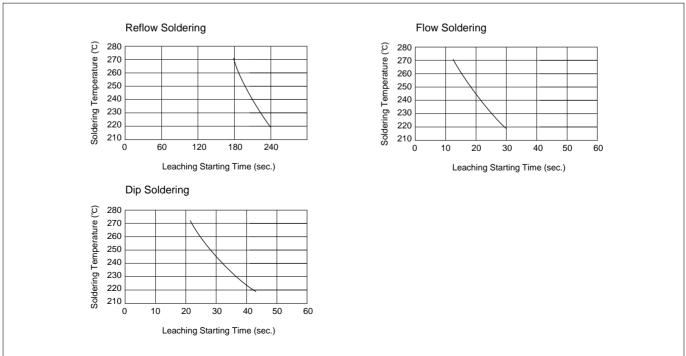
3 Dip soldering:

After dipping the test sample with a pair of tweezers in static solder (eutectic solder), check for leaching that may have occurred on the outer electrode.

4 Flux to be used: An ethanol solution of 25% rosin.



(4) Results



Reference Data

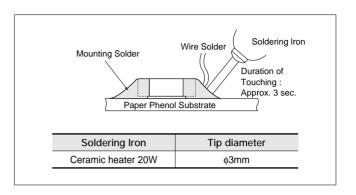
Continued from the preceding page.

8. Thermal Shock when Making Corrections with a Soldering Iron

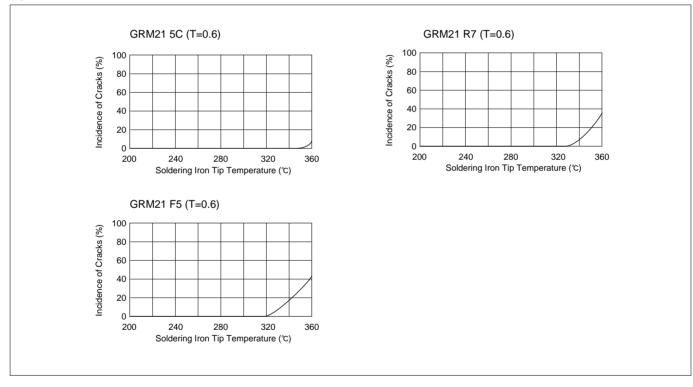
(1) Test Method

Apply a soldering iron meeting the conditions below to the soldered joint of a chip that has been soldered to a paper phenol board, while supplying wire solder. (Note: the soldering iron tip should not directly touch the ceramic element of the chip.)

- (2) Test Samples GRM21 5C/R7/F5 Characteristics T=0.6mm
- (3) Acceptance Criteria for Defects Observe the appearance of the test sample with a 60-power optical microscope. Those units displaying any breaks or cracks are determined to be defective.



(4) Results



Chip Monolithic Ceramic Capacitors

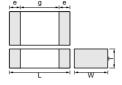


Medium Voltage Low Dissipation Factor

■ Features

- 1. Low-loss and suitable for high frequency circuits
- 2. Murata's original internal electrode structure realizes high flash-over voltage.
- 3. A new monolithic structure for small, surfacemountable devices capable of operating at high voltage levels
- 4. Sn-plated external electrodes realize good solderability.
- 5. Use the GRM21/31 type with flow or reflow soldering, and other types with reflow soldering only.

W W W



Part Number	Dimensions (mm)						
Part Number	L	W	T	e min.	g min.		
GRM21A	2.0 ±0.2	1.25 ±0.2	1.0 +0 0.3		0.7		
GRM31A	3.2 ±0.2	1.6 ±0.2	1.0 +0,-0.3				
GRM31B	3.2 ±0.2	1.6 ±0.2	1.25 +0,-0.3		1.5*		
GRM32A	3.2 ±0.2	2.5 ±0.2	1.0 +0,-0.3	0.3	1.5		
GRM32B	3.2 10.2	2.5 ±0.2	1.25 + 0, -0.3				
GRM42A	4.5 ±0.3	2.0 ±0.2	1.0 +0,-0.3		2.9		

* GRM31A7U3D, GRM32A7U3D, GRM32B7U3D : 1.8mm min.

Applications

Ideal for use on high frequency pulse circuits such as snubber circuits for switching power supplies, DC-DC converters, ballasts (inverter fluorescent lamps), etc.

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GRM21A7U2E101JW31D	DC250	U2J (EIA)	100 ±5%	2.0	1.25	1.0	0.7	0.3 min.
GRM21A7U2E151JW31D	DC250	U2J (EIA)	150 ±5%	2.0	1.25	1.0	0.7	0.3 min.
GRM21A7U2E221JW31D	DC250	U2J (EIA)	220 ±5%	2.0	1.25	1.0	0.7	0.3 min.
GRM21A7U2E331JW31D	DC250	U2J (EIA)	330 ±5%	2.0	1.25	1.0	0.7	0.3 min.
GRM21A7U2E471JW31D	DC250	U2J (EIA)	470 ±5%	2.0	1.25	1.0	0.7	0.3 min.
GRM21A7U2E681JW31D	DC250	U2J (EIA)	680 ±5%	2.0	1.25	1.0	0.7	0.3 min.
GRM21A7U2E102JW31D	DC250	U2J (EIA)	1000 ±5%	2.0	1.25	1.0	0.7	0.3 min.
GRM21A7U2E152JW31D	DC250	U2J (EIA)	1500 ±5%	2.0	1.25	1.0	0.7	0.3 min.
GRM21A7U2E222JW31D	DC250	U2J (EIA)	2200 ±5%	2.0	1.25	1.0	0.7	0.3 min.
GRM31A7U2E332JW31D	DC250	U2J (EIA)	3300 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2E472JW31D	DC250	U2J (EIA)	4700 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31B7U2E682JW31L	DC250	U2J (EIA)	6800 ±5%	3.2	1.6	1.25	1.5	0.3 min.
GRM31B7U2E103JW31L	DC250	U2J (EIA)	10000 ±5%	3.2	1.6	1.25	1.5	0.3 min.
GRM31A7U2J100JW31D	DC630	U2J (EIA)	10 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J150JW31D	DC630	U2J (EIA)	15 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J220JW31D	DC630	U2J (EIA)	22 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J330JW31D	DC630	U2J (EIA)	33 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J470JW31D	DC630	U2J (EIA)	47 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J680JW31D	DC630	U2J (EIA)	68 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J101JW31D	DC630	U2J (EIA)	100 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J151JW31D	DC630	U2J (EIA)	150 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J221JW31D	DC630	U2J (EIA)	220 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J331JW31D	DC630	U2J (EIA)	330 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J471JW31D	DC630	U2J (EIA)	470 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J681JW31D	DC630	U2J (EIA)	680 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U2J102JW31D	DC630	U2J (EIA)	1000 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM32A7U2J152JW31D	DC630	U2J (EIA)	1500 ±5%	3.2	2.5	1.0	1.5	0.3 min.
GRM32A7U2J222JW31D	DC630	U2J (EIA)	2200 ±5%	3.2	2.5	1.0	1.5	0.3 min.
GRM31A7U3A100JW31D	DC1000	U2J (EIA)	10 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U3A150JW31D	DC1000	U2J (EIA)	15 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U3A220JW31D	DC1000	U2J (EIA)	22 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U3A330JW31D	DC1000	U2J (EIA)	33 ±5%	3.2	1.6	1.0	1.5	0.3 min.

Continued from the preceding page.

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GRM31A7U3A470JW31D	DC1000	U2J (EIA)	47 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U3A680JW31D	DC1000	U2J (EIA)	68 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U3A101JW31D	DC1000	U2J (EIA)	100 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U3A151JW31D	DC1000	U2J (EIA)	150 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U3A221JW31D	DC1000	U2J (EIA)	220 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31A7U3A331JW31D	DC1000	U2J (EIA)	330 ±5%	3.2	1.6	1.0	1.5	0.3 min.
GRM31B7U3A471JW31L	DC1000	U2J (EIA)	470 ±5%	3.2	1.6	1.25	1.5	0.3 min.
GRM31A7U3D100JW31D	DC2000	U2J (EIA)	10 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D120JW31D	DC2000	U2J (EIA)	12 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D150JW31D	DC2000	U2J (EIA)	15 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D180JW31D	DC2000	U2J (EIA)	18 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D220JW31D	DC2000	U2J (EIA)	22 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D270JW31D	DC2000	U2J (EIA)	27 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D330JW31D	DC2000	U2J (EIA)	33 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D390JW31D	DC2000	U2J (EIA)	39 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D470JW31D	DC2000	U2J (EIA)	47 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D560JW31D	DC2000	U2J (EIA)	56 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM31A7U3D680JW31D	DC2000	U2J (EIA)	68 ±5%	3.2	1.6	1.0	1.8	0.3 min.
GRM32A7U3D820JW31D	DC2000	U2J (EIA)	82 ±5%	3.2	2.5	1.0	1.8	0.3 min.
GRM32A7U3D101JW31D	DC2000	U2J (EIA)	100 ±5%	3.2	2.5	1.0	1.8	0.3 min.
GRM32A7U3D121JW31D	DC2000	U2J (EIA)	120 ±5%	3.2	2.5	1.0	1.8	0.3 min.
GRM32A7U3D151JW31D	DC2000	U2J (EIA)	150 ±5%	3.2	2.5	1.0	1.8	0.3 min.
GRM32B7U3D181JW31L	DC2000	U2J (EIA)	180 ±5%	3.2	2.5	1.25	1.8	0.3 min.
GRM32B7U3D221JW31L	DC2000	U2J (EIA)	220 ±5%	3.2	2.5	1.25	1.8	0.3 min.
GRM42A7U3F270JW31L	DC3150	U2J (EIA)	27 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A7U3F330JW31L	DC3150	U2J (EIA)	33 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A7U3F390JW31L	DC3150	U2J (EIA)	39 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A7U3F470JW31L	DC3150	U2J (EIA)	47 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A7U3F560JW31L	DC3150	U2J (EIA)	56 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A7U3F680JW31L	DC3150	U2J (EIA)	68 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A7U3F820JW31L	DC3150	U2J (EIA)	82 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A7U3F101JW31L	DC3150	U2J (EIA)	100 ±5%	4.5	2.0	1.0	2.9	0.3 min.

Specifications and Test Methods

No.	Ite	em	Specifications	Test Method			
1	Operating Temperatu	ıre Range	−55 to +125°C	-			
2	Appearar	nce	No defects or abnormalities	Visual inspection			
3	Dimensio	ns	Within the specified dimension	Using calipers			
4	Dielectric	Strength	No defects or abnormalities	No failure should be observed when voltage in Table is applied between the terminations for 1 to 5 sec., provided the charge/ discharge current is less than 50mA. Rated voltage Test voltage DC250V 200% of the rated voltage DC630V 150% of the rated voltage DC1kV, DC2kV 120% of the rated voltage DC3.15kV DC4095V			
5	Insulation I	Resistance	More than 10,000MΩ	The insulation resistance should be measured with DC500±50V (DC250±25V in case of rated voltage: DC250V) and within 60±5 sec. of charging.			
6	Capacita	nce	Within the specified tolerance	The capacitance/Q should be measured at the frequency and			
7	7 Q 1,000		1,000 min.	voltage shown as follows. Capacitance Frequency Voltage C<1,000pF			
8	Capacitance 8 Temperature Characteristics		Temp. Coefficient -750±120 ppm/℃ (Temp. Range: +25 to +125℃) -750+120, -347 ppm/℃ (Temp. Range: -55 to +25℃)	The capacitance measurement should be made at each step specified in Table. Step Temperature (°C) 1 25±2 2 Min. Operating Temp.±3 3 25±2 4 Max. Operating Temp.±2 5 25±2			
9	Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 1. Then apply 10N force in the direction of the arrow. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 10N, 10±1s Glass Epoxy Board Glass Epoxy Board Fig. 1			
		Appearance	No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board).			
			Within the specified tolerance	The capacitor should be subjected to a simple harmonic motion			
10	O Vibration Resistance Q		1,000 min.	having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 min. This motion should be applied for a period of 2 hrs. in each of 3 mutually perpendicular directions (total of 6 hrs.). Solder resist Glass Epoxy Board			

Continued on the following page. $\begin{tabular}{|c|c|c|c|} \hline \end{tabular}$



Specifications and Test Methods

Continued from the preceding page Specifications No Item Test Method No cracking or marking defects should occur. Solder the capacitor to the testing jig (glass epoxy board) shown Then apply a force in the direction shown in Fig. 3. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 20 50 Pressurizing speed: 1.0mm/s Deflection

L×W		Dimensi	on (mm)	
(mm)	а	b	С	d
2.0×1.25	1.2	4.0	1.65	
3.2×1.6	2.2	5.0	2.0	1.0
3.2×2.5	2.2	5.0	2.9	1.0
4.5×2.0	3.5	7.0	2.4	
		Fig. 2		

Pressurize Flexure=1 (in mm) Fig. 3

12	12 Solderability of Termination		75% of the terminations are to be soldered evenly and continuously.
		Appearance	No marking defects
		Capacitance Change	Within ±2.5%
10	Resistance	Q	1,000 min.
13	to Soldering		

More than $10,000M\Omega$

In accordance with item No.4

In accordance with item No.4

No marking defects

More than 1,000M Ω

Within ±3.0%

350 min.

I.R.

Dielectric

Dielectric

Strength

Appearance

Capacitance

Change

Q

I.R.

Heat

Temperature Cycle

Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Immerse in solder solution for 2±0.5 sec. Immersing speed: 25±2.5mm/s

Temp. of solder: 245±5°C Lead Free Solder (Sn-3.0Ag-0.5Cu) 235±5°C H60A or H63A Eutectic Solder

Immerse the capacitor in solder solution at 260±5℃ for 10±1 sec.

•Immersing speed: 25±2.5mm/s

Preheat the capacitor at 120 to 150°C* for 1 min.

Let sit at room condition* for 24±2 hrs., then measure.

*Preheating for more than 3.2×2.5mm

Step	Temperature	Time
1	100 to 120℃	1 min.
2	170 to 200℃	1 min.

Strength No marking defects Appearance Capacitance Within ±2.5% Change 500 min. I.R. More than $10,000M\Omega$

Fix the capacitor to the supporting jig (glass epoxy board) shown Perform the 5 cycles according to the 4 heat treatments listed in the following table.

Let sit for 24±2 hrs. at room condition*, then measure.

Step	Temperature (℃)	Time (min.)
1	Min. Operating Temp.±3	30±3
2	Room Temp.	2 to 3
3	Max. Operating Temp.±2	30±3
4	Room Temp.	2 to 3

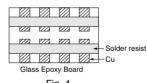


				Fig. 4
		Appearance	No marking defects	
	15 Humidity (Steady State) I.	Capacitance Change	Within ±5.0%	Let the capacitor sit at 40±2°C and relative humidity of 90 to 95%
		Q	350 min.	for 500 ⁺²⁴ / _o hrs.
		I.R.	More than 1,000M Ω	Remove and let sit for 24±2 hrs. at room condition*, then measure.
		Dielectric Strength	In accordance with item No.4	incusare.

Apply 120% of the rated voltage for 1,000 ± 48 hrs. at maximum operating temperature ±3°C. Remove and let sit for 24±2 hrs. at room condition*, then

The charge/discharge current is less than 50mA.

* "Room condition" Temperature: 15 to 35℃, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa



Life

16

Dielectric In accordance with item No.4 Strength

Chip Monolithic Ceramic Capacitors



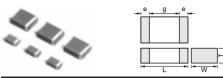
Medium Voltage High Capacitance for General Use

■ Features

- 1. A new monolithic structure for small, high capacitance capable of operating at high voltage
- 2. Sn-plated external electrodes realizes good solderability.
- 3. Use the GRM18/21/31 types with flow or reflow soldering, and other types with reflow soldering only.

■ Applications

- 1. Ideal for use on diode-snubber circuits for switching power supplies
- 2. Ideal for use as primary-secondary coupling for DC-DC converter
- 3. Ideal for use on line filters and ringer detectors for telephones, facsimiles and modems



Part Number	Dimensions (mm)								
rait Nullibei	L W T		е	g min.					
GRM188	1.6 ±0.1	0.8 ±0.1	0.8 ±0.1	0.2 to 0.5	0.4				
GRM21A	2.0 ±0.2	1.25 ±0.2	1.0 +0,-0.3		0.7				
GRM21B	2.0 ±0.2	1.25 ±0.2	1.25 ±0.2		0.7				
GRM31B	3.2 ±0.2	1.6 ±0.2	1.25 +0,-0.3						
GRM31C	3.2 ±0.2	1.0 ±0.2	1.6 ±0.2	0.3 min.	1.2				
GRM32Q	3.2 ±0.3	2.5 ±0.2	1.5 +0,-0.3						
GRM32D	3.2 ±0.3	2.5 ±0.2	2.0 +0,-0.3						
GRM43Q	4.5 ±0.4	3.2 ±0.3	1.5 +0,-0.3		2.2				
GRM43D	4.5 ±0.4	3.2 ±0.3	2.0 + 0, -0.3		2.2				
GRM55D	5.7 ±0.4	5.0 ±0.4	2.0 +0,-0.3		3.2				

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GRM188R72E221KW07D	DC250	X7R (EIA)	220pF ±10%	1.6	0.8	0.8	0.4	0.2 to 0.5
GRM188R72E331KW07D	DC250	X7R (EIA)	330pF ±10%	1.6	0.8	0.8	0.4	0.2 to 0.5
GRM188R72E471KW07D	DC250	X7R (EIA)	470pF ±10%	1.6	0.8	0.8	0.4	0.2 to 0.5
GRM188R72E681KW07D	DC250	X7R (EIA)	680pF ±10%	1.6	0.8	0.8	0.4	0.2 to 0.5
GRM188R72E102KW07D	DC250	X7R (EIA)	1000pF ±10%	1.6	0.8	0.8	0.4	0.2 to 0.5
GRM21AR72E102KW01D	DC250	X7R (EIA)	1000pF ±10%	2.0	1.25	1.0	0.7	0.3 min.
GRM188R72E152KW07D	DC250	X7R (EIA)	1500pF ±10%	1.6	0.8	0.8	0.4	0.2 to 0.5
GRM21AR72E152KW01D	DC250	X7R (EIA)	1500pF ±10%	2.0	1.25	1.0	0.7	0.3 min.
GRM188R72E222KW07D	DC250	X7R (EIA)	2200pF ±10%	1.6	0.8	0.8	0.4	0.2 to 0.5
GRM21AR72E222KW01D	DC250	X7R (EIA)	2200pF ±10%	2.0	1.25	1.0	0.7	0.3 min.
GRM21AR72E332KW01D	DC250	X7R (EIA)	3300pF ±10%	2.0	1.25	1.0	0.7	0.3 min.
GRM21AR72E472KW01D	DC250	X7R (EIA)	4700pF ±10%	2.0	1.25	1.0	0.7	0.3 min.
GRM21AR72E682KW01D	DC250	X7R (EIA)	6800pF ±10%	2.0	1.25	1.0	0.7	0.3 min.
GRM21BR72E103KW03L	DC250	X7R (EIA)	10000pF ±10%	2.0	1.25	1.25	0.7	0.3 min.
GRM31BR72E153KW01L	DC250	X7R (EIA)	15000pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR72E223KW01L	DC250	X7R (EIA)	22000pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31CR72E333KW03L	DC250	X7R (EIA)	33000pF ±10%	3.2	1.6	1.6	1.2	0.3 min.
GRM31CR72E473KW03L	DC250	X7R (EIA)	47000pF ±10%	3.2	1.6	1.6	1.2	0.3 min.
GRM31BR72E683KW01L	DC250	X7R (EIA)	68000pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM32QR72E683KW01L	DC250	X7R (EIA)	68000pF ±10%	3.2	2.5	1.5	1.2	0.3 min.
GRM31CR72E104KW03L	DC250	X7R (EIA)	0.10μF ±10%	3.2	1.6	1.6	1.2	0.3 min.
GRM32DR72E104KW01L	DC250	X7R (EIA)	0.10μF ±10%	3.2	2.5	2.0	1.2	0.3 min.
GRM43QR72E154KW01L	DC250	X7R (EIA)	0.15μF ±10%	4.5	3.2	1.5	2.2	0.3 min.
GRM32DR72E224KW01L	DC250	X7R (EIA)	0.22μF ±10%	3.2	2.5	2.0	1.2	0.3 min.
GRM43DR72E224KW01L	DC250	X7R (EIA)	0.22μF ±10%	4.5	3.2	2.0	2.2	0.3 min.
GRM43DR72E334KW01L	DC250	X7R (EIA)	0.33μF ±10%	4.5	3.2	2.0	2.2	0.3 min.
GRM55DR72E334KW01L	DC250	X7R (EIA)	0.33μF ±10%	5.7	5.0	2.0	3.2	0.3 min.
GRM43DR72E474KW01L	DC250	X7R (EIA)	0.47μF ±10%	4.5	3.2	2.0	2.2	0.3 min.
GRM55DR72E474KW01L	DC250	X7R (EIA)	0.47μF ±10%	5.7	5.0	2.0	3.2	0.3 min.
GRM55DR72E105KW01L	DC250	X7R (EIA)	1.0μF ±10%	5.7	5.0	2.0	3.2	0.3 min.
GRM31BR72J102KW01L	DC630	X7R (EIA)	1000pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR72J152KW01L	DC630	X7R (EIA)	1500pF ±10%	3.2	1.6	1.25	1.2	0.3 min.

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Continued from the preceding page.

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GRM31BR72J222KW01L	DC630	X7R (EIA)	2200pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR72J332KW01L	DC630	X7R (EIA)	3300pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR72J472KW01L	DC630	X7R (EIA)	4700pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR72J682KW01L	DC630	X7R (EIA)	6800pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR72J103KW01L	DC630	X7R (EIA)	10000pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31CR72J153KW03L	DC630	X7R (EIA)	15000pF ±10%	3.2	1.6	1.6	1.2	0.3 min.
GRM32QR72J223KW01L	DC630	X7R (EIA)	22000pF ±10%	3.2	2.5	1.5	1.2	0.3 min.
GRM32DR72J333KW01L	DC630	X7R (EIA)	33000pF ±10%	3.2	2.5	2.0	1.2	0.3 min.
GRM32DR72J473KW01L	DC630	X7R (EIA)	47000pF ±10%	3.2	2.5	2.0	1.2	0.3 min.
GRM43QR72J683KW01L	DC630	X7R (EIA)	68000pF ±10%	4.5	3.2	1.5	2.2	0.3 min.
GRM43DR72J104KW01L	DC630	X7R (EIA)	0.10μF ±10%	4.5	3.2	2.0	2.2	0.3 min.
GRM55DR72J154KW01L	DC630	X7R (EIA)	0.15μF ±10%	5.7	5.0	2.0	3.2	0.3 min.
GRM55DR72J224KW01L	DC630	X7R (EIA)	0.22μF ±10%	5.7	5.0	2.0	3.2	0.3 min.
GRM31BR73A471KW01L	DC1000	X7R (EIA)	470pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR73A102KW01L	DC1000	X7R (EIA)	1000pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR73A152KW01L	DC1000	X7R (EIA)	1500pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR73A222KW01L	DC1000	X7R (EIA)	2200pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR73A332KW01L	DC1000	X7R (EIA)	3300pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM31BR73A472KW01L	DC1000	X7R (EIA)	4700pF ±10%	3.2	1.6	1.25	1.2	0.3 min.
GRM32QR73A682KW01L	DC1000	X7R (EIA)	6800pF ±10%	3.2	2.5	1.5	1.2	0.3 min.
GRM32QR73A103KW01L	DC1000	X7R (EIA)	10000pF ±10%	3.2	2.5	1.5	1.2	0.3 min.
GRM32DR73A153KW01L	DC1000	X7R (EIA)	15000pF ±10%	3.2	2.5	2.0	1.2	0.3 min.
GRM32DR73A223KW01L	DC1000	X7R (EIA)	22000pF ±10%	3.2	2.5	2.0	1.2	0.3 min.
GRM43DR73A333KW01L	DC1000	X7R (EIA)	33000pF ±10%	4.5	3.2	2.0	2.2	0.3 min.
GRM43DR73A473KW01L	DC1000	X7R (EIA)	47000pF ±10%	4.5	3.2	2.0	2.2	0.3 min.
GRM55DR73A104KW01L	DC1000	X7R (EIA)	0.10μF ±10%	5.7	5.0	2.0	3.2	0.3 min.

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Specifications and Test Methods

No.	Ite	m	Specifications	Test Method			
1	Operating Temperatu	re Range	-55 to +125℃	_			
2	Appearan	ce	No defects or abnormalities	Visual inspection			
3	Dimension	าร	Within the specified dimensions	Using calipers			
4	Dielectric	Strength	No defects or abnormalities	No failure should be observed when 150% of the rated voltage (200% of the rated voltage in case of rated voltage: DC250V, 120% of the rated voltage in case of rated voltage: DC1kV) is applied between the terminations for 1 to 5 sec., provided the charge/discharge current is less than 50mA.			
5	Insulation R (I.R.)	esistance	C≥0.01μF: More than 100M Ω • μF C<0.01μF: More than 10,000M Ω	The insulation resistance should be measured with DC500±50\ (DC250±25V in case of rated voltage: DC250V) and within 60± sec. of charging.			
6	Capacitan	ice	Within the specified tolerance	The capacitance/D.F. should be measured at a frequency of			
7	Dissipatio Factor (D.		0.025 max.	1±0.2kHz and a voltage of AC1±0.2V(r.m.s.)			
9	Capacitance 8 Temperature Characteristics		Cap. Change Within ±15% (Temp. Range: −55 to +125°C) No removal of the terminations or other defect should occur.	The capacitance measurement should be made at each step specified in Table. Step Temperature (°C) 1 25±2 2 Min. Operating Temp.±3 3 25±2 4 Max. Operating Temp.±2 5 25±2 • Pretreatment Perform a heat treatment at 150 ± 9 o °C for 60±5 min. and then let sit for 24±2 hrs. at room condition*. Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 1. Then apply 10N force in the direction of the arrow. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.			
				Glass Epoxy Board Fig. 1			
		Appearance	No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board). The capacitor should be subjected to a simple harmonic motion			
		Capacitance	Within the specified tolerance	having a total amplitude of 1.5mm, the frequency being varied			
10	Vibration Resistance D.F.		0.025 max.	uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 min. This motion should be applied for a period of 2 hrs. in each of 3 mutually perpendicular directions (total of 6 hrs.). Solder resist Cu Glass Epoxy Board			

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa





No.	Item	Specifications	Test Method			
11 Deflection		No cracking or marking defects should occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 2. Then apply a force in the direction shown in Fig. 3. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 20 50 Pressurizing speed: 1.0mm/s peed: 1.0mm/s Pressurize Flexure=1 (in mm) Fig. 3			
	lerability of nination	75% of the terminations are to be soldered evenly and continuously.	rosin (JIS-K-5902) (25% rosin in weight proportion). Immerse in solder solution for 2±0.5 sec. Immersing speed: 25±2.5mm/s Temp. of solder: 245±5°C Lead Free Solder (Sn-3.0Ag-0.5Cu) 235±5°C H60A or H63A Eutectic Solder			
Resistan 13 to Solde Heat		No marking defects Within ±10% 0.025 max. C≥0.01μF: More than 100MΩ • μF C<0.01μF: More than 10,000MΩ	Preheat the capacitor at 120 to 150°C* for 1 min. Immerse the capacitor in solder solution at 260±5°C for 10±1 sec. Let sit at room condition* for 24±2 hrs., then measure. •Immersing speed: 25±2.5mm/s •Pretreatment Perform a heat treatment at 150±18°C for 60±5 min. and ther let sit for 24±2 hrs. at room condition*.			
riodi	Dielectric Strength	In accordance with item No.4	Step Temperature Time 1 100 to 120℃ 1 min. 2 170 to 200℃ 1 min.			
	Appearance Capacitance Change D.F. I.R.	No marking defects $Within \pm 7.5\%$ 0.025 max. $C \ge 0.01 \mu F: More than 100 MΩ • μF$ $C < 0.01 μF: More than 10,000 MΩ$	Fix the capacitor to the supporting jig (glass epoxy board) shown in Fig. 4. Perform the 5 cycles according to the 4 heat treatments listed in the following table. Let sit for 24±2 hrs. at room condition*, then measure. Step Temperature (°C) Time (min.) 1 Min. Operating Temp.±3 30±3			
Tempera Cycle	Dielectric Strength	In accordance with item No.4	Perform a heat treatment at 150±18°C for 60±5 min. and then let sit for 24±2 hrs. at room condition*. 2 to 3 3 Max. Operating Temp.±2 30±3 4 Room Temp. 2 to 3 • Pretreatment Perform a heat treatment at 150±18°C for 60±5 min. and then let sit for 24±2 hrs. at room condition*. Solder resist Cu Glass Epoxy Board			
	Appearance	No marking defects	1 ig. 4			
	Capacitance Change	Within ±15%	Let the capacitor sit at $40\pm2^{\circ}$ C and relative humidity of 90 to 95% for $500^{\pm24}_{\circ}$ hrs.			
Humic 15 (Stead State)	idy D.F.	0.05 max. C≥0.01μF: More than 10MΩ • μF C<0.01μF: More than 1,000MΩ	Remove and let sit for 24±2 hrs. at room condition*, then measure. • Pretreatment Perform a heat treatment at 150± ₁ 8° for 60±5 min. and then			
15 (Stead	Change D.F.	0.05 max. C≥0.01μF: More than 10MΩ • μF	Glass Epoxy Board Fig. 4 Let the capacitor sit at 40±2°C and relators 500±2°d hrs. Remove and let sit for 24±2 hrs. at romeasure. • Pretreatment			

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa



Continued from the preceding page.

No.	Ite	em	Specifications	Test Method		
		Appearance No marking defects		Apply 120% of the rated voltage (150% of the rated voltage in		
		Capacitance Change	Within ±15% (rated voltage: DC250V, DC630V) Within ±20% (rated voltage: DC1kV)	case of rated voltage: DC250V, 110% of the rated voltage in case of rated voltage: DC1kV) for 1,000 ^{± 48} / ₈ hrs. at maximum		
16	Life	D.F.	0.05 max.	operating temperature ±3°C. Remove and let sit for 24 ±2 hrs. at room condition*, then measure.		
		I.R.	C≥0.01μF: More than 10M Ω • μF C<0.01μF: More than 1,000M Ω	The charge/discharge current is less than 50mA. • Pretreatment		
		Dielectric Strength	In accordance with item No.4	Apply test voltage for 60±5 min. at test temperature. Remove and let sit for 24±2 hrs. at room condition*.		
		Appearance	No marking defects			
	Humidity Loading	Capacitance Change	Within ±15%	Apply the rated voltage at $40\pm2^{\circ}\text{C}$ and relative humidity of 90 to 95% for $500\pm^{24}\text{ch}$ hrs.		
17	(Application:	D.F.	0.05 max.	Remove and let sit for 24±2 hrs. at room condition*, then measure.		
.,	DC250V, DC630V	I.R.	C≥0.01μF: More than 10M Ω • μF C<0.01μF: More than 1,000M Ω	Pretreatment Apply test voltage for 60±5 min. at test temperature.		
	item) -	Dielectric Strength	In accordance with item No.4	Remove and let sit for 24±2 hrs. at room condition*.		

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa





Only for LCD Backlight Inverter Circuit

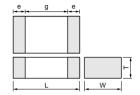
■ Features

- 1. Low-loss and suitable for high frequency circuits
- 2. Murata's original internal electrode structure realizes high flash-over voltage.
- 3. A new monolithic structure for small, surfacemountable devices capable of operating at high voltage levels.
- 4. Sn-plated external electrodes realize good solderability.
- 5. Only for reflow soldering
- 6. The capacitors less than 22pF can be applied maximum 4.0kV peak to peak at 100kHz or less only for the ballast or the resonance usage in the LCD backlight inverter circuit.



Ideal for use as the ballast in LCD backlight inverter.





Part Number		Dimensions (mm)								
Part Number	L	W	Т	e min.	g min.					
GRM42A	4.5 ±0.3	2.0 ±0.2	1.0 +0, -0.3	0.3	2.9					

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GRM42A5C3F050DW01L	DC3150	COG (EIA)	5.0 ±0.5pF	4.5	2.0	1.0	2.9	0.3 min.
GRM42A5C3F100JW01L	DC3150	C0G (EIA)	10 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A5C3F120JW01L	DC3150	C0G (EIA)	12 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A5C3F150JW01L	DC3150	C0G (EIA)	15 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A5C3F180JW01L	DC3150	C0G (EIA)	18 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A5C3F220JW01L	DC3150	C0G (EIA)	22 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A5C3F270JW01L	DC3150	C0G (EIA)	27 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A5C3F330JW01L	DC3150	C0G (EIA)	33 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A5C3F390JW01L	DC3150	C0G (EIA)	39 ±5%	4.5	2.0	1.0	2.9	0.3 min.
GRM42A5C3F470JW01L	DC3150	COG (EIA)	47 ±5%	4.5	2.0	1.0	2.9	0.3 min.

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No. Item		Specifications	Test Method		
Operating Temperatu	ıre Range	-55 to +125℃	-		
2 Appearance No defects or abnormalities			Visual inspection		
Dimensio	ns	Within the specified dimension	Using calipers		
4 Dielectric Strength		No defects or abnormalities	No failure should be observed when DC4095V is applied between the terminations for 1 to 5 sec., provided the charge/ discharge current is less than 50mA.		
Insulation I (I.R.)	Resistance	More than 10,000M Ω	The insulation resistance should be measured with DC500±50V and within 60±5 sec. of charging.		
Capacita	nce	Within the specified tolerance	The capacitance/Q should be measured at a frequency of		
Q		1,000 min.	1±0.2MHz and a voltage of AC0.5 to 5V(r.m.s.)		
Capacitance 8 Temperature Characteristics		Temp. Coefficient 0±30 ppm/°C (Temp. Range: +25 to +125°C) 0+30, −72 ppm/°C (Temp. Range: −55 to +25°C)	The capacitance measurement should be made at each step specified in Table. Step Temperature (°C) 1 25±2 2 Min. Operating Temp.±3 3 25±2 4 Max. Operating Temp.±2 5 25±2		
Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 1. Then apply 10N force in the direction of the arrow. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 10N, 10±1s Glass Epoxy Board Glass Epoxy Board		
	Appearance	No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board).		
Appearance Capacitance Vibration Resistance Q		Within the specified tolerance 1,000 min.	The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 min. This motion should be applied for a period of 2 hrs. in each of 3 mutually perpendicular directions (total of 6 hrs.). Solder resist Cu Glass Epoxy Board		
		No cracking or marking defects should occur.	Solder the capacitor to the testing jig (glass epoxy board) shown		
11 Deflection		Dimension (mm) C d d d d d d d d d	in Fig. 2. Then apply a force in the direction shown in Fig. 3. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 20 50 Pressurizing speed: 1.0mm/s Pressurize Capacitance meter 45 (in mm) Fig. 3		
	Operating Temperature Appearary Dimension Dielectrical Insulation F (I.R.) Capacitature Q Capacitature Capacitature Charactery Charactery Of Terminal Vibration Resistance	Operating Temperature Range Appearance Dimensions Dielectric Strength Insulation Resistance (I.R.) Capacitance Q Capacitance Temperature Characteristics Adhesive Strength of Termination Appearance Capacitance Q Q	Operating Temperature Range		



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• This PDF catalog has only typical specifications because there is no space for detailed specifications. Therefore, please approve our product specifications or transact the approval sheet for product specifications before ordering.

Specifications and Test Methods

Continued from the preceding page.

Nc	Continued in		Specifications	Toot Mathod					
No.	Ite	2111	Specifications	Test Method					
12	Solderability of Termination		75% of the terminations are to be soldered evenly and continuously.	Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Immerse in solder solution for 2±0.5 sec. Immersing speed: 25±2.5mm/s Temp. of solder: 245±5°C Lead Free Solder (Sn-3.0Ag-0.5Cu) 235±5°C H60A or H63A Eutectic Solder					
		Appearance	No marking defects	Preheat the capacitor as table.					
		Capacitance Change	Within ±2.5%	Immerse the capacitor in solder solution at 260±5°C for 10±1 sec. Let sit at room condition* for 24±2 hrs., then measure. •Immersing speed: 25±2.5mm/s					
12	Resistance	Q	1,000 min.						
13	to Soldering Heat	I.R.	More than 10,000M Ω	*Preheating					
				Step Temperature Time					
		Dielectric	In accordance with item No.4	1 100 to 120℃ 1 min.					
		Strength		2 170 to 200°C 1 min.					
		Appearance	No marking defects	Fix the capacitor to the supporting jig (glass epoxy board) shown					
		Capacitance Change	Within ±2.5%	in Fig. 4. Perform the 5 cycles according to the 4 heat treatments listed in the following table.					
		Q	1,000 min.	Let sit for 24±2 hrs. at room condition*, then measure.					
		I.R.	More than 10,000MΩ	Step Temperature (°C) Time (min.)					
14	Temperature Cycle	erature		1 Min. Operating Temp.±3 30±3 2 Room Temp. 2 to 3 3 Max. Operating Temp.±2 30±3 4 Room Temp. 2 to 3					
		Dielectric Strength	In accordance with item No.4	Solder resist Glass Epoxy Board Fig. 4					
		Appearance	No marking defects						
	Humidity	Capacitance Change	Within ±5.0%	Let the capacitor sit at 40±2°C and relative humidity of 90 to 95%					
15	(Steady	Q	350 min.	for 500 ⁺²⁴ / ₀ hrs.					
	State)	I.R.	More than 1,000M Ω	Remove and let sit for 24±2 hrs. at room condition*, then measure.					
		Dielectric Strength	In accordance with item No.4						
		Appearance	No marking defects						
		Capacitance Change	Within ±3.0%	Apply 120% of the rated voltage for 1,000 ± ⁴ 8 hrs. at maximum operating temperature ±3°C.					
16	Life	Q	350 min.	Remove and let sit for 24±2 hrs. at room condition*, then					
		I.R.	More than 1,000M Ω	measure.					
		Dielectric Strength	In accordance with item No.4	The charge/discharge current is less than 50mA.					

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa



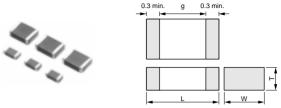
Only for Information Devices/Tip & Ring

■ Features

- These items are designed specifically for telecommunications devices (IEEE802.3) in Ethernet LAN and primary-secondary coupling for DC-DC converter.
- 2. A new monolithic structure for small, high capacitance capable of operating at high voltage
- 3. Sn-plated external electrodes realizes good solderability.
- 4. Only for reflow soldering
- 5. The low-profile type (thickness: 1.5mm max.) is available. Fit for use on thinner type equipment.

■ Applications

- Ideal for use on telecommunications devices in Ethernet LAN
- Ideal for use as primary-secondary coupling for DC-DC converter



Dout Number				
Part Number	L	W	T	g min.
GR442Q	4.5 ±0.3	2.0 ±0.2	1.5 +0, -0.3	
GR443D	4.5 ±0.4	3.2 ±0.3	2.0 +0, -0.3	2.5
GR443Q	4.5 ±0.4	3.2 ±0.3	1.5 +0, -0.3	
GR455D	5.7 ±0.4	5.0 ±0.4	2.0 +0, -0.3	3.2

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GR442QR73D101KW01L	DC2000	X7R (EIA)	100 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D121KW01L	DC2000	X7R (EIA)	120 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D151KW01L	DC2000	X7R (EIA)	150 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D181KW01L	DC2000	X7R (EIA)	180 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D221KW01L	DC2000	X7R (EIA)	220 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D271KW01L	DC2000	X7R (EIA)	270 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D331KW01L	DC2000	X7R (EIA)	330 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D391KW01L	DC2000	X7R (EIA)	390 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D471KW01L	DC2000	X7R (EIA)	470 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D561KW01L	DC2000	X7R (EIA)	560 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D681KW01L	DC2000	X7R (EIA)	680 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D821KW01L	DC2000	X7R (EIA)	820 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D102KW01L	DC2000	X7R (EIA)	1000 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D122KW01L	DC2000	X7R (EIA)	1200 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR442QR73D152KW01L	DC2000	X7R (EIA)	1500 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GR443QR73D182KW01L	DC2000	X7R (EIA)	1800 ±10%	4.5	3.2	1.5	2.5	0.3 min.
GR443QR73D222KW01L	DC2000	X7R (EIA)	2200 ±10%	4.5	3.2	1.5	2.5	0.3 min.
GR443QR73D272KW01L	DC2000	X7R (EIA)	2700 ±10%	4.5	3.2	1.5	2.5	0.3 min.
GR443QR73D332KW01L	DC2000	X7R (EIA)	3300 ±10%	4.5	3.2	1.5	2.5	0.3 min.
GR443QR73D392KW01L	DC2000	X7R (EIA)	3900 ±10%	4.5	3.2	1.5	2.5	0.3 min.
GR443DR73D472KW01L	DC2000	X7R (EIA)	4700 ±10%	4.5	3.2	2.0	2.5	0.3 min.
GR455DR73D103KW01L	DC2000	X7R (EIA)	10000 ±10%	5.7	5.0	2.0	3.2	0.3 min.

No.	Ite	m	Specifications		Test Method			
1	Operating Temperatu	re Range	−55 to +125°C		-			
2	Appearan	ice	No defects or abnormalities	Visual inspection				
3	Dimension	ns	Within the specified dimensions	Using calipers				
4	Dielectric Strength				No failure should be observed when voltage in table is ap between the terminations, provided the charge/discharge is less than 50mA. Rated voltage Test Voltage Time 120% of the rated voltage 60±1			
5	Pulse Volt	tage	No self healing breakdowns or flash-overs have taken place in the capacitor.	AC1500V(r.m.s.) 60±1 sec. 10 impulse of alternating polarity is subjected. (5 impulse for each polarity) The interval between impulse is 60 sec. Applied Voltage: 2.5kV zero to peak				
6	Insulation R (I.R.)	Resistance	More than $6{,}000M\Omega$	The insulation resist and within 60±5 sec	ance should be measured witl c. of charging.	h DC500±50V		
7	Capacitar	nce	Within the specified tolerance	The canacitance/D	= should be measured at a fro	edilency of		
8	8 Dissipation Factor (D.F.) 0.025 max. The capacitance/D.F. should be measur 1±0.2kHz and a voltage of AC1±0.2V(r.					squericy of		
9	Capacitan Temperatu Characteri	ure	Cap. Change within ±15% (Temp. Range: −55 to +125°C)	The capacitance measurement should be made at each step specified in Table. Step Temperature (°C) 1 25±2 2 Min. Operating Temp.±3 3 25±2 4 Max. Operating Temp.±2 5 25±2 • Pretreatment Perform a heat treatment at 150 ⁺ / ₁₀ °C for 60±5 min. and then let sit for 24±2 hrs. at room condition*.				
10	Adhesive of Termina		No removal of the terminations or other defect should occur.	in Fig. 1. Then apply 10N force The soldering should	to the testing jig (glass epoxy be in the direction of the arrow do be done using the reflow med with care so that the soldering such as heat shock. 10N, 10±1s Glass Epoxy Boar Fig. 1	ethod and ng is uniform		
		Appearance	No defects or abnormalities	Solder the capacitor	to the test jig (glass epoxy bo	pard).		
		Capacitance	Within the specified tolerance	The capacitor should	d be subjected to a simple har	rmonic motion		
11	Vibration Resistance	D.F.	0.025 max.	uniformly between the frequency range, fro traversed in approximation of 2 hrs. directions (total of 6	ude of 1.5mm, the frequency one approximate limits of 10 and m 10 to 55Hz and return to 10 mately 1 min. This motion shows in each of 3 mutually perpendings.). Solder resist Cullass Epoxy Board	d 55Hz. The DHz, should be ould be applied dicular		

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa



Continued from the preceding page Specifications No Item Test Method No cracking or marking defects should occur. Solder the capacitor to the testing jig (glass epoxy board) shown Then apply a force in the direction shown in Fig. 3. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 20 50 Pressurizing speed: 1.0mm/s Deflection 12 Pressurize Dimension (mm) L×W (mm) а b С d 4.5X2.0 3.5 7 0 24 Flexure=1 1.0 4.5X3.2 3.5 7.0 3.7 Capacitance mete Fig. 2 (in mm) Fig. 3 Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Solderability of Immerse in solder solution for 2±0.5 sec. 75% of the terminations are to be soldered evenly and continuously. Termination Immersing speed: 25±2.5mm/s Temp. of solder: 245±5°C Lead Free Solder (Sn-3.0Ag-0.5Cu) 235±5°C H60A or H63A Eutectic Solder No marking defects Appearance Preheat the capacitor as table. Immerse the capacitor in solder solution at 260±5℃ for 10±1 Capacitance Within ±10% sec. Let sit at room condition* for 24±2 hrs., then measure. Change •Immersing speed: 25±2.5mm/s 0.025 max. D.F Pretreatment Perform a heat treatment at 150 ± 100 °C for 60±5 min. and then Resistance I.R More than $1,000M\Omega$ to Soldering let sit for 24±2 hrs. at room condition*. Heat *Preheating Dielectric In accordance with item No.4 Step Temperature Time Strength 100 to 120℃ 1 min 170 to 200℃ 2 1 min Appearance No marking defects Fix the capacitor to the supporting jig (glass epoxy board) shown in Fig. 4. Capacitance Perform the 5 cycles according to the 4 heat treatments listed in Within ±15% Change the following table D.F. 0.05 max. Let sit for 24±2 hrs. at room condition*, then measure. Temperature (°C) Time (min.) Step I.R. More than $3,000M\Omega$ Min. Operating Temp.±3 30±3 2 Room Temp. 2 to 3 3 Max. Operating Temp.±2 30 ± 3 4 Room Temp. 2 to 3 Temperature 15 Pretreatment Cycle Perform a heat treatment at 150±10 °C for 60±5 min. and then let sit for 24±2 hrs. at room condition*. Dielectric In accordance with item No.4 Strength *m* m m Cu Glass Epoxy Board Fig. 4 Appearance No marking defects Let the capacitor sit at 40±2℃ and relative humidity of 90 to 95% Capacitance for 500 ±24 hrs. Within +15% Change Humidity Remove and let sit for 24±2 hrs. at room condition*, then (Steady D.F. 0.05 max measure 16 Pretreatment State) I.R. More than $1,000M\Omega$ Perform a heat treatment at 150⁺₁₀ °C for 60±5 min. and then Dielectric let sit for 24±2 hrs. at room condition*.

In accordance with item No.4

Strength



^{* &}quot;Room condition" Temperature: 15 to 35℃, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa

Continued from the preceding page.

No.	. Item		Specifications	Test Method		
		Appearance	No marking defects			
		Capacitance Change	Within ±20%	Apply 110% of the rated voltage for 1,000 ±48 hrs. at maximum operating temperature ±3°C. Remove and let sit for 24 ±2 hrs. at room condition*, then measure.		
17	Life	D.F.	0.05 max.	The charge/discharge current is less than 50mA.		
		I.R.	More than $2,000M\Omega$	Pretreatment Apply test voltage for 60±5 min. at test temperature.		
		Dielectric Strength	In accordance with item No.4	Remove and let sit for 24±2 hrs. at room condition*.		

^{* &}quot;Room condition" Temperature: 15 to 35℃, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa

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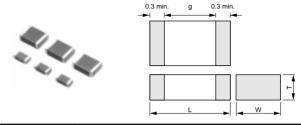
Only for Camera Flash Circuit

■ Features

- 1. Suitable for the trigger of the flash circuit, because real capacitance is stable during operating voltage
- 2. The thin type fit for thinner camera.
- 3. Sn-plated external electrodes realizes good solderability.
- 4. For flow and reflow soldering

■ Applications

For strobe circuit



Don't Number	Dimensions (mm)							
Part Number	L	L W T		g min.				
GR731A			1.0 +0, -0.3					
GR731B	3.2 ±0.2	1.6 ±0.2	1.25 +0, -0.3	1.2				
GR731C			1.6 ±0.2					

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GR731AW0BB103KW01D	DC350	-	10000 ±10%	3.2	1.6	1.0	1.2	0.3 min.
GR731AW0BB153KW01D	DC350	-	15000 ±10%	3.2	1.6	1.0	1.2	0.3 min.
GR731BW0BB223KW01L	DC350	-	22000 ±10%	3.2	1.6	1.25	1.2	0.3 min.
GR731BW0BB333KW01L	DC350	-	33000 ±10%	3.2	1.6	1.25	1.2	0.3 min.
GR731CW0BB473KW03L	DC350	-	47000 ±10%	3.2	1.6	1.6	1.2	0.3 min.

07.2.6

Specifications and Test Methods

Ite	em	Specifications	Test Method		
Operating Temperatu	ıre Range	-55 to +125℃	-		
Appearan	ice	No defects or abnormalities	Visual inspection		
Dimensio	ns	Within the specified dimensions	Using calipers		
		No defects or abnormalities	No failure should be observed when DC500V is applied between the terminations for 1 to 5 sec., provided the charge/discharge current is less than 50mA.		
Insulation F (I.R.)	Resistance	C≥0.01μF: More than $100M\Omega \bullet \mu F$ C<0.01μF: More than $10,000M\Omega$	The insulation resistance should be measured with DC250±50V and within 60±5 sec. of charging.		
Capacitar	nce	Within the specified tolerance			
		0.025 max.	The capacitance/D.F. should be measured at a frequency of 1±0.2kHz and a voltage of AC1±0.2V(r.m.s.)		
			The capacitance measurement should be made at each step specified in Table.		
Capacitance B Temperature Characteristics		Cap. Change Within ±10% (Apply DC350V bias) Within ±3중 % (No DC bias) (Temp. Range : -55 to +125℃)	Step Temperature (°C) 1 25±2 2 Min. Operating Temp.±3 3 25±2 4 Max. Operating Temp.±2 5 25±2 •Pretreatment		
			Perform a heat treatment at 150^{+0}_{-10} °C for 60 ± 5 min. and then let sit for 24 ± 2 hrs. at room condition*.		
Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 1. Then apply 10N force in the direction of the arrow. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 10N, 10±1s Glass Epoxy Board Fig. 1		
	Annearance	No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board).		
			The capacitor should be subjected to a simple harmonic motion		
Vibration Resistance	D.F.	0.025 max.	having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 min. This motion should be applied for a period of 2 hrs. in each of 3 mutually perpendicular directions (total of 6 hrs.). Solder resist Glass Epoxy Board		
	Operating Temperature Appearant Dimension Dielectricon Insulation F (I.R.) Capacitan Dissipatic Factor (Dielectricon Capacitan Temperature Character Adhesive of Termin Vibration	Temperature Range Appearance Dimensions Dielectric Strength Insulation Resistance (I.R.) Capacitance Dissipation Factor (D.F.) Capacitance Temperature Characteristics Adhesive Strength of Termination Appearance Capacitance Capacitance Characteristics	Operating Temperature Range −55 to +125℃ Appearance No defects or abnormalities Dimensions Within the specified dimensions Dielectric Strength No defects or abnormalities Insulation Resistance (I,R) C≥0.01μF: More than 100MΩ • μF C<0.01μF: More than 10,000MΩ		

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa



Continued from the preceding page.

7	Continued from the preceding page.									
No.	Ite	em	Specifications		Test Method					
11	11 Deflection		b 64.5		Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 2. Then apply a force in the direction shown in Fig. 3. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 20 50 Pressurizing speed: 1.0mm/s Pressurize Pressurize (in mm) Fig. 3					
12	Solderab Terminati		75% of the terminations are to be soldered evenly and continuously.	Immerse the capacitor in a solution of ethanol (JIS-K-rosin (JIS-K-5902) (25% rosin in weight proportion). Immerse in solder solution for 2±0.5 sec. Immersing speed: 25±2.5mm/s Temp. of solder: 245±5°C Lead Free Solder (Sn-3.0/235±5°C H60A or H63A Eutectic So						
		Appearance	No marking defects							
	Desistance	Capacitance Change	Within ±10%	Preheat the capacitor at 120 to 150°C* for 1 min. Immerse the capacitor in solder solution at 260±5°C for 10±1						
13	Resistance to Soldering Heat	D.F.	0.025 max.		sec. Let sit at room condition* for 24±2 hrs., then measure. •Immersing speed: 25±2.5mm/s •Pretreatment Perform a heat treatment at 150± ₁ 8°C for 60±5 min. and then let sit for 24±2 hrs. at room condition*.					
		I.R.	C≥0.01μF: More than $100MΩ • μF$ $C<0.01μF$: More than $10,000MΩ$	Perform a he						
		Dielectric Strength	In accordance with item No.4	16t Sit 101 24	LZ IIIS. At 100III COIIdiiloII .					
		Appearance	No marking defects	Fix the capacitor to the supporting jig (glass epoxy board) shown in Fig. 4. Perform the 5 cycles according to the 4 heat treatments listed in the following table.						
		Capacitance Change	Within ±7.5%							
		D.F.	0.025 max.	_	±2 hrs. at room condition*, the					
		I.R.	C≥0.01μF: More than 100MΩ • μF C<0.01μF: More than 10,000MΩ	Step 1	Temperature (℃) Min. Operating Temp.±3	Time (min.) 30±3				
			C<0.01μF. INIOTE trial 10,000IVIS2	2	Room Temp.	2 to 3				
				3 4	Max. Operating Temp.±2	30±3				
14	Temperature Cycle	·		Pretreatmer Perform a he	eat treatment at 150± ₁₈ °C for the base of the base o	2 to 3 60±5 min. and then				
		Appearance	No marking defects		3					
		Capacitance Change	Within ±15%	Let the capace for 500 \pm ² ⁴ h	itor sit at 40±2℃ and relative rs.	humidity of 90 to 95%				
15	Humidity	D.F.	0.05 max.		let sit for 24±2 hrs. at room o	ondition*, then				
15	(Steady State)	I.R.	C≥0.01μF: More than 10MΩ • μF C<0.01μF: More than 1,000MΩ	measure.PretreatmerPerform a he	nt eat treatment at 150±₁8°C fo	60±5 min. and then				
		Dielectric Strength	In accordance with item No.4	let sit for 24±2 hrs. at room condition*.						

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa



Continued from the preceding page.

No.	Ite	em	Specifications	Test Method			
		Appearance	No marking defects				
		Capacitance Change	Within ±15%	Apply DC350V for 1,000 ± 48 hrs. at maximum operating temperature ±3°C. Remove and let sit for 24 ±2 hrs. at room			
16	Life	D.F.	0.05 max.	condition*, then measure. The charge/discharge current is less than 50mA.			
	Liio	I.R.	C≥0.01μF: More than 10M Ω • μF C<0.01μF: More than 1,000M Ω	Pretreatment Apply test voltage for 60±5 min. at test temperature.			
		Dielectric Strength	In accordance with item No.4	Remove and let sit for 24±2 hrs. at room condition*.			
		Appearance	No marking defects				
		Capacitance Change	Within ±15%	Apply the rated voltage at $40\pm2^{\circ}$ C and relative humidity of 90 to 95% for $500\pm^{24}$ hrs.			
17	Humidity	D.F.	0.05 max.	Remove and let sit for 24±2 hrs. at room condition*, then measure.			
.,	Loading	I.R.	C≥0.01μF: More than 10M Ω • μF C<0.01μF: More than 1,000M Ω	Pretreatment Apply test voltage for 60±5 min. at test temperature.			
		Dielectric Strength	In accordance with item No.4	Remove and let sit for 24±2 hrs. at room condition*.			

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa



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Chip Monolithic Ceramic Capacitors



AC250V (r.m.s.) Type (Which Meet Japanese Law)

■ Features

- 1. Chip monolithic ceramic capacitor for AC lines
- A new monolithic structure for small, high capacitance capable of operating at high voltage levels
- 3. Sn-plated external electrodes realizes good solderability.
- 4. Only for reflow soldering
- 5. Capacitance 0.01 to 0.1uF for connecting lines and 470 to 4700pF for connecting lines to earth

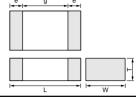
■ Applications

Noise suppression filters for switching power supplies, telephones, facsimiles, modems

■ Reference standard

GA2 series obtains no safety approval. This series is based on JIS C 5102, JIS C 5150, and the standards of the electrical appliance and material safety law of Japan (separated table 4).





			-	••				
Part Number	Dimensions (mm)							
Part Number	L	W	Т	e min.	g min.			
GA242Q	4.5 ±0.3	2.0 ±0.2	1.5 +0, -0.3		2.5			
GA243D	4.5 ±0.4	3.2 ±0.3	2.0 +0, -0.3	0.3				
GA243Q	4.5 ±0.4		1.5 +0, -0.3	0.3				
GA255D	5.7 ±0.4	5.0 ±0.4	2.0 +0, -0.3		3.2			

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GA242QR7E2471MW01L	AC250 (r.m.s.)	X7R (EIA)	470pF ±20%	4.5	2.0	1.5	2.5	0.3 min.
GA242QR7E2102MW01L	AC250 (r.m.s.)	X7R (EIA)	1000pF ±20%	4.5	2.0	1.5	2.5	0.3 min.
GA243QR7E2222MW01L	AC250 (r.m.s.)	X7R (EIA)	2200pF ±20%	4.5	3.2	1.5	2.5	0.3 min.
GA243QR7E2332MW01L	AC250 (r.m.s.)	X7R (EIA)	3300pF ±20%	4.5	3.2	1.5	2.5	0.3 min.
GA243DR7E2472MW01L	AC250 (r.m.s.)	X7R (EIA)	4700pF ±20%	4.5	3.2	2.0	2.5	0.3 min.
GA243QR7E2103MW01L	AC250 (r.m.s.)	X7R (EIA)	10000pF ±20%	4.5	3.2	1.5	2.5	0.3 min.
GA243QR7E2223MW01L	AC250 (r.m.s.)	X7R (EIA)	22000pF ±20%	4.5	3.2	1.5	2.5	0.3 min.
GA243DR7E2473MW01L	AC250 (r.m.s.)	X7R (EIA)	47000pF ±20%	4.5	3.2	2.0	2.5	0.3 min.
GA255DR7E2104MW01L	AC250 (r.m.s.)	X7R (EIA)	0.10μF ±20%	5.7	5.0	2.0	3.2	0.3 min.

No.	Ite	m	Specifications	Test Method
1	Operating Temperatu	re Range	−55 to +125°C	-
2	Appearan	ce	No defects or abnormalities	Visual inspection
3	Dimensio	ns	Within the specified dimensions	Using calipers
4	Dielectric	Strength	No defects or abnormalities	No failure should be observed when voltage in table is applied between the terminations for 60±1 sec., provided the charge/discharge current is less than 50mA. Nominal Capacitance Test voltage C≥10,000pF AC575V (r.m.s.)
				C<10,000pF AC5/3V (r.m.s.)
5	Insulation F (I.R.)	Resistance	More than $2{,}000M\Omega$	The insulation resistance should be measured with DC500±50V and within 60±5 sec. of charging.
6	Capacitar	nce	Within the specified tolerance	The consistence /D F should be recovered at a frequency of
7	Dissipation Factor (D.		0.025 max.	The capacitance/D.F. should be measured at a frequency of 1±0.2kHz and a voltage of AC1±0.2V (r.m.s.)
8	Capacitar Temperati Character	ure	Cap. Change Within ±15% (Temp. Range: −55 to +125°C)	The capacitance measurement should be made at each step specified in Table. Step Temperature (°C) 1 25±2 2 Min. Operating Temp.±3 3 25±2 4 Max. Operating Temp.±2 5 25±2 • Pretreatment Perform a heat treatment at 150±10 °C for 60±5 min. and then let sit for 24±2 hrs. at room condition*.
9	Discharge Test (Application: Nominal Capacitance C<10,000pF)	Appearance	No defects or abnormalities	As in Fig., discharge is made 50 times at 5 sec. intervals from the capacitor (Cd) charged at DC voltage of specified. R3 R1 Ct: Capacitor under test Cd: 0.001μF R1: 1,000Ω R2: 100MΩ R3: Surge resistance
10	Adhesive Strength of Termination		No removal of the terminations or other defects should occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 1. Then apply 10N force in the direction of the arrow. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Glass Epoxy Board Fig. 1
		Appearance	No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board).
		Capacitance	Within the specified tolerance	The capacitor should be subjected to a simple harmonic motion
11	Vibration Resistance	DE	0.025 may	having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 min. This motion should be applied for a period of 2 hrs. in each of 3 mutually perpendicular directions (total of 6 hrs.).
		D.F.	0.025 max.	Solder resist Glass Epoxy Board

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa



Continued from the preceding page Specifications No Item Test Method Solder the capacitor to the testing jig (glass epoxy board) shown No cracking or marking defects should occur. Then apply a force in the direction shown in Fig. 3. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 20 50 Pressurizing ↓ Pressurize Deflection t · 16 100 Flexure=1 Dimension (mm) LXW (mm) d Capacitance meter а С 4.5×2.0 3.5 7.0 (in mm) 4.5X3.2 3.5 7.0 3.7 1.0 Fig. 3 5.7×5.0 4.5 8.0 5.6 Fig. 2 Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Solderability of Immerse in solder solution for 2±0.5 sec. 75% of the terminations are to be soldered evenly and continuously. Immersing speed: 25±2.5mm/s Termination Temp. of solder: 245±5°C Lead Free Solder (Sn-3.0Ag-0.5Cu) 235±5°C H60A or H63A Eutectic Solder No marking defects Appearance Capacitance Within ±15% Change The capacitor should be subjected to 40±2℃, relative humidity of Humidity D.F. 0.05 max. 90 to 98% for 8 hrs., and then removed in room condition* for 16 Insulation hrs. until 5 cycles. More than $1,000M\Omega$ I.R. Dielectric In accordance with item No.4 Strength Appearance No marking defects Preheat the capacitor as table. Immerse the capacitor in solder solution at 260±5℃ for 10±1 Capacitance Within ±10% sec. Let sit at room condition* for 24±2 hrs., then measure. Change •Immersing speed: 25±2.5mm/s 0.025 max. D.F Pretreatment Resistance I.R. More than $2,000M\Omega$ Perform a heat treatment at 150 ± 10 °C for 60±5 min. and then to Soldering 15 let sit for 24±2 hrs. at room condition*. Heat *Preheating Dielectric Step In accordance with item No.4 Temperature Time Strength 100 to 120℃ 1 min 2 170 to 200℃ 1 min. Fix the capacitor to the supporting jig (glass epoxy board) shown No marking defects Appearance in Fig. 4. Capacitance Within ±15% Perform the 5 cycles according to the 4 heat treatments listed in Change the following table. D.F. 0.05 max. Let sit for 24±2 hrs. at room condition*, then measure. Temperature (°C) Time (min.) I.R. More than $2,000M\Omega$ Step Min. Operating Temp.±3 30±3 2 Room Temp. 2 to 3 3 Max. Operating Temp.±2 30 ± 3 4 Room Temp. 2 to 3 Temperature 16 Cycle Pretreatment Perform a heat treatment at 150⁺₁₀ °C for 60±5 min. and then let sit for 24±2 hrs. at room condition*. Dielectric In accordance with item No.4 Strength *m m m*

Continued on the following page.

Glass Epoxy Board Fig. 4



^{* &}quot;Room condition" Temperature: 15 to 35℃, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa

Continued from the preceding page.

No.	Ite	em	Specifications	Test Method
		Appearance	No marking defects	
	Humidity	Capacitance Change	Within ±15%	Let the capacitor sit at 40±2°C and relative humidity of 90 to 95% for 500±2°d hrs. Remove and let sit for 24±2 hrs. at room condition*, then
17	(Steady	D.F.	0.05 max.	measure.
	State)	I.R.	More than 1,000M Ω	Perform a heat treatment at 150 ± 18 ℃ for 60±5 min. and then
		Dielectric Strength	In accordance with item No.4	let sit for 24±2 hrs. at room condition*.
		Appearance	No marking defects	Apply voltage and time as Table at 85±2°C. Remove and let sit
		Capacitance Change	Within ±20%	for 24 ±2 hrs. at room condition*, then measure. The charge / discharge current is less than 50mA.
		D.F.	0.05 max.	Nominal Capacitance Test Time Test voltage C≥10,000pF 1,000±48 hrs. AC300V (r.m.s.)
18	Life	I.R.	More than 1,000MΩ	C<10,000pF 1,500 ⁺⁴⁸ _o hrs. AC500V (r.m.s.) *
		Dielectric Strength	In accordance with item No.4	 * Except that once each hour the voltage is increased to AC1,000V (r.m.s.) for 0.1 sec. •Pretreatment Apply test voltage for 60±5 min. at test temperature. Remove and let sit for 24±2 hrs. at room condition*.
		Appearance	No marking defects	
		Capacitance Change	Within ±15%	Apply the rated voltage at 40±2°C and relative humidity of 90 to 95% for 500±26 hrs. Remove and let sit for 24±2 hrs. at room condition*, then
19	Humidity Loading	D.F.	0.05 max.	measure.
	Loading	I.R.	More than 1,000M Ω	Pretreatment Apply test voltage for 60±5 min. at test temperature.
		Dielectric Strength	In accordance with item No.4	Remove and let sit for 24±2 hrs. at room condition*.

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa

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Chip Monolithic Ceramic Capacitors



Safety Standard Recognized Type GC (UL, IEC60384-14 Class X1/Y2)

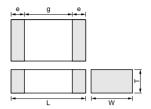
■ Features

- Chip monolithic ceramic capacitor (certified as conforming to safety standards) for AC lines
- A new monolithic structure for small, high capacitance capable of operating at high voltage levels
- 3. Compared to lead type capacitors, this new capacitor is greatly downsized and low-profiled to 1/10 or less in volume, and 1/4 or less in height.
- 4. The type GC can be used as an X1-class and Y2-class capacitor, line-by-pass capacitor of UL1414.
- 5. +125 degree C guaranteed
- 6. Only for reflow soldering

■ Applications

- Ideal for use as Y capacitor or X capacitor for various switching power supplies
- 2. Ideal for modem applications





Part Number	Dimensions (mm)							
Part Number	L	W	Т	e min.	g min.			
GA355D	5.7 ±0.4	5.0 ±0.4	2.0 ±0.3	0.3	4.0			

■ Standard Recognition

	Standard No.	Status of R	Rated	
	Standard No.	Type GB	Type GC	Voltage
UL	UL1414	_	0*	
BSI		_	0	
VDE	EN132400	0	0	AC250V
SEV	EN132400	0	0	(r.m.s.)
SEMKO		0	0	
EN132400 Class		X2	X1, Y2	

*: Line By-pass only

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GA355DR7GC101KY02L	AC250 (r.m.s.)	X7R (EIA)	100 ±10%	5.7	5.0	2.0	4.0	0.3 min.
GA355DR7GC151KY02L	AC250 (r.m.s.)	X7R (EIA)	150 ±10%	5.7	5.0	2.0	4.0	0.3 min.
GA355DR7GC221KY02L	AC250 (r.m.s.)	X7R (EIA)	220 ±10%	5.7	5.0	2.0	4.0	0.3 min.
GA355DR7GC331KY02L	AC250 (r.m.s.)	X7R (EIA)	330 ±10%	5.7	5.0	2.0	4.0	0.3 min.



Safety Standard Recognized Type GD (IEC60384-14 Class Y3)

■ Features

- Available for equipment based on IEC/EN60950 and UL1950
- 2. The type GD can be used as a Y3-class capacitor.
- A new monolithic structure for small, high capacitance capable of operating at high voltage levels
- 4. +125 degree C guaranteed
- 5. Only for reflow soldering
- 6. The low-profile type (thickness: 1.5mm max.) is available. Fit for use on thinner type equipment.

Applications

- Ideal for use on line filters and couplings for DAA modems without transformers
- 2. Ideal for use on line filters for information equipment





Part Number	Dimensions (mm)								
Part Number	L	W	T	e min.	g min.				
GA342A			1.0 +0, -0.3						
GA342D	4.5 ±0.3	2.0 ±0.2	2.0 ±0.3	0.3	2.5				
GA342Q			1.5 +0, -0.3						
GA343D	4.5 ±0.4	3.2 ±0.3	2.0 +0, -0.3						
GA343Q	4.5 ±0.4	3.∠ ±0.3	1.5 +0, -0.3						

■ Standard Recognition

	Standard	Class	Status of Recognition	Rated
	No.	Class	Type GD	Voltage
SEMKO	EN132400	Y3	0	AC250V(r.m.s.)

Applications

Size	Switching power supplies	Communication network devices such as a modem	
4.5×3.2mm and under	ı	0	

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GA342D1XGD100JY02L	AC250 (r.m.s.)	SL (JIS)	10 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342D1XGD120JY02L	AC250 (r.m.s.)	SL (JIS)	12 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342D1XGD150JY02L	AC250 (r.m.s.)	SL (JIS)	15 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342D1XGD180JY02L	AC250 (r.m.s.)	SL (JIS)	18 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342D1XGD220JY02L	AC250 (r.m.s.)	SL (JIS)	22 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342A1XGD270JW31L	AC250 (r.m.s.)	SL (JIS)	27 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGD330JW31L	AC250 (r.m.s.)	SL (JIS)	33 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGD390JW31L	AC250 (r.m.s.)	SL (JIS)	39 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGD470JW31L	AC250 (r.m.s.)	SL (JIS)	47 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGD560JW31L	AC250 (r.m.s.)	SL (JIS)	56 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGD680JW31L	AC250 (r.m.s.)	SL (JIS)	68 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGD820JW31L	AC250 (r.m.s.)	SL (JIS)	82 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342QR7GD101KW01L	AC250 (r.m.s.)	X7R (EIA)	100 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA342QR7GD151KW01L	AC250 (r.m.s.)	X7R (EIA)	150 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA342QR7GD221KW01L	AC250 (r.m.s.)	X7R (EIA)	220 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA342QR7GD331KW01L	AC250 (r.m.s.)	X7R (EIA)	330 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA342QR7GD471KW01L	AC250 (r.m.s.)	X7R (EIA)	470 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA342QR7GD681KW01L	AC250 (r.m.s.)	X7R (EIA)	680 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA342QR7GD102KW01L	AC250 (r.m.s.)	X7R (EIA)	1000 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA342QR7GD152KW01L	AC250 (r.m.s.)	X7R (EIA)	1500 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA343QR7GD182KW01L	AC250 (r.m.s.)	X7R (EIA)	1800 ±10%	4.5	3.2	1.5	2.5	0.3 min.
GA343QR7GD222KW01L	AC250 (r.m.s.)	X7R (EIA)	2200 ±10%	4.5	3.2	1.5	2.5	0.3 min.
GA343DR7GD472KW01L	AC250 (r.m.s.)	X7R (EIA)	4700 ±10%	4.5	3.2	2.0	2.5	0.3 min.



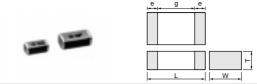
Safety Standard Recognized Type GF (IEC60384-14 Class Y2, X1/Y2)

■ Features

- 1. Available for equipment based on IEC/EN60950 and UL1950. Besides, the GA352/355 types are available for equipment based on IEC/EN60065, UL1492, and UL6500
- 2. The type GF can be used as a Y2-class capacitor.
- 3. A new monolithic structure for small, high capacitance capable of operating at high voltage levels
- 4. +125 degree C guaranteed
- 5. Only for reflow soldering
- 6. The low-profile type (thickness: 1.5mm max.) is available. Fit for use on thinner type equipment.

■ Applications

- 1. Ideal for use on line filters and couplings for DAA modems without transformers
- 2. Ideal for use on line filters for information equipment
- 3. Ideal for use as Y capacitor or X capacitor for various switching power supplies (GA352/355 types only)



Part Number	Dimensions (mm)					
Part Number	L	W	T	e min.	g min.	
GA342A			1.0 +0, -0.3	0.3		
GA342D	4.5 ±0.3	2.0 ±0.2	2.0 ±0.2*		2.5	
GA342Q	1		1.5 +0, -0.3			
GA352Q		2.8 ±0.3	1.5 +0, -0.3	0.3		
GA355D	5.7 ±0.4	5.0 ±0.4	2.0 +0, -0.3		4.0	
GA355Q		3.0 <u>1</u> 0.4	1.5 +0, -0.3			

^{*} GA342D1X: 2.0±0.3

■ Standard Recognition

			Status of R	ecognition	
	Standard	Class	Туре	Rated	
	No.		Size : 4.5×2.0mm	Size : 5.7×2.8mm and over	Voltage
UL	UL1414	X1, Y2	_	0	AC250V
SEMKO	EN132400	Y2	0	0	(r.m.s.)

Applications								
Size	Switching power supplies	Communication network devices such as a modem						
4.5×2.0mm	_	0						
5.7×2.8mm and over	0	0						

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GA342D1XGF100JY02L	AC250 (r.m.s.)	SL (JIS)	10 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342D1XGF120JY02L	AC250 (r.m.s.)	SL (JIS)	12 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342D1XGF150JY02L	AC250 (r.m.s.)	SL (JIS)	15 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342D1XGF180JY02L	AC250 (r.m.s.)	SL (JIS)	18 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342D1XGF220JY02L	AC250 (r.m.s.)	SL (JIS)	22 ±5%	4.5	2.0	2.0	2.5	0.3 min.
GA342A1XGF270JW31L	AC250 (r.m.s.)	SL (JIS)	27 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGF330JW31L	AC250 (r.m.s.)	SL (JIS)	33 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGF390JW31L	AC250 (r.m.s.)	SL (JIS)	39 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGF470JW31L	AC250 (r.m.s.)	SL (JIS)	47 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGF560JW31L	AC250 (r.m.s.)	SL (JIS)	56 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGF680JW31L	AC250 (r.m.s.)	SL (JIS)	68 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342A1XGF820JW31L	AC250 (r.m.s.)	SL (JIS)	82 ±5%	4.5	2.0	1.0	2.5	0.3 min.
GA342QR7GF101KW01L	AC250 (r.m.s.)	X7R (EIA)	100 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA342QR7GF151KW01L	AC250 (r.m.s.)	X7R (EIA)	150 ±10%	4.5	2.0	1.5	2.5	0.3 min.
GA342DR7GF221KW02L	AC250 (r.m.s.)	X7R (EIA)	220 ±10%	4.5	2.0	2.0	2.5	0.3 min.
GA342DR7GF331KW02L	AC250 (r.m.s.)	X7R (EIA)	330 ±10%	4.5	2.0	2.0	2.5	0.3 min.
GA352QR7GF471KW01L	AC250 (r.m.s.)	X7R (EIA)	470 ±10%	5.7	2.8	1.5	4.0	0.3 min.
GA352QR7GF681KW01L	AC250 (r.m.s.)	X7R (EIA)	680 ±10%	5.7	2.8	1.5	4.0	0.3 min.
GA352QR7GF102KW01L	AC250 (r.m.s.)	X7R (EIA)	1000 ±10%	5.7	2.8	1.5	4.0	0.3 min.
GA352QR7GF152KW01L	AC250 (r.m.s.)	X7R (EIA)	1500 ±10%	5.7	2.8	1.5	4.0	0.3 min.
GA355QR7GF182KW01L	AC250 (r.m.s.)	X7R (EIA)	1800 ±10%	5.7	5.0	1.5	4.0	0.3 min.
GA355QR7GF222KW01L	AC250 (r.m.s.)	X7R (EIA)	2200 ±10%	5.7	5.0	1.5	4.0	0.3 min.
GA355QR7GF332KW01L	AC250 (r.m.s.)	X7R (EIA)	3300 ±10%	5.7	5.0	1.5	4.0	0.3 min.
GA355DR7GF472KW01L	AC250 (r.m.s.)	X7R (EIA)	4700 ±10%	5.7	5.0	2.0	4.0	0.3 min.



Safety Standard Recognized Type GB (IEC60384-14 Class X2)

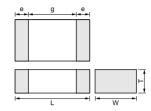
■ Features

- 1. The type GB can be used as an X2-class capacitor.
- 2. Chip monolithic ceramic capacitor (certified as conforming to safety standards) for AC lines
- 3. A new monolithic structure for small, high capacitance capable of operating at high voltage
- 4. Compared to lead type capacitors, this new capacitor is greatly downsized and low-profiled to 1/10 or less in volume, and 1/4 or less in height.
- 5. +125 degree C guaranteed
- 6. Only for reflow soldering

■ Applications

Ideal for use as X capacitor for various switching power supplies





Part Number	Dimensions (mm)					
Part Number	L	W	Т	e min.	g min.	
GA355D	5.7 ±0.4	5.0 ±0.4	2.0 ±0.3	0.3	4.0	
GA355X	3.7 ±0.4		2.7 ±0.3	0.3	4.0	

■ Standard Recognition

	Standard No.	Status of R	Status of Recognition		
	Standard No.	Type GB	Type GC	Voltage	
UL	UL1414	_	0*		
BSI		_	0		
VDE	EN132400	0	0	AC250V	
SEV	EN132400	0	0	(r.m.s.)	
SEMKO		0	0		
EN13240	0 Class	X2	X1, Y2		

^{*:} Line By-pass only

Part Number	Rated Voltage (V)	TC Code (Standard)	Capacitance (pF)	Length L (mm)	Width W (mm)	Thickness T (mm)	Electrode g min. (mm)	Electrode e (mm)
GA355DR7GB103KY02L	AC250 (r.m.s.)	X7R (EIA)	10000 ±10%	5.7	5.0	2.0	4.0	0.3 min.
GA355DR7GB153KY02L	AC250 (r.m.s.)	X7R (EIA)	15000 ±10%	5.7	5.0	2.0	4.0	0.3 min.
GA355DR7GB223KY02L	AC250 (r.m.s.)	X7R (EIA)	22000 ±10%	5.7	5.0	2.0	4.0	0.3 min.
GA355XR7GB333KY06L	AC250 (r.m.s.)	X7R (EIA)	33000 ±10%	5.7	5.0	2.7	4.0	0.3 min.

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No.	Ite	em	Specifications	Test Method
1	Operating Temperatu	ure Range	-55 to +125℃	_
2	Appearar	nce	No defects or abnormalities	Visual inspection
3	Dimensio	ns	Within the specified dimensions	Using calipers
4	Dielectric Strength		No defects or abnormalities	No failure should be observed when voltage in table is applied between the terminations for 60±1 sec., provided the charge/discharge current is less than 50mA. Test Voltage Type GB DC1075V Type GC/GD/GF AC1500V (r.m.s.)
5	Pulse Vol (Applicati GD/GF)	•	No self healing breakdowns or flash-overs have taken place in the capacitor.	10 impulse of alternating polarity is subjected. (5 impulse for each polarity) The interval between impulse is 60 sec. Applied Voltage: 2.5kV zero to peak
6	Insulation F (I.R.)	Resistance	More than $6{,}000M\Omega$	The insulation resistance should be measured with DC500±50V and within 60±5 sec. of charging.
7	Capacita	nce	Within the specified tolerance	
8	Dissipation Factor (D		Char. Specification X7R D.F.≤0.025 SL Q≥400+20C*² (C<30pF)	The capacitance/Q/D.F. should be measured at a frequency of 1±0.2kHz (SL char.: 1±0.2MHz) and a voltage of AC1±0.2V (r.m.s.).
9	Capacitar Temperat Character	ure	Char. Capacitance Change X7R Within ±15% Temperature characteristic guarantee is −55 to +125°C Char. Temperature Coefficient SL +350 to −1000ppm/°C Temperature characteristic guarantee is +20 to +85°C	The capacitance measurement should be made at each step specified in Table. Step Temperature (°C) 1 25±2 (20±2 for SL char.) 2 Min. Operating Temp.±3 3 25±2 (20±2 for SL char.) 4 Max. Operating Temp.±2 5 25±2 (20±2 for SL char.) SL char.: The capacitance should be measured at even 85°C between step 3 and step 4. • Pretreatment for X7R char. Perform a heat treatment at 150±10°C for 60±5 min. and then let sit for 24±2 hrs. at room condition*1.
		Appearance	No defects or abnormalities	As in Fig., discharge is made 50 times at 5 sec. intervals from
		I.R.	More than 1,000MΩ	the capacitor (Cd) charged at DC voltage of specified.
10	Discharge Test (Application: Type GC)	Dielectric Strength	In accordance with item No.4	R3 R1 TokV V Ct: Capacitor under test Cd: 0.001μF R1: 1,000Ω R2: 100ΜΩ R3: Surge resistance
11	1 Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 1. Then apply 10N force in the direction of the arrow. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.

^{*1 &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa



^{*2 &}quot;C" expresses nominal capacitance value (pF).

Continued from the preceding page

lo.	Ite	em	Specifications	Test Method		
		Appearance	No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board).		
		Capacitance	Within the specified tolerance	The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The		
12	Vibration Resistance	D.F. Q	Char. Specification X7R D.F.≤0.025 SL Q≥400+20C*² (C<30pF)	frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 min. This motion should be applied for a period of 2 hrs. in each of 3 mutually perpendicular directions (total of 6 hrs.).		
			No cracking or marking defects should occur.	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 2		
		b 04.5		in Fig. 2. Then apply a force in the direction shown in Fig. 3. The solderin should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.		
3	Deflection			Pressurizing speed: 1.0mm/s Pressurize Pressurize Flexure=1 Capacitance meter 45 (in mm)		
			Fig. 2	Fig. 3		
14	Solderab Terminati		75% of the terminations are to be soldered evenly and continuously.	Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Immerse in solder solution for 2±0.5 sec. Immersing speed: 25±2.5mm/s Temp. of solder: 245±5°C Lead Free Solder (Sn-3.0Ag-0.5Cu) 235±5°C H60A or H63A Eutectic Solder		
		Appearance	No marking defects	Preheat the capacitor as table. Immerse the capacitor in solder		
15	Resistance Change Change		Char. Capacitance Change X7R Within ±10% SL Within ±2.5% or ±0.25pF (Whichever is larger)	solution at 260±5°C for 10±1 sec. Let sit at room condition*¹ fo 24±2 hrs., then measure. •Immersing speed: 25±2.5mm/s •Pretreatment for X7R char. Perform a heat treatment at 150±18°C for 60±5 min. and then let sit for 24±2 hrs. at room condition*¹.		
	Heat	I.R.	More than 1,000M Ω			
				*Preheating		
		Dielectric	In accordance with item No.4	Step Temperature Time 1 100 to 120℃ 1 min.		

^{*1 &}quot;Room condition" Temperature: 15 to 35℃, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa



^{*2 &}quot;C" expresses nominal capacitance value (pF).

Continued from the preceding page. Specifications No Item Test Method Fix the capacitor to the supporting jig (glass epoxy board) shown Appearance No marking defects Perform the 5 cycles according to the 4 heat treatments listed in Char. Capacitance Change the following table Capacitance Within +15%

Charge St. Within ±2.5% or ±0.25pF (Whichever is larger)	the following table.				
1	n measure.				
16 Temperature Cycle Temperature Cycle Char Specification STR D.F. so. 0.5 S.L. Q≥400+20C° (C<30pF) Q≥400+	Time (min.)				
Temperature D.F. Char. Specification Strength D.F. Solution Strength State D.F. Solution Strength D.F. Solution Strength State D.F. Solution Strength State D.F. Solution State Strength State Strength State Strength State Strength State Strength State Strength Streng	30±3				
D.F. Char. Specification State)	2 to 3				
Temperature Q SL Q≥400+20° (C<30pF) Q≥1000 (C≥30pF) Q≥1000 (C≥30pF) Pretreatment for X7R char. Perform a heat treatment at 150°±,8° c for 60±5 min. and the let sit for 24±2 hrs. at room condition*. Pretreatment for X7R char. P					
Temperature Cycle S.L. Q≥1000 (C≥30pF)					
LR. More than 3,000MΩ Performe a heat treatment at 150±,3°c for 60±5 min. and the let sit for 24±2 hrs. at room condition*!.					
I.R. More than 3,000MΩ Iet sit for 24±2 hrs. at room condition**.					
Dielectric Strength In accordance with item No.4 Dielectric Strength	60±5 min. and the				
Dielectric Strength In accordance with item No.4 Solder resist Solde					
Appearance No marking defects Char. Capacitance Change X7R Within ±15% SL Within ±5.0% or ±0.5pF (Whichever is larger)	ler resist				
Char. Capacitance Change X7R Within ±15% St. Within ±5.0% or ±0.5pF (Whichever is larger)					
Capacitance Change X7R Within ±15% SL Within ±5.0% or ±0.5pF Within ±15.0% or ±0.5pF Within ±15.0% or ±0.5pF Within ±15% SL Whichever is larger D.F. X7R D.F.≤0.05 SL Q≥275+5/2C*² (C<30pF) Q≥350 (C≥30pF) I.R. More than 3,000MΩ Dielectric Strength Dielectric Strength Dielectric Strength Dielectric Strength Capacitance Change X7R Within ±20% Char. Capacitance Change X7R Within ±20% SL Within ±3.0% or ±0.3pF Within ±3.0% or ±0.3pF Char. Specification V7R D.F.≤0.05 D.F. Char. Specification V7R D.F.≤0.05 D.F. V7R D.F.≤0.05					
Capacitance Change X7R Within ±15% SL Within ±5.0% or ±0.5pF Within ±15.0% or ±0.5pF Within ±15.0% or ±0.5pF Within ±15% SL Whichever is larger D.F. X7R D.F.≤0.05 SL Q≥275+5/2C*² (C<30pF) Q≥350 (C≥30pF) I.R. More than 3,000MΩ Dielectric Strength Dielectric Strength Dielectric Strength Dielectric Strength Capacitance Change X7R Within ±20% Char. Capacitance Change X7R Within ±20% SL Within ±3.0% or ±0.3pF Within ±3.0% or ±0.3pF Char. Specification V7R D.F.≤0.05 D.F. Char. Specification V7R D.F.≤0.05 D.F. V7R D.F.≤0.05					
Humidity (Steady State) State D.F. Q ≥ 275+5/2C*² (C<30pF) Q≥275+5/2C*² (C<30pF) Q≥350 (C≥30pF) Q≥350 (C≥30pF	ing is performed				
Humidity (Steady State) D.F. Char. Specification SL Q≥275+5/2C*² (C<30pF) SL Q≥350 (C≥30pF) Steepth In accordance with item No.4					
Humidity (Steady State) D.F.	(466.00.00.00.00.00.00.00.00.00.00.00.00.0				
Char. Specification State St					
Char. Specification State St	humidity of 90 to 95				
State D.F. X7R D.F.≤0.05 Remove and let sit for 24±2 hrs. at room condition*¹, then measure.	,				
SL Q≥275+5/2C*² (C<30pF) I.R. More than 3,000MΩ Dielectric Strength Appearance No marking defects Capacitance Change X7R Within ±20% Change Change SL Within ±3.0% or ±0.3pF (Whichever is larger) Char. Specification	ondition*1, then				
Pretreatment for X7R char. Perform a heat treatment at 150±₁8 °C for 60±5 min. and the let sit for 24±2 hrs. at room condition**. Pretreatment for X7R char.					
I.R. More than 3,000MΩ let sit for 24±2 hrs. at room condition**.					
Dielectric Strength Appearance No marking defects Char. Capacitance Change Vitem 11 Adhesive Strength of Termination (apply force is 5N)	60±5 min. and the				
Strength Appearance No marking defects Capacitance Change Chan					
Strength Appearance No marking defects Capacitance Change Chan					
Appearance No marking defects Char. Capacitance Change X7R Within ±20% SL Whichever is larger) Char. Specification Char. Sp					
Char. Capacitance Change	ing is performed				
Capacitance Change X7R Within ±20% SL Within ±3.0% or ±0.3pF (Whichever is larger) Char. Specification Char. Specification Y7P D F < 0.05 Char. Capacitance Change X7R Within ±20% Impulse Voltage Each individual capacitor should be subjected to a 2.5kV (Type GC/GF: 5kV) Impulse (the voltage value means zero to	• .				
Capacitance Change $X7R$ Within $\pm 20\%$ SL Within $\pm 3.0\%$ or $\pm 0.3pF$ (Whichever is larger) Char. Specification YZP D D $= 5.005$ Char. Specification YZP D D $= 5.005$ Front time (T ₁)=1.2µs=1.677 Time to half-value (T ₂)=50µs Each individual capacitor should be subjected to a 2.5kV (Type GC/GF: 5kV) Impulse (the voltage value means zero to	,				
Change SL Within ±3.0% or ±0.3pF (Whichever is larger) Impulse Voltage Each individual capacitor should be subjected to a 2.5kV (Type GC/GF: 5kV) Impulse (the voltage value means zero to Char. Specification YZP D F ≤ 0.05					
Each individual capacitor should be subjected to a 2.5kV (Type GC/GF: 5kV) Impulse (the voltage value means zero to	to half-value (Ta)-50ue				
Char. Specification VZP D E < 0.05 Char. Specification VZP D E < 0.05	to παιι-ναία ε (12 <i>)</i> =50μS)				
Char. Specification VZP D E < 0.05 Char. Specification VZP D E < 0.05	1				
VOITage value means zero to					
	+				
peak) for the times. Then the	<u> </u>				
Capacitors are applied to life test					
O>275+5/2C*2 (C<30pE) peak) for three times. Then the)				

| Q≧350 (C≧30pF) Life

Apply voltage as Table for 1,000 hrs. at 125 ⁺² °C, relative humidity 50% max.

Type	Applied Voltage
GB	AC312.5V (r.m.s.), except that once each hour the voltage is increased to AC1,000V (r.m.s.) for 0.1 sec.
GC GD GF	AC425V (r.m.s.), except that once each hour the voltage is increased to AC1,000V (r.m.s.) for 0.1 sec.

Let sit for 24±2 hrs. at room condition*1, then measure.

•Pretreatment for X7R char.

Perform a heat treatment at 150±18 ℃ for 60±5 min. and then let sit for 24±2 hrs. at room condition*1.

I.R.

Dielectric

Strength

More than $3,000M\Omega$

In accordance with item No.4

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^{*1 &}quot;Room condition" Temperature: 15 to 35℃, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa

^{*2 &}quot;C" expresses nominal capacitance value (pF).

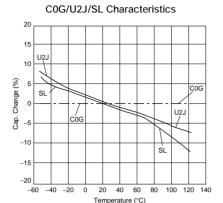
	Continued from the preceding page.					
No.	Item Specifications		Test Method			
	Appearance Capacitance Change	No marking defects Char. Capacitance Change X7R Within ±15% SL Within ±5.0% or ±0.5pF (Whichever is larger)	Before this test, the test shown in the following is performedItem 11 Adhesive Strength of Termination (apply force is 5N) -Item 13 Deflection			
19 Humidi Loadino		Char. Specification X7R D.F.≦0.05 SL Q≥275+5/2C*² (C<30pF)	Apply the rated voltage at 40±2°C and relative humidity of 90 to 95% for 500±2°6 hrs. Remove and let sit for 24±2 hrs. at room condition*¹, then measure. •Pretreatment for X7R char. Perform a heat treatment at 150±1°0°C for 60±5 min. and then			
	I.R.	More than $3{,}000M\Omega$	let sit for 24±2 hrs. at room condition**.			
	Dielectric Strength	In accordance with item No.4				
		The cheesecloth should not be on fire.	The capacitor should be individually wrapped in at least one but not more than two complete layers of cheesecloth. The capacitor should be subjected to 20 discharges. The interval between successive discharges should be 5 sec. The UAC should be maintained for 2 min. after the last discharge. C1,2: 1μF±10% C3: 0.033μF±5% 10kV L1 to 4: 1.5mH±20% 16A Rod core choke Ct: 3μF±5% 10kV Cx: Capacitor under test VAC: UR±5% F: Fuse, Rated 16A UR: Rated Voltage Ut: Voltage applied to Ct Type GB, GD 2.5kV GC, GF 5kV			
Passive Flammability		The burning time should not exceed 30 sec. The tissue paper should not ignite.	The capacitor under test should be held in the flame in the position which best promotes burning. Each specimen should only be exposed once to the flame. Time of exposure to flame: 30 sec. Length of flame: 12±1mm Gas burner : Length 35mm min. Inside Dia. 0.5±0.1mm Outside Dia. 0.9mm max. Gas : Butane gas Purity 95% min. Test Specimen Tissue About 10mm Thick Board			

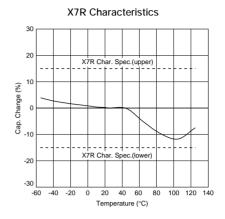
^{*1 &}quot;Room condition" Temperature: 15 to 35℃, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa

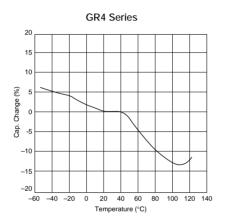
^{*2 &}quot;C" expresses nominal capacitance value (pF).

GRM/GR4/GR7/GA2/GA3 Series Data (Typical Example)

■ Capacitance - Temperature Characteristics

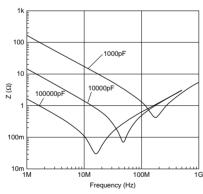




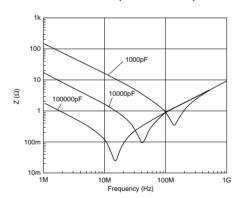


■ Impedance - Frequency Characteristics





GRM Series (X7R Char. 630V)



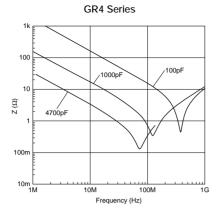


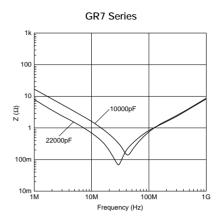


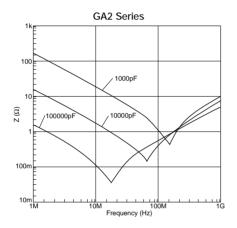
GRM/GR4/GR7/GA2/GA3 Series Data (Typical Example)

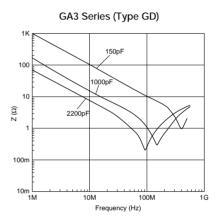
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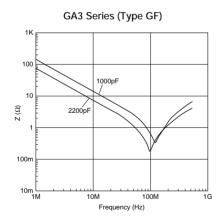
■ Impedance - Frequency Characteristics

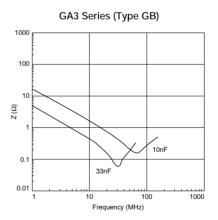










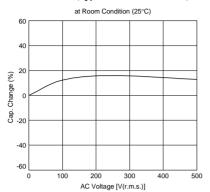


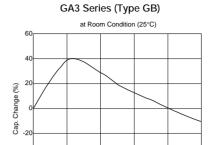
GRM/GR4/GR7/GA2/GA3 Series Data (Typical Example)

-60

■ Capacitance - AC Voltage Characteristics

GA3 Series (Type GD/GF, X7R char.)





AC Voltage [V(r.m.s.)]



Package

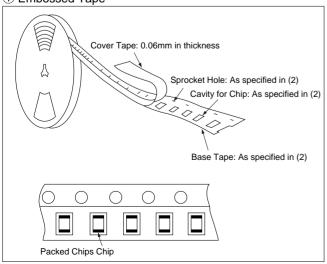
Taping is standard packaging method.

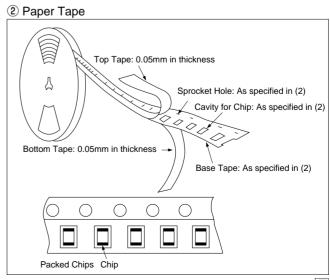
■ Minimum Quantity Guide

			Dimensions (mm	,	Quantity (pcs.)		
Part Nu	mber		Difficultions (min)		ø180mm Reel		
		L	W	T	Paper Tape	Embossed Tape	
	GRM18	1.6	0.8	0.8	4,000	-	
	GRM21	2.0	4.05	1.0	4,000	-	
	GRIVIZT	2.0	1.25	1.25	-	3,000	
				1.0	4,000	-	
	GRM31/GR731	3.2	1.6	1.25	-	3,000	
				1.6	-	2,000	
				1.0	4,000	-	
	GRM32	3.2		1.25	-	3,000	
ledium-voltage	GRIVISZ	ა.∠	2.5	1.5	-	2,000	
				2.0	-	1,000	
		4.5	2.0	1.0	-	3,000	
	GRM42/GR442			1.5	-	2,000	
				2.0	-	2,000	
			3.2	1.5	-	1,000	
	GRM43/GR443	4.5		2.0	-	1,000	
				2.5	-	500	
	GRM55/GR455	5.7	5.0	2.0	-	1,000	
	GA242	4.5	2.0	1.5	-	2,000	
A C 2 F O V	GA243	4.5	3.2	1.5	-	1,000	
AC250V				2.0	-	1,000	
	GA255	5.7	5.0	2.0	-	1,000	
				1.0	-	3,000	
	GA342	4.5 2.0	2.0	1.5	-	2,000	
				2.0	-	2,000	
Safety Std.	GA343	4.5	3.2	1.5	-	1,000	
Recognition	GA343	4.5	3.2	2.0	-	1,000	
	GA352	5.7	2.8	1.5	-	1,000	
				1.5	-	1,000	
	GA355	5.7	5.0	2.0	-	1,000	
				2.7	-	500	

■ Tape Carrier Packaging

- (1) Appearance of Taping
- ① Embossed Tape







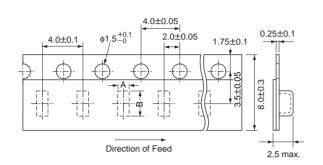
Package

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(2) Dimensions of Tape

① Embossed Tape

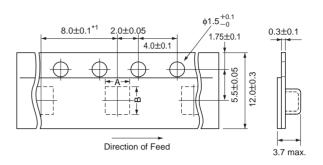
8mm width 4mm pitch Tape



Part Number	A*	B*
GRM21 (T≧1.25mm)	1.45	2.25
GRM31/GR731 (T≧1.25mm)	2.0	3.6
GRM32 (T≧1.25mm)	2.9	3.6

*Nominal Value

12mm width 8mm/4mm pitch Tape



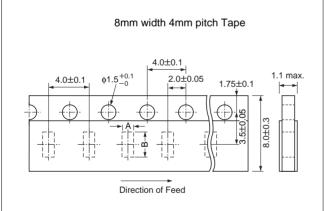
Part Number	A*	B*
GRM42/GR442/GA242/GA342	2.5	5.1
GRM43/GR443/GA243/GA343	3.6	4.9
GA352	3.2	6.1
GRM55/GR455/GA255/GA355	5.4	6.1

^{*1 4.0±0.1}mm in case of GRM42/GR442/GA242/GA342

*Nominal Value

(in mm)

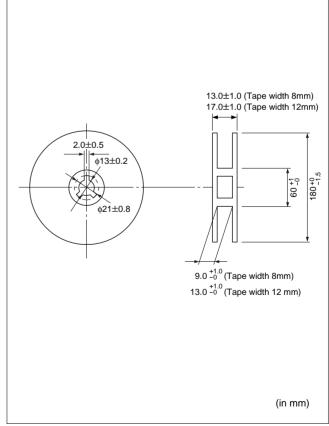
2 Paper Tape



Part Number	A*	B*
GRM18	1.05	1.85
GRM21 (T=1.0mm)	1.45	2.25
GRM31/GR731 (T=1.0mm)	2.0	3.6
GRM32 (T=1.0mm)	2.9	3.6

*Nominal value (in mm)

(3) Dimensions of Reel

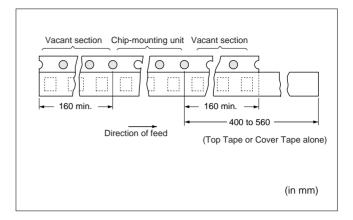


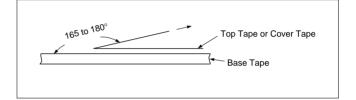
Package

Continued from the preceding page.

(4) Taping Method

- 1) Tapes for capacitors are wound clockwise. The sprocket holes are to the right as the tape is pulled toward the user.
- 2 Part of the leader and part of the empty tape should be attached to the end of the tape as shown at right.
- 3 The top tape or cover tape and base tape are not attached at the end of the tape for a minimum of 5 pitches.
- 4 Missing capacitors number within 0.1% of the number per reel or 1 pc, whichever is greater, and are not continuous.
- 5 The top tape or cover tape and bottom tape should not protrude beyond the edges of the tape and should not cover sprocket holes.
- 6 Cumulative tolerance of sprocket holes, 10 pitches:
- 7 Peeling off force: 0.1 to 0.6N in the direction shown at right.







■ Storage and Operating Conditions

Operating and storage environment
Do not use or store capacitors in a corrosive
atmosphere, especially where chloride gas, sulfide
gas, acid, alkali, salt or the like are present. And
avoid exposure to moisture. Before cleaning, bonding
or molding this product, verify that these processes
do not affect product quality by testing the
performance of a cleaned, bonded or molded product
in the intended equipment. Store the capacitors

where the temperature and relative humidity do not exceed 5 to 40 degrees centigrade and 20 to 70%. Use capacitors within 6 months after delivered. Check the solderability after 6 months or more.

FAILURE TO FOLLOW THE ABOVE CAUTIONS MAY RESULT, WORST CASE, IN A SHORT CIRCUIT AND CAUSE FUMING OR PARTIAL DISPERSION WHEN THE PRODUCT IS USED.

■ Handling

- Vibration and impact
 Do not expose a capacitor to excessive shock or vibration during use.
- Do not directly touch the chip capacitor, especially the ceramic body. Residue from hands/fingers may create a short circuit environment.

FAILURE TO FOLLOW THE ABOVE CAUTIONS MAY RESULT, WORST CASE, IN A SHORT CIRCUIT AND CAUSE FUMING OR PARTIAL DISPERSION WHEN THE PRODUCT IS USED.



⚠Caution

■ Caution (Rating)

1. Operating Voltage

When DC-rated capacitors are to be used in AC or ripple current circuits, be sure to maintain the Vp-p value of the applied voltage or the Vo-p which contains DC bias within the rated voltage range.

When the voltage is applied to the circuit, starting or stopping may generate irregular voltage for a transit period because of resonance or switching. Be sure to use a capacitor with a rated voltage range that includes these irregular voltages.

Voltage	DC Voltage	DC+AC Voltage	AC Voltage	Pulse Voltage (1)	Pulse Voltage (2)
Positional Measurement	V0-p	Vo-p	Vp-p	Vp-p	Vp-p

- 2. Operating Temperature, Self-generated Heat, and Lead Reduction at High-frequency voltage condition Keep the surface temperature of a capacitor below the upper limit of its rated operating temperature range. Be sure to take into account the heat generated by the capacitor itself. When the capacitor is used in a highfrequency voltage, pulse voltage, it may self-generate heat due to dielectric loss.
- (1) In case of X7R char.

Applied voltage should be the load such as selfgenerated heat is within 20°C on the condition of atmosphere temperature 25°C. When measuring, use a thermocouple of small thermal capacity -K of Ø0.1mm in conditions where the capacitor is not affected by radiant heat from other components or surrounding ambient fluctuations. Excessive heat may lead to deterioration of the capacitor's characteristics and reliability. (Never attempt to perform measurement with the cooling fan running. Otherwise, accurate measurement cannot be ensured.)





Continued from the preceding page.

(2) In case of C0G, U2J char.

Due to the low self-heating characteristics of lowdissipation capacitors, the allowable electric power of these capacitors is generally much higher than that of X7R characteristic capacitors.

When a high frequency voltage which cause 20°C self heating to the capacitor is applied, it will exceed capacitor's allowable electric power.

<C0G char.>

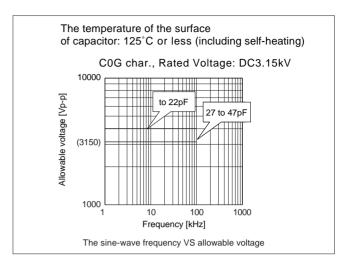
Therefore, in case of COG char., the frequency of the applied sine wave voltage should be less than 100kHz. The applied voltage should be less than the value shown in figure at right. The capacitors less than 22pF can be applied maximum 4.0kV peak to peak at 100kHz or less only for the ballast or the resonance usage in the LCD backlight inverter circuit.

<U2J char.>

In case of U2J char., the frequency of the applied sine wave voltage should be less than 500kHz (less than 100kHz in case of rated voltage: DC3.15kV). The applied voltage should be less than the value shown in figure below.

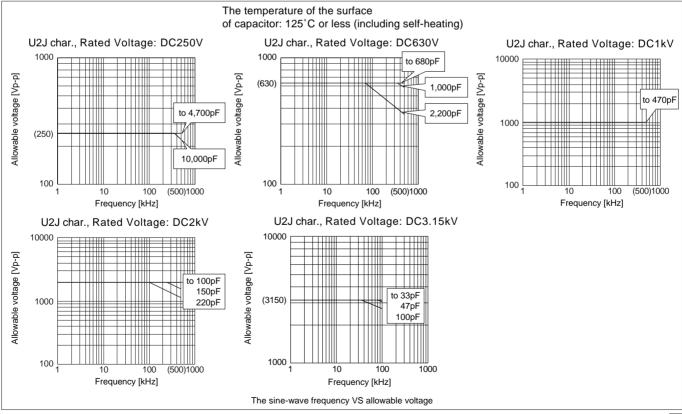
<Capacitor selection tool>

We are also offering free software the "capacitor selection tool: Murata Medium Voltage Capacitors Selection Tool by Voltage Form (*)" which will assist you in selecting a suitable capacitor.



The software can be downloaded from Murata's Internet Website (http://www.murata.com/designlib/mmcsv_e.html). By inputting capacitance values and applied voltage waveform of the specific capacitor series, this software will calculate the capacitor's power consumption and list suitable capacitors (non-sine wave is also available).

- * As of Jul. 2006, subject series are below.
- · Temperature Characteristics C0G, U2J

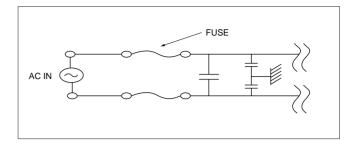


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3. Fail-safe

Failure of a capacitor may result in a short circuit. Be sure to provide an appropriate fail-safe function such as a fuse on your product to help eliminate possible electric shock, fire, or fumes.

Please consider using fuses on each AC line if the capacitors are used between the AC input lines and earth (line bypass capacitors), to prepare for the worst case, such as a short circuit.



4. Test condition for AC withstanding Voltage

(1) Test Equipment

Tests for AC withstanding voltage should be made with equipment capable of creating a wave similar to a 50/60 Hz sine wave.

If the distorted sine wave or overload exceeding the specified voltage value is applied, a defect may be caused.

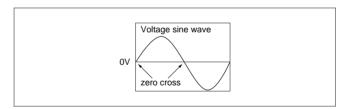
(2) Voltage applied method

The capacitor's leads or terminals should be firmly connected to the output of the withstanding voltage test equipment, and then the voltage should be raised from near zero to the test voltage. If the test voltage is applied directly to the capacitor without raising it from near zero, it should be applied with the zero cross*. At the end of the test time, the test voltage should be reduced to near zero, and then the capacitor's leads or terminals should be taken off the output of the withstanding voltage test equipment. If the test voltage is applied directly to the capacitor without raising it from near zero, surge voltage may occur and cause a defect.

*ZERO CROSS is the point where voltage sine wave pass 0V.

- See the figure at right -

FAILURE TO FOLLOW THE ABOVE CAUTIONS MAY RESULT, WORST CASE, IN A SHORT CIRCUIT AND CAUSE FUMING OR PARTIAL DISPERSION WHEN THE PRODUCT IS USED.



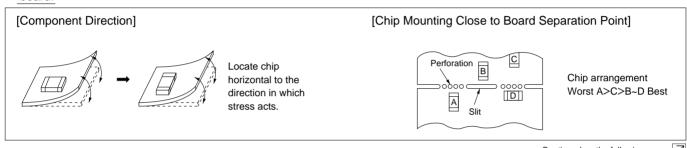
■ Caution (Soldering and Mounting)

1. Vibration and Impact Do not expose a capacitor to excessive shock or vibration during use.

2. Circuit Board Material

In case that ceramic chip capacitor is soldered on the metal board, such as Aluminum board, the stress of heat expansion and contraction might cause the crack of ceramic capacitor, due to the difference of thermal expansion coefficient between metal board and ceramic chip.

3. Land Layout for Cropping PC Board Choose a mounting position that minimizes the stress imposed on the chip during flexing or bending of the board.





Continued from the preceding page

4. Reflow Soldering

- When sudden heat is given to the components, the mechanical strength of the components should go down because remarkable temperature change causes deformity of components inside. In order to prevent mechanical damage in the components, preheating should be required for both of the components and the PCB board. Preheating conditions are shown in Table 1. It is required to keep temperature differential between the soldering and the components surface (ΔT) as small as
- Solderability of Tin plating termination chip might be deteriorated when low temperature soldering profile where peak solder temperature is below the Tin melting point is used. Please confirm the solderability of Tin plating termination chip before use.
- When components are immersed in solvent after mounting, be sure to maintain the temperature difference (ΔT) between the component and solvent within the range shown in the Table 1.

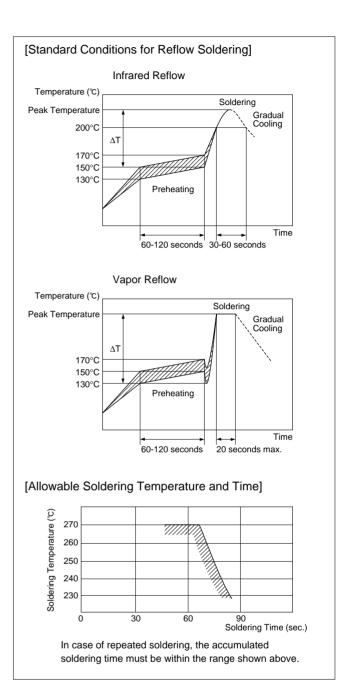
Table 1

Part Number	Temperature Differential	
G□□18/21/31	ΔΤ≦190℃	
G□□32/42/43/52/55	ΔΤ≦130℃	

Recommended Conditions

	Pb-Sn S		
	Infrared Reflow	Vapor Reflow	Lead Free Solder
Peak Temperature	230-250°C	230-240°C	240-260°C
Atmosphere	Air	Air	Air or N2

Pb-Sn Solder: Sn-37Pb Lead Free Solder: Sn-3.0Ag-0.5Cu

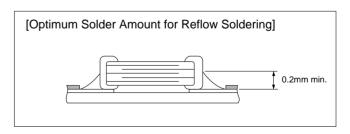


Optimum Solder Amount for Reflow Soldering

- Overly thick application of solder paste results in excessive fillet height solder.
 - This makes the chip more susceptible to mechanical and thermal stress on the board and may cause cracked
- Too little solder paste results in a lack of adhesive strength on the outer electrode, which may result in chips breaking loose from the PCB.
- Make sure the solder has been applied smoothly to the end surface to a height of 0.2mm min.

Inverting the PCB

Make sure not to impose an abnormal mechanical shock on the PCB.







Continued from the preceding page

5. Flow Soldering

- When sudden heat is given to the components, the mechanical strength of the components should go down because remarkable temperature change causes deformity of components inside. And an excessively long soldering time or high soldering temperature results in leaching by the outer electrodes, causing poor adhesion or a reduction in capacitance value due to loss of contact between electrodes and end termination.
- In order to prevent mechanical damage in the components, preheating should be required for both of the components and the PCB board. Preheating conditions are shown in Table 2. It is required to keep temperature differential between the soldering and the components surface (ΔT) as small as possible.
- When components are immersed in solvent after mounting, be sure to maintain the temperature difference between the component and solvent within the range shown in Table 2.

Do not apply flow soldering to chips not listed in Table 2.

Table 2

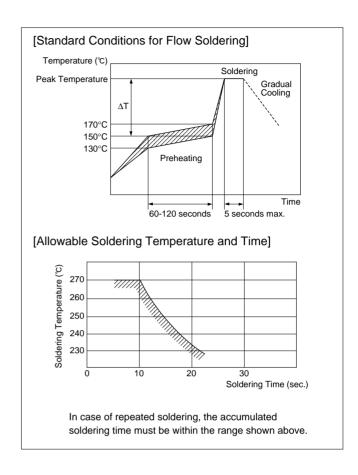
Part Number	Temperature Differential	
G□□18/21/31	ΔT≦150°C	

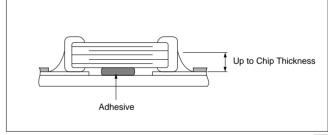
Recommended Conditions

	Pb-Sn Solder	Lead Free Solder
Peak Temperature	240-250°C	250-260°C
Atmosphere	Air	N ₂

Pb-Sn Solder: Sn-37Pb Lead Free Solder: Sn-3.0Ag-0.5Cu

 Optimum Solder Amount for Flow Soldering The top of the solder fillet should be lower than the thickness of components. If the solder amount is excessively big, the risk of cracking is higher during board bending or under any other stressful conditions.







Continued from the preceding page.

6. Correction with a Soldering Iron

(1) For Chip Type Capacitors

 When sudden heat is applied to the components by soldering iron, the mechanical strength of the components should go down because remarkable temperature change causes deformity of components inside. In order to prevent mechanical damage in the components, preheating should be required for both of the components and the PCB board. Preheating conditions are shown in Table 3. It is required to keep temperature differential between the soldering and the components surface (ΔT) as small as possible. After soldering, it should not be allowed to cool down rapidly.

Table 3

Part Number	Temperature Differential	Peak Temperature	Atmosphere
G□□18/21/31	ΔT≦190°C	300°C max. 3 sec. max. / termination (both sides total 6 sec. max.)	Air
G==32/42/43/ 52/55	ΔT≦130°C	270°C max. 3 sec. max. / termination (both sides total 6 sec. max.)	Air

^{*}Applicable for both Pb-Sn and Lead Free Solder.

Pb-Sn Solder: Sn-37Pb

Lead Free Solder: Sn-3.0Ag-0.5Cu

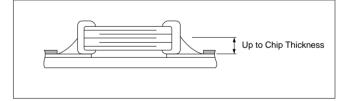
 Optimum Solder Amount when Corrections Are Made Using a Soldering Iron

The top of the solder fillet should be lower than the thickness of components. If the solder amount is excessively big, the risk of cracking is higher during board bending or under any other stressful conditions. Soldering iron ø3mm or smaller should be required. And it is necessary to keep a distance between the soldering iron and the components without direct touch. Thread solder with Ø0.5mm or smaller is required for soldering.



Excessive output of ultrasonic oscillation during cleaning causes PCBs to resonate, resulting in cracked chips or broken solder. Take note not to vibrate PCBs.

FAILURE TO FOLLOW THE ABOVE CAUTIONS MAY RESULT, WORST CASE, IN A SHORT CIRCUIT AND FUMING WHEN THE PRODUCT IS USED.



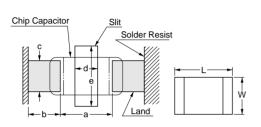
Notice

■ Notice (Soldering and Mounting)

1. Construction of Board Pattern

After installing chips, if solder is excessively applied to the circuit board, mechanical stress will cause destruction resistance characteristics to lower. To prevent this, be extremely careful in determining shape and dimension before designing the circuit board diagram.

Construction and Dimensions of Pattern (Example)



Preparing slit helps flux cleaning and resin coating on the back of the capacitor.

Flow Soldering

L×W	а	b	С
1.6×0.8	0.6-1.0	0.8-0.9	0.6-0.8
2.0×1.25	1.0-1.2	0.9-1.0	0.8-1.1
3.2×1.6	2.2-2.6	1.0-1.1	1.0-1.4

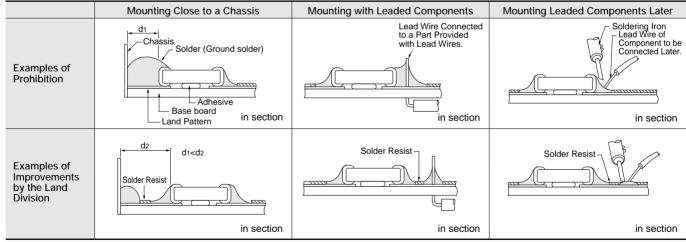
Flow soldering: 3.2×1.6 or less available.

Reflow Soldering

L×W	а	b	С	d	е
1.6×0.8	0.6-0.8	0.6-0.7	0.6-0.8	-	-
2.0×1.25	1.0-1.2	0.9-1.0	0.8-1.1	-	-
3.2×1.6	2.2-2.4	0.8-0.9	1.0-1.4	1.0-2.0	3.2-3.7
3.2×2.5	2.0-2.4	1.0-1.2	1.8-2.3	1.0-2.0	4.1-4.6
4.5×2.0	2.8-3.4	1.2-1.4	1.4-1.8	1.0-2.8	3.6-4.1
4.5×3.2	2.8-3.4	1.2-1.4	2.3-3.0	1.0-2.8	4.8-5.3
5.7×2.8	4.0-4.6	1.4-1.6	2.1-2.6	1.0-4.0	4.4-4.9
5.7×5.0	4.0-4.6	1.4-1.6	3.5-4.8	1.0-4.0	6.6-7.1

(in mm)

Land Layout to Prevent Excessive Solder







Notice



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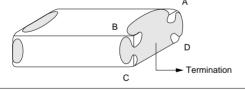
- 2. Mounting of Chips
- Thickness of adhesives applied Keep thickness of adhesives applied (50-105µm or more) to reinforce the adhesive contact considering the thickness of the termination or capacitor (20-70µm) and the land pattern (30-35µm).
- Mechanical shock of the chip placer When the positioning claws and pick-up nozzle are worn, the load is applied to the chip while positioning is concentrated in one position, thus causing cracks, breakage, faulty positioning accuracy, etc. Careful checking and maintenance are necessary to prevent unexpected trouble. An excessively low bottom dead point of the suction nozzle imposes great force on the chip during mounting, causing cracked chips. Please set the suction nozzle's bottom dead point on the upper surface of the board.

3. Soldering

(1) Limit of losing effective area of the terminations and conditions needed for soldering.

Depending on the conditions of the soldering temperature and/or immersion (melting time), effective areas may be lost in some part of the terminations.

To prevent this, be careful in soldering so that any possible loss of the effective area on the terminations will securely remain at a maximum of 25% on all edge length A-B-C-D-A of part with A, B, C, D, shown in the Figure below.



 Please use it after confirming there is no problem in the reliability of the product beforehand with the intended equipment. The residue of flux might cause a decrease in nonconductivity and the corrosion of an external electrode, etc.





Notice



Continued from the preceding page.

4. Cleaning

Please confirm there is no problem in the reliability of the product beforehand when cleaning it with the intended

The residue after cleaning it might cause the decrease in the surface resistance of the chip and the corrosion of the electrode part, etc. As a result it might cause reliability to deteriorate. Please confirm beforehand that there is no problem with the intended equipment in ultrasonic cleansing.

5. Resin Coating

Please use it after confirming there is no influence on the product with a intended equipment beforehand when the resin coating and molding.

A cracked chip might be caused at the cooling/heating cycle by the amount of resin spreading and/or bias

The resin for coating and molding must be selected as the stress is small when stiffening and the hygroscopic is low as possible.

■ Rating

- 1. Capacitance change of capacitor
- (1) In case of X7R char.

Capacitors have an aging characteristic, whereby the capacitor continually decreases its capacitance slightly if the capacitor is left on for a long time. Moreover, capacitance might change greatly depending on the surrounding temperature or an applied voltage. So, it is not likely to be suitable for use in a time constant circuit.

Please contact us if you need detailed information.

(2) In case of any char. except X7R Capacitance might change a little depending on the surrounding temperature or an applied voltage. Please contact us if you intend to use this product in a strict time constant circuit.

2. Performance check by equipment

inductance of the circuit.

Before using a capacitor, check that there is no problem in the equipment's performance and the specifications.

Generally speaking, CLASS 2 (X7R char.) ceramic capacitors have voltage dependence characteristics and temperature dependence characteristics in capacitance. So, the capacitance value may change depending on the operating condition in the equipment. Therefore, be sure to confirm the apparatus performance of receiving influence in a capacitance value change of a capacitor, such as leakage current and noise suppression characteristics. Moreover, check the surge-proof ability of a capacitor in the equipment, if needed, because the surge voltage may exceed specific value by the



ISO 9001 Certifications

■ Qualified Standards

The products listed here have been produced by ISO 9001 certified factory.

Plant				
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Izumo Murata Mfg. Co., Ltd.				
Okayama Murata Mfg. Co., Ltd.				
Murata Electronics Singapore (Pte.) Ltd.				
Murata Amazonia Industria E Comercio Ltda.				
Suzhou Murata Electronics Co., Ltd.				
Beijing Murata Electronics Co., Ltd.				



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 - 2 Aerospace equipment
 - (5) Medical equipment
- 4 Power plant equipment
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- (7) Traffic signal equipment
- (8) Disaster prevention / crime prevention equipment
- 9 Data-processing equipment
- ① Application of similar complexity and/or reliability requirements to the applications listed above
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